

MPC5200/D  
Rev. 2, 5/2004

MPC5200 Hardware  
Specifications



Topic	Page
1 Overview .....	1
2 Features .....	1
3 Electrical and Thermal Characteristics.....	5
4 Package Description .....	60
5 System Design Information .....	69
6 Ordering Information .....	74
7 Document Revision History .....	75

**NOTE:**

The information in this document is subject to change. For the latest data on the MPC5200, visit [www.mobilegt.com](http://www.mobilegt.com) and proceed to the MPC5200 Product Summary Page.

## 1 Overview

The MPC5200 integrates a high performance MPC603e series G2\_LE core with a rich set of peripheral functions focused on communications and systems integration. The G2\_LE core design is based on the PowerPC® core architecture. MPC5200 incorporates an innovative BestComm I/O subsystem, which isolates routine maintenance of peripheral functions from the embedded G2\_LE core. The MPC5200 contains a SDRAM/DDR Memory Controller, a flexible External Bus Interface, PCI Controller, USB, ATA, Ethernet, six Programmable Serial Controllers (PSC), I<sup>2</sup>C, SPI, CAN, J1850, Timers, and GPIOs.

## 2 Features

Key features are shown below.

- MPC603e series G2\_LE core
  - Superscalar architecture
  - 760 MIPS at 400 MHz (-40 to +85 °C)
  - 16 k Instruction cache, 16 k Data cache
  - Double precision FPU
  - Instruction and Data MMU
  - Standard and Critical interrupt capability
- SDRAM / DDR Memory Interface
  - up to 132-MHz operation
  - SDRAM and DDR SDRAM support
  - 256-MByte addressing range per CS, two CS available
  - 32-bit data bus
  - Built-in initialization and refresh
- Flexible multi-function External Bus Interface
  - Supports interfacing to ROM/Flash/SRAM memories or other memory mapped devices

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## Features

- 8 programmable Chip Selects
- Non multiplexed data access using 8/16/32 bit databus with up to 26-bit address
- Short or Long Burst capable
- Multiplexed data access using 8/16/32 bit databus with up to 25-bit address
- Peripheral Component Interconnect (PCI) Controller
  - Version 2.2 PCI compatibility
  - PCI initiator and target operation
  - 32-bit PCI Address/Data bus
  - 33- and 66-MHz operation
  - PCI arbitration function
- ATA Controller
  - Version 4 ATA compatible external interface—IDE Disk Drive connectivity
- BestComm DMA subsystem
  - Intelligent virtual DMA Controller
  - Dedicated DMA channels to control peripheral reception and transmission
  - Local memory (SRAM 16 kBytes)
- 6 Programmable Serial Controllers (PSC), configurable for the following:
  - UART or RS232 interface
  - CODEC interface for Soft Modem, Master/Slave CODEC Mode, I<sup>2</sup>S and AC97
  - Full duplex SPI mode
  - IrDA mode from 2400 bps to 4 Mbps
- Fast Ethernet Controller (FEC)
  - Supports 100Mbps IEEE 802.3 MII, 10 Mbps IEEE 802.3 MII, 10 Mbps 7-wire interface
- Universal Serial Bus Controller (USB)
  - USB Revision 1.1 Host
  - Open Host Controller Interface (OHCI)
  - Integrated USB Hub, with two ports.
- Two Inter-Integrated Circuit Interfaces (I<sup>2</sup>C)
- Serial Peripheral Interface (SPI)
- Dual CAN 2.0 A/B Controller (MSCAN)
  - Motorola Scalable Controller Area Network (MSCAN) architecture
  - Implementation of version 2.0A/B CAN protocol
  - Standard and extended data frames
- J1850 Byte Data Link Controller (BDLC)
  - J1850 Class B data communication network interface compatible and ISO compatible for low speed (<125 kbps) serial data communications in automotive applications.
  - Supports 4X mode, 41.6 kbps
  - In-frame response (IFR) types 0, 1, 2, and 3 supported

- Systems level features
  - Interrupt Controller supports four external interrupt request lines and 47 internal interrupt sources
  - GPIO/Timer functions
    - Up to 56 total GPIO pins (depending on functional multiplexing selections) that support a variety of interrupt/WakeUp capabilities.
    - Eight GPIO pins with timer capability supporting input capture, output compare, and pulse width modulation (PWM) functions
  - Real-time Clock with one-second resolution
  - Systems Protection (watch dog timer, bus monitor)
  - Individual control of functional block clock sources
  - Power management: Nap, Doze, Sleep, Deep Sleep modes
  - Support of WakeUp from low power modes by different sources (GPIO, RTC, CAN)
- Test/Debug features
  - JTAG (IEEE 1149.1 test access port)
  - Common On-chip Processor (COP) debug port
- On-board PLL and clock generation

Figure 1 shows a simplified MPC5200 block diagram.

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## Features

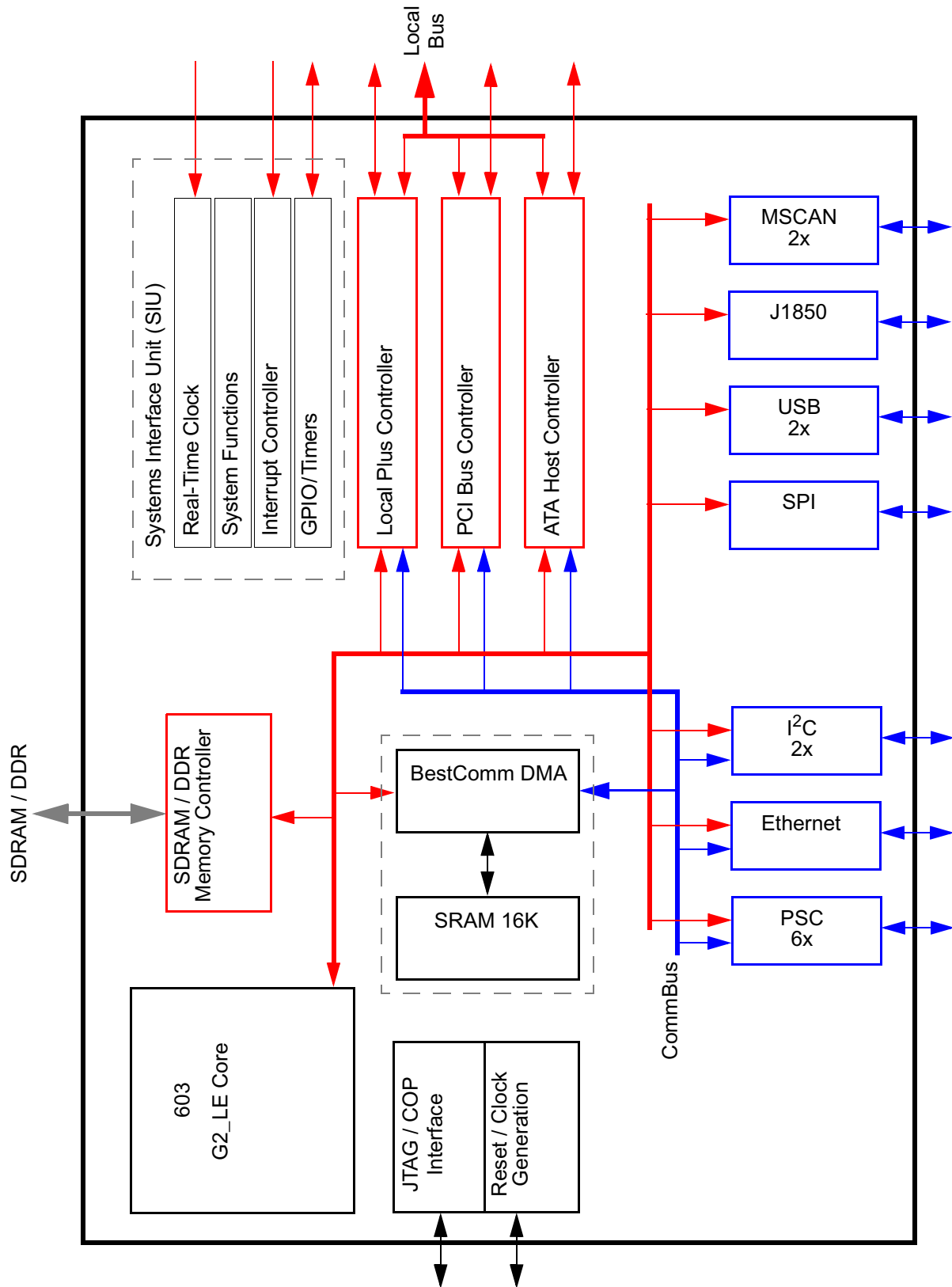


Figure 1 Simplified Block Diagram—MPC5200

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## Electrical and Thermal Characteristics

### 3 Electrical and Thermal Characteristics

#### 3.1 DC Electrical Characteristics

##### 3.1.1 Absolute Maximum Ratings

The tables in this section describe the MPC5200 DC Electrical characteristics. [Table 1](#) gives the absolute maximum ratings.

**Table 1 Absolute Maximum Ratings <sup>1</sup>**

Characteristic	Symbol	Min	Max	Unit	SpecID
Supply voltage - G2_LE core and peripheral logic	VDD_CORE	-0.3	1.8	V	D1.1
Supply voltage - I/O buffers	VDD_IO, VDD_MEM_IO	-0.3	3.6	V	D1.2
Supply voltage - System APLL	SYS_PLL_AVDD	-0.3	2.1	V	D1.3
Supply voltage - G2_LE APLL	CORE_PLL_AVDD	-0.3	2.1	V	D1.4
Input voltage (VDD_IO)	V <sub>in</sub>	-0.3	VDD_IO + 0.3	V	D1.5
Input voltage (VDD_MEM_IO)	V <sub>in</sub>	-0.3	VDD_MEM_IO + 0.3	V	D1.6
Input voltage overshoot	V <sub>inos</sub>	-	1.0	V	D1.7
Input voltage undershoot	V <sub>inus</sub>	-	1.0	V	D1.8
Storage temperature range	T <sub>stg</sub>	-55	150	°C	D1.9

<sup>1</sup> Absolute maximum ratings are stress ratings only, and functional operation at the maximums is not guaranteed. Stresses beyond those listed may affect device reliability or cause permanent damage.

##### 3.1.2 Recommended Operating Conditions

[Table 2](#) gives the recommended operating conditions.

**Table 2 Recommended Operating Conditions**

Characteristic	Symbol	Min <sup>1</sup>	Max <sup>1</sup>	Unit	SpecID
Supply voltage - G2_LE core and peripheral logic	VDD_CORE	1.42	1.58	V	D2.1
Supply voltage - standard I/O buffers	VDD_IO	3.0	3.6	V	D2.2
Supply voltage - memory I/O buffers (SDR)	VDD_MEM_IO <sub>SDR</sub>	3.0	3.6	V	D2.3
Supply voltage - memory I/O buffers (DDR)	VDD_MEM_IO <sub>DDR</sub>	2.42	2.63	V	D2.4
Supply voltage - System APLL	SYS_PLL_AVDD	1.42	1.58	V	D2.5
Supply voltage - G2_LE APLL	CORE_PLL_AVDD	1.42	1.58	V	D2.6
Input voltage - standard I/O buffers	V <sub>in</sub>	0	VDD_IO	V	D2.7
Input voltage - memory I/O buffers (SDR)	V <sub>inSDR</sub>	0	VDD_MEM_IO <sub>SDR</sub>	V	D2.8
Input voltage - memory I/O buffers (DDR)	V <sub>inDDR</sub>	0	VDD_MEM_IO <sub>DDR</sub>	V	D2.9

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## Electrical and Thermal Characteristics

**Table 2 Recommended Operating Conditions (continued)**

Characteristic	Symbol	Min <sup>1</sup>	Max <sup>1</sup>	Unit	SpecID
Ambient operating temperature range <sup>2</sup>	T <sub>A</sub>	-40	+85	°C	D2.10
Extended ambient operating temperature range <sup>3</sup>	T <sub>Aext</sub>	-40	+105	°C	D2.11
Die junction operating temperature range	T <sub>J</sub>	-40	+115	°C	D2.12
Extended die junction operating temperature range	T <sub>Jext</sub>	-40	+125	°C	D2.13

- 1 These are recommended and tested operating conditions. Proper device operation outside these conditions is not guaranteed.
- 2 Maximum G2\_LE core operating frequency is 400 MHz
- 3 Maximum G2\_LE core operating frequency is 264 MHz

### 3.1.3 DC Electrical Specifications

Table 3 gives the DC Electrical characteristics for the MPC5200 at recommended operating conditions (see Table 2).

**Table 3 DC Electrical Specifications**

Characteristic	Condition	Symbol	Min	Max	Unit	SpecID
Input high voltage	Input type = TTL VDD_IO/VDD_MEM_IO <sub>SDR</sub>	V <sub>IH</sub>	2.0	—	V	D3.1
Input high voltage	Input type = TTL VDD_MEM_IO <sub>DDR</sub>	V <sub>IH</sub>	1.7	—	V	D3.2
Input high voltage	Input type = PCI VDD_IO	V <sub>IH</sub>	2.0	—	V	D3.3
Input high voltage	Input type = SCHMITT VDD_IO	V <sub>IH</sub>	2.0	—	V	D3.4
Input high voltage	SYS_XTAL_IN	CV <sub>IH</sub>	2.0	—	V	D3.5
Input high voltage	RTC_XTAL_IN	CV <sub>IH</sub>	2.0	—	V	D3.6
Input low voltage	Input type = TTL VDD_IO/VDD_MEM_IO <sub>SDR</sub>	V <sub>IL</sub>	—	0.8	V	D3.7
Input low voltage	Input type = TTL VDD_MEM_IO <sub>DDR</sub>	V <sub>IL</sub>	—	0.7	V	D3.8
Input low voltage	Input type = PCI VDD_IO	V <sub>IL</sub>	—	0.8	V	D3.9
Input low voltage	Input type = SCHMITT VDD_IO	V <sub>IL</sub>	—	0.8	V	D3.10
Input low voltage	SYS_XTAL_IN	CV <sub>IL</sub>	—	0.8	V	D3.11
Input low voltage	RTC_XTAL_IN	CV <sub>IL</sub>	—	0.8	V	D3.12
Input leakage current	V <sub>in</sub> = 0 or VDD_IO/VDD_IO_MEM <sub>SDR</sub> (depending on input type <sup>1</sup> )	I <sub>IN</sub>	—	±10	µA	D3.13

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## Electrical and Thermal Characteristics

**Table 3 DC Electrical Specifications (continued)**

Characteristic	Condition	Symbol	Min	Max	Unit	SpecID
Input leakage current	SYS_XTAL_IN Vin = 0 or VDD_IO	I <sub>IN</sub>	—	±10	μA	D3.14
Input leakage current	RTC_XTAL_IN Vin = 0 or VDD_IO	I <sub>IN</sub>	—	±10	μA	D3.15
Input current, pullup resistor	PULLUP VDD_IO Vin = 0	I <sub>INpu</sub>	40	109	μA	D3.16
Input current, pullup resistor - memory I/O buffers	PULLUP_MEM VDD_IO_MEM <sub>SDR</sub> Vin = 0	I <sub>INpu</sub>	41	111	μA	D3.17
Input current, pulldown resistor	PULLDOWN VDD_IO Vin = VDD_IO	I <sub>INpd</sub>	36	106	μA	D3.18
Output high voltage	IOH is driver dependent <sup>2</sup> VDD_IO, VDD_IO_MEM <sub>SDR</sub>	V <sub>OH</sub>	2.4	—	V	D3.19
Output high voltage	IOH is driver dependent <sup>2</sup> VDD_IO_MEM <sub>DDR</sub>	V <sub>OHDDR</sub>	1.7	—	V	D3.20
Output low voltage	IOL is driver dependent <sup>2</sup> VDD_IO, VDD_IO_MEM <sub>SDR</sub>	V <sub>OL</sub>	—	0.4	V	D3.21
Output low voltage	IOL is driver dependent <sup>2</sup> VDD_IO_MEM <sub>DDR</sub>	V <sub>OLDDR</sub>	—	0.4	V	D3.22
DC Injection Current Per Pin <sup>3</sup>		I <sub>CS</sub>	-1.0	1.0	mA	D3.23
Capacitance	Vin = 0V, f = 1 MHz	C <sub>in</sub>	—	15	pF	D3.24

- 1 Leakage current is measured with output drivers disabled and pull-up/pull-downs inactive.
- 2 See [Table 4](#) for the typical drive capability of a specific signal pin based on the type of output driver associated with that pin as listed in [Table 51](#).
- 3 All injection current is transferred to VDD\_IO/VDD\_IO\_MEM. An external load is required to dissipate this current to maintain the power supply within the specified voltage range.  
Total injection current for all digital input-only and all digital input/output pins must not exceed 10 mA. Exceeding this limit can cause disruption of normal operation.

**Table 4 Drive Capability of MPC5200 Output Pins**

Driver Type	Supply Voltage	I <sub>OH</sub>	I <sub>OL</sub>	Unit	SpecID
DRV4	VDD_IO = 3.3V	4	4	mA	D3.25
DRV8	VDD_IO = 3.3V	8	8	mA	D3.26
DRV8_OD	VDD_IO = 3.3V	-	8	mA	D3.27
DRV16_MEM	VDD_IO_MEM = 3.3V	16	16	mA	D3.28
DRV16_MEM	VDD_IO_MEM = 2.5V	16	16	mA	D3.29
PCI	VDD_IO = 3.3V	16	16	mA	D3.30

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## Electrical and Thermal Characteristics

### 3.1.4 Electrostatic Discharge

**— CAUTION —**

*This device contains circuitry that protects against damage due to high-static voltage or electrical fields. However, it is advised that normal precautions be taken to avoid application of any voltages higher than maximum-rated voltages. Operational reliability is enhanced if unused inputs are tied to an appropriate logic voltage level (i.e., either GND or V<sub>CC</sub>). Table 7 gives package thermal characteristics for this device.*

**Table 5 ESD and Latch-Up Protection Characteristics**

Sym	Rating	Min	Max	Unit	SpecID
V <sub>HBM</sub>	Human Body Model (HBM)—JEDEC JESD22-A114-B	2000	—	V	D4.1
V <sub>MM</sub>	Machine Model (MM)—JEDEC JESD22-A115	200	—	V	D4.2
V <sub>CDM</sub>	Charge Device Model (CDM)—JEDEC JESD22-C101	500	—	V	D4.3
I <sub>LAT</sub>	Latch-up Current at T <sub>A</sub> =85°C positive negative	+100 -100	—	mA	D4.4
I <sub>LAT</sub>	Latch-up Current at T <sub>A</sub> =27°C positive negative	+200 -200	—	mA	D4.5

### 3.1.5 Power Dissipation

Power dissipation of the MPC5200 is caused by 3 different components: the dissipation of the internal or core digital logic (supplied by VDD\_CORE), the dissipation of the analog circuitry (supplied by SYS\_PLL\_AVDD and CORE\_PLL\_AVDD) and the dissipation of the IO logic (supplied by VDD\_IO\_MEM and VDD\_IO). Table 6 details typical measured core and analog power dissipation figures for a range of operating modes. However, the dissipation due to the switching of the IO pins can not be given in general, but must be calculated by the user for each application case using the following formula

$$P_{IO} = P_{IOint} + \sum_M N \times C \times VDD\_IO^2 \times f$$

where N is the number of output pins switching in a group M, C is the capacitance per pin, VDD\_IO is the IO voltage swing, f is the switching frequency and P<sub>IOint</sub> is the power consumed by the unloaded IO stage. The total power consumption of the MPC5200 processor

$$P_{total} = P_{core} + P_{analog} + P_{IO}$$

must not exceed the value, which would cause the maximum junction temperature to be exceeded.



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## Electrical and Thermal Characteristics

Table 6 Power Dissipation

Core Power Supply (VDD_CORE)					SpecID
Mode	SYS_XTAL/XLB/PCI/IPG/CORE (MHz)		Unit	Notes	
	33/66/33/33/264	33/132/66/132/396			
	Typ	Typ			
Operational	727.5	1080	mW	1, 2	D5.1
Doze	—	600	mW	1, 3	D5.2
Nap	—	225	mW	1, 4	D5.3
Sleep	—	225	mW	1, 5	D5.4
Deep-Sleep	52.5	52.5	mW	1, 6	D5.5
PLL Power Supplies (SYS_PLL_AVDD, CORE_PLL_AVDD)					
Mode	Typ		Unit	Notes	
Typical	2		mW	7	D5.6
Unloaded I/O Power Supplies (VDD_IO, VDD_MEM_IO <sup>8</sup> )					
Mode	Typ		Unit	Notes	
Typical	33		mW	9	D5.7

- 1 Typical core power is measured at VDD\_CORE = 1.5 V, Tj = 25 C
- 2 Operational power is measured while running an entirely cache-resident program with floating-point multiplication instructions in parallel with a continuous PCI transaction via BestComm.
- 3 Doze power is measured with the G2\_LE core in Doze mode, the system oscillator, System PLL and Core PLL are active, all other system modules are inactive
- 4 Nap power is measured with the G2\_LE core in Nap mode, the stem oscillator, System PLL and Core PLL are active, all other system modules are inactive
- 5 Sleep power is measured with the G2\_LE core in Sleep mode, the stem oscillator, System PLL and Core PLL are active, all other system modules are inactive
- 6 Deep-Sleep power is measured with the G2\_LE core in Sleep mode, the stem oscillator, System PLL, Core PLL and all other system modules are inactive
- 7 Typical PLL power is measured at SYS\_PLL\_AVDD = CORE\_PLL\_AVDD = 1.5 V, Tj = 25 C
- 8 IO power figures given in the table represent the worst case scenario. For the mem\_io rail connected to 2.5V the IO power is expected to be lower and bounded by the worst case with VDD\_MEM\_IO connected to 3.3V.
- 9 Unloaded typical I/O power is measured in Deep-Sleep mode at VDD\_IO = VDD\_MEM\_IO<sub>SDR</sub> = 3.3 V, Tj = 25 C

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## Electrical and Thermal Characteristics

### 3.1.6 Thermal Characteristics

**Table 7 Thermal Resistance Data**

Rating			Value	Unit	Notes	SpecID
Junction to Ambient Natural Convection	Single layer board (1s)	$R_{\theta JA}$	30	°C/W	<sup>1, 2</sup>	D6.1
Junction to Ambient Natural Convection	Four layer board (2s2p)	$R_{\theta JMA}$	22	°C/W	<sup>1, 3</sup>	D6.2
Junction to Ambient (@200 ft/min)	Single layer board (1s)	$R_{\theta JMA}$	24	°C/W	<sup>1, 3</sup>	D6.3
Junction to Ambient (@200 ft/min)	Four layer board (2s2p)	$R_{\theta JMA}$	19	°C/W	<sup>1, 3</sup>	D6.4
Junction to Board		$R_{\theta JB}$	14	°C/W	<sup>4</sup>	D6.5
Junction to Case		$R_{\theta JC}$	8	°C/W	<sup>5</sup>	D6.6
Junction to Package Top	Natural Convection	$\Psi_{JT}$	2	°C/W	<sup>6</sup>	D6.7

- 1 Junction temperature is a function of die size, on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, power dissipation of other components on the board, and board thermal resistance.
- 2 Per SEMI G38-87 and JEDEC JESD51-2 with the single layer board horizontal.
- 3 Per JEDEC JESD51-6 with the board horizontal.
- 4 Thermal resistance between the die and the printed circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
- 5 Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1).
- 6 Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2. When Greek letters are not available, the thermal characterization parameter is written as Psi-JT.

#### 3.1.6.1 Heat Dissipation

An estimation of the chip-junction temperature,  $T_J$ , can be obtained from the following equation:

$$T_J = T_A + (R_{\theta JA} \times P_D) \quad \text{Eqn. 1}$$

where:

$T_A$  = ambient temperature for the package (°C)

$R_{\theta JA}$  = junction to ambient thermal resistance (°C/W)

$P_D$  = power dissipation in package (W)

The junction to ambient thermal resistance is an industry standard value, which provides a quick and easy estimation of thermal performance. Unfortunately, there are two values in common usage: the value determined on a single layer board, and the value obtained on a board with two planes. For packages such as the PBGA, these values can be different by a factor of two. Which value is correct depends on the power dissipated by other components on the board. The value obtained on a single layer board is appropriate for the tightly packed printed circuit board. The value obtained on the board with the internal planes is usually appropriate if the board has low power dissipation and the components are well separated.

Historically, the thermal resistance has frequently been expressed as the sum of a junction to case thermal resistance and a case to ambient thermal resistance:

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## Electrical and Thermal Characteristics

$$R_{\theta JA} = R_{\theta JC} + R_{\theta CA} \quad \text{Eqn. 2}$$

where:

$R_{\theta JA}$  = junction to ambient thermal resistance ( $^{\circ}\text{C}/\text{W}$ )

$R_{\theta JC}$  = junction to case thermal resistance ( $^{\circ}\text{C}/\text{W}$ )

$R_{\theta CA}$  = case to ambient thermal resistance ( $^{\circ}\text{C}/\text{W}$ )

$R_{\theta JC}$  is device related and cannot be influenced by the user. The user controls the thermal environment to change the case to ambient thermal resistance,  $R_{\theta CA}$ . For instance, the user can change the air flow around the device, add a heat sink, change the mounting arrangement on printed circuit board, or change the thermal dissipation on the printed circuit board surrounding the device. This description is most useful for ceramic packages with heat sinks where some 90% of the heat flow is through the case to the heat sink to ambient. For most packages, a better model is required.

A more accurate thermal model can be constructed from the junction to board thermal resistance and the junction to case thermal resistance<sup>1-3</sup>. The junction to case covers the situation where a heat sink will be used or where a substantial amount of heat is dissipated from the top of the package. The junction to board thermal resistance describes the thermal performance when most of the heat is conducted to the printed circuit board. This model can be used for either hand estimations or for a computational fluid dynamics (CFD) thermal model.

To determine the junction temperature of the device in the application after prototypes are available, the Thermal Characterization Parameter ( $\Psi_{JT}$ ) can be used to determine the junction temperature with a measurement of the temperature at the top center of the package case using the following equation:

$$T_J = T_T + (\Psi_{JT} \times P_D) \quad \text{Eqn. 3}$$

where:

$T_T$  = thermocouple temperature on top of package ( $^{\circ}\text{C}$ )

$\Psi_{JT}$  = thermal characterization parameter ( $^{\circ}\text{C}/\text{W}$ )

$P_D$  = power dissipation in package (W)

The thermal characterization parameter is measured per JESD51-2 specification using a 40-gauge type T thermocouple epoxied to the top center of the package case. The thermocouple should be positioned, so that the thermocouple junction rests on the package. A small amount of epoxy is placed over the thermocouple junction and over approximately one mm of wire extending from the junction. The thermocouple wire is placed flat against the package case to avoid measurement errors caused by cooling effects of the thermocouple wire.

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## Electrical and Thermal Characteristics

### 3.2 Oscillator and PLL Electrical Characteristics

The MPC5200 System requires a system-level clock input SYS\_XTAL. This clock input may be driven directly from an external oscillator or with a crystal using the internal oscillator.

There is a separate oscillator for the independent Real-Time Clock (RTC) system.

The MPC5200 clock generation uses two phase locked loop (PLL) blocks.

- The system PLL (SYS\_PLL) takes an external reference frequency and generates the internal system clock. The system clock frequency is determined by the external reference frequency and the settings of the SYS\_PLL configuration.
- The G2\_LE core PLL (CORE\_PLL) generates a master clock for all of the CPU circuitry. The G2\_LE core clock frequency is determined by the system clock frequency and the settings of the CORE\_PLL configuration.

#### 3.2.1 System Oscillator Electrical Characteristics

**Table 8 System Oscillator Electrical Characteristics**

Characteristic	Symbol	Notes	Min	Typical	Max	Unit	SpecID
SYS_XTAL frequency	$f_{\text{sys\_xtal}}$		15.6	33.3	35.0	MHz	O1.1
Oscillator start-up time	$t_{\text{up\_osc}}$		—	—	100	$\mu\text{s}$	O1.2

#### 3.2.2 RTC Oscillator Electrical Characteristics

**Table 9 RTC Oscillator Electrical Characteristics**

Characteristic	Symbol	Notes	Min	Typical	Max	Unit	SpecID
RTC_XTAL frequency	$f_{\text{rtc\_xtal}}$		—	32.768	—	kHz	O2.1

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## Electrical and Thermal Characteristics

### 3.2.3 System PLL Electrical Characteristics

Table 10 System PLL Specifications

Characteristic	Symbol	Notes	Min	Typical	Max	Unit	SpecID
SYS_XTAL frequency	$f_{\text{sys\_xtal}}$	1	15.6	33.3	35.0	MHz	O3.1
SYS_XTAL cycle time	$T_{\text{sys\_xtal}}$	1	66.6	30.0	28.5	ns	O3.2
SYS_XTAL clock input jitter	$t_{\text{jitter}}$	2	—	—	150	ps	O3.3
System VCO frequency	$f_{\text{VCOsys}}$	1	250	533	800	MHz	O3.4
System PLL relock time	$t_{\text{lock}}$	3	—	—	100	$\mu\text{s}$	O3.5

- 1 The SYS\_XTAL frequency and PLL Configuration bits must be chosen such that the resulting system frequency, CPU (core) frequency, and PLL (VCO) frequency do not exceed their respective maximum or minimum operating frequencies.
- 2 This represents total input jitter - short term and long term combined - and is guaranteed by design. Two different types of jitter can exist on the input to core\_sysclk, systemic and true random jitter. True random jitter is rejected, but the PLL. Systemic jitter will be passed into and through the PLL to the internal clock circuitry, directly reducing the operating frequency.
- 3 Relock time is guaranteed by design and characterization. PLL-relock time is the maximum amount of time required for the PLL lock after a stable Vdd and core\_sysclk are reached during the power-on reset sequence. This specification also applies when the PLL has been disabled and subsequently re-enabled during sleep modes.

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## Electrical and Thermal Characteristics

### 3.2.4 G2\_LE Core PLL Electrical Characteristics

The internal clocking of the G2\_LE core is generated from and synchronized to the system clock by means of a voltage-controlled core PLL.

**Table 11 G2\_LE PLL Specifications**

Characteristic	Symbol	Notes	Min	Typical	Max	Unit	SpecID
G2_LE frequency	$f_{core}$	1	50	—	550	MHz	O4.1
G2_LE cycle time	$t_{core}$	1	2.85	—	40.0	ns	O4.2
G2_LE VCO frequency	$f_{VCOcore}$	1	400	—	1200	MHz	O4.3
G2_LE input clock frequency	$f_{SYSCLK}$		25	—	367	MHz	O4.4
G2_LE input clock cycle time	$t_{SYSCLK}$		2.73	—	50.0	ns	O4.5
G2_LE input clock jitter	$t_{jitter}$	2	—	—	150	ps	O4.6
G2_LE PLL relock time	$t_{lock}$	3	—	—	100	$\mu$ s	O4.7

- 1 The SYSCLK frequency and G2\_LE PLL Configuration bits must be chosen such that the resulting system frequencies, CPU (core) frequency, and G2\_LE PLL (VCO) frequency do not exceed their respective maximum or minimum operating frequencies.
- 2 This represents total input jitter - short term and long term combined - and is guaranteed by design. Two different types of jitter can exist on the input to core\_sysclk, systemic and true random jitter. True random jitter is rejected, but the PLL. Systemic jitter will be passed into and through the PLL to the internal clock circuitry, directly reducing the operating frequency.
- 3 Relock time is guaranteed by design and characterization. PLL-relock time is the maximum amount of time required for the PLL lock after a stable Vdd and core\_sysclk are reached during the power-on reset sequence. This specification also applies when the PLL has been disabled and subsequently re-enabled during sleep modes.

# Freescale Semiconductor, Inc.

## Electrical and Thermal Characteristics

### 3.3 AC Electrical Characteristics

Hyperlinks to the indicated timing specification sections are provided below.

- [AC Operating Frequency Data](#)
- [Clock AC Specifications](#)
- [Resets](#)
- [External Interrupts](#)
- [SDRAM](#)
- [PCI](#)
- [Local Plus Bus](#)
- [ATA](#)
- [Ethernet](#)
- [USB](#)
- [SPI](#)
- [MSCAN](#)
- [I<sup>2</sup>C](#)
- [J1850](#)
- [PSC](#)
- [GPIOs and Timers](#)
- [IEEE 1149.1 \(JTAG\) AC Specifications](#)

#### AC Test Timing Conditions:

Unless otherwise noted, all test conditions are as follows:

- TA = -40 to 85 °C
- Tj = -40 to 115 °C
- VDD\_CORE = 1.42 to 1.58 V  
VDD\_IO = 3.0 to 3.6 V
- Input conditions:  
All Inputs: tr, tf <= TBD
- Output Loading:  
All Outputs: 50 pF

#### 3.3.1 AC Operating Frequency Data

[Table 12](#) provides the operating frequency information for the MPC5200.

**Table 12 Clock Frequencies**

		Min	Max	Units	SpecID
1	G2_LE Processor Core	—	400	MHz	A1.1
2	SDRAM Clock	—	133	MHz	A1.2
3	XL Bus Clock	—	133	MHz	A1.3
4	IP Bus Clock	—	133	MHz	A1.4
5	PCI / Local Plus Bus Clock	—	66	MHz	A1.5
6	PLL Input Range	15.6	35	MHz	A1.6

# Freescale Semiconductor, Inc.

## Electrical and Thermal Characteristics

### 3.3.2 Clock AC Specifications

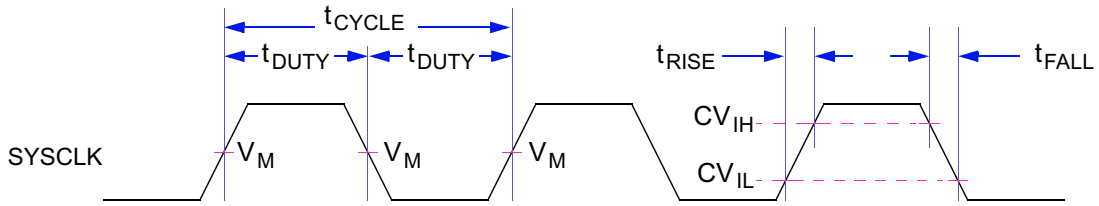


Figure 2 Timing Diagram—SYS\_XTAL\_IN

Table 13 SYS\_XTAL\_IN Timing

Sym	Description	Min	Max	Units	SpecID
$t_{\text{CYCLE}}$	SYS_XTAL_IN cycle time. <sup>1</sup>	28.6	64.1	ns	A2.1
$t_{\text{RISE}}$	SYS_XTAL_IN rise time.	—	5.0	ns	A2.2
$t_{\text{FALL}}$	SYS_XTAL_IN fall time.	—	5.0	ns	A2.3
$t_{\text{DUTY}}$	SYS_XTAL_IN duty cycle (measured at $V_M$ ). <sup>2</sup>	40.0	60.0	%	A2.4
$CV_{\text{IH}}$	SYS_XTAL_IN input voltage high	2.0	—	V	A2.5
$CV_{\text{IL}}$	SYS_XTAL_IN input voltage low	—	0.8	V	A2.6

- CAUTION**—The SYS\_XTAL\_IN frequency and system PLL\_CFG[0-6] settings must be chosen such that the resulting system frequencies do not exceed their respective maximum or minimum operating frequencies. See the MPC5200 User Manual [1].
- SYS\_XTAL\_IN duty cycle is measured at  $V_M$ .



# Freescale Semiconductor, Inc.

## Electrical and Thermal Characteristics

### 3.3.3 Resets

The MPC5200 has three reset pins:

- $\overline{\text{PORESET}}$  - Power on Reset
- $\overline{\text{HRESET}}$  - Hard Reset
- $\overline{\text{SRESET}}$  - Software Reset

These signals are asynchronous I/O signals and can be asserted at any time. The input side uses a Schmitt trigger and requires the same input characteristics as other MPC5200 inputs, as specified in the DC Electrical Specifications section. Table 14 specifies the pulse widths of the Reset inputs.

**Table 14 Reset Pulse Width**

Name	Description	Min Pulse Width	Max Pulse Width	Reference Clock	SpecID
$\overline{\text{PORESET}}$	Power On Reset	$t_{\text{VDD\_stable}} + t_{\text{up\_osc}} + t_{\text{lock}}$	—	SYS_XTAL_IN	A3.1
$\overline{\text{HRESET}}$	Hardware Reset	4 clock cycles	—	SYS_XTAL_IN	A3.2
$\overline{\text{SRESET}}$	Software Reset	4 clock cycles	—	SYS_XTAL_IN	A3.3

Notes:

1. For  $\overline{\text{PORESET}}$  the value of the minimum pulse width reflects the power on sequence. If  $\overline{\text{PORESET}}$  is asserted afterwards its minimum pulse width equals the minimum given for  $\overline{\text{HRESET}}$  related to the same reference clock.
2. The  $t_{\text{VDD\_stable}}$  describes the time which is needed to get all power supplies stable.
3. For  $t_{\text{lock}}$ , refer to the Oscillator/PLL section of this specification for further details.
4. For  $t_{\text{up\_osc}}$ , refer to the Oscillator/PLL section of this specification for further details.
5. Following the deassertion of  $\overline{\text{PORESET}}$ ,  $\overline{\text{HRESET}}$  and  $\overline{\text{SRESET}}$  remain low for 4096 reference clock cycles.
6. The deassertion of  $\overline{\text{HRESET}}$  for at least the minimum pulse width forces the internal resets to be active for an additional 4096 clock cycles.

**NOTE:**

As long as VDD is not stable the  $\overline{\text{HRESET}}$  output is not stable.

**Table 15 Reset Rise / Fall Timing**

Description	Min	Max	Unit	SpecID
$\overline{\text{PORESET}}$ fall time	—	1	ms	A3.4
$\overline{\text{PORESET}}$ rise time	—	1	ms	A3.5
$\overline{\text{HRESET}}$ fall time	—	TBD	ns	A3.6
$\overline{\text{HRESET}}$ rise time	—	TBD	ns	A3.7
$\overline{\text{SRESET}}$ fall time	—	TBD	ns	A3.8
$\overline{\text{SRESET}}$ rise time	—	TBD	ns	A3.9

For additional information, see the MPC5200 User Manual [1].

**NOTE:**

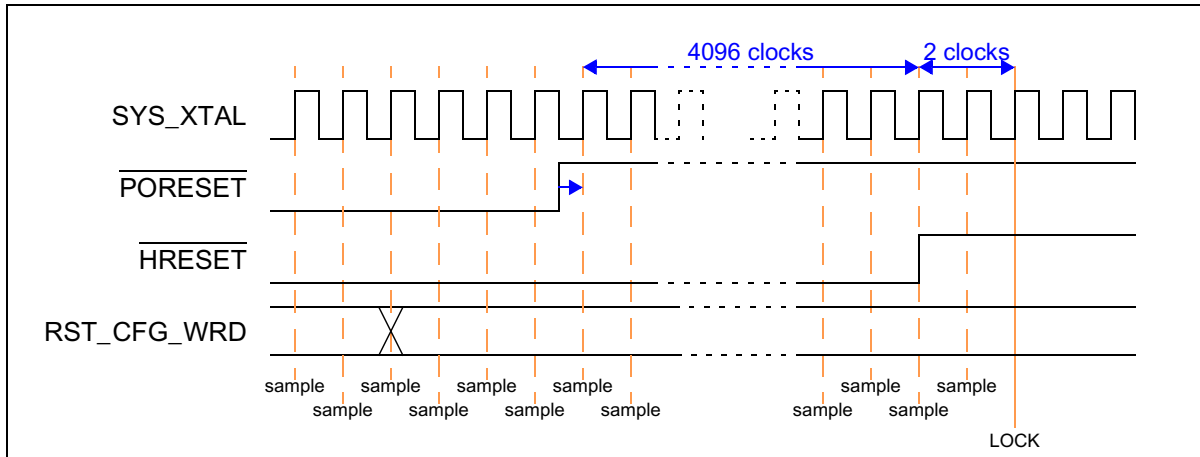
Make sure that the  $\overline{\text{PORESET}}$  does not carry any glitches. The MPC5200 has no filter to prevent them from getting into the chip.

# Freescale Semiconductor, Inc.

## Electrical and Thermal Characteristics

### 3.3.3.1 Reset Configuration Word

During reset ( $\overline{\text{HRESET}}$  and  $\overline{\text{PORESET}}$ ) the Reset Configuration Word is cached in the related Reset Configuration Word Register with each rising edge of the SYS\_XTAL signal. If both resets ( $\overline{\text{HRESET}}$  and  $\overline{\text{PORESET}}$ ) are inactive (high), the contents of this register get locked after two further SYS\_XTAL cycles (see Figure 3).



**Figure 3 Reset Configuration Word Locking**

**NOTE:**

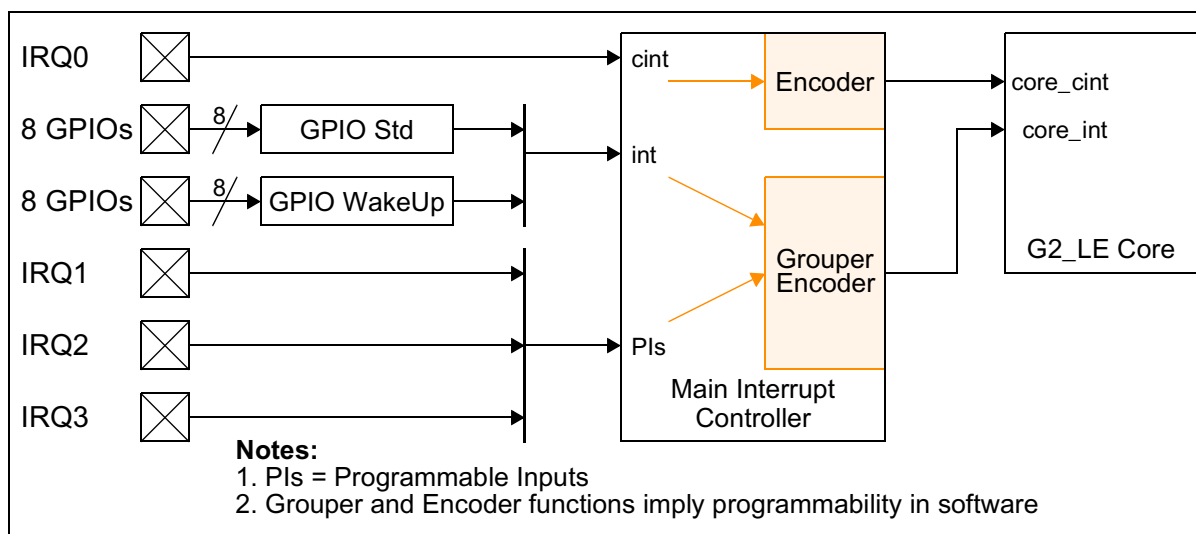
Beware of changing the values on the pins of the reset configuration word after the deassertion of  $\overline{\text{PORESET}}$ . This may cause problems because it may change the internal clock ratios and so extend the PLL locking process.

### 3.3.4 External Interrupts

The MPC5200 provides three different kinds of external interrupts:

- Four IRQ interrupts
- Eight GPIO interrupts with simple interrupt capability (not available in power-down mode)
- Eight WakeUp interrupts (special GPIO pins)

The propagation of these three kinds of interrupts to the core is shown in the following graphic:



**Figure 4 External interrupt scheme**

Due to synchronization, prioritization, and mapping of external interrupt sources, the propagation of external interrupts to the core processor is delayed by several IP\_CLK clock cycles. The following table specifies the interrupt latencies in IP\_CLK cycles. The IP\_CLK frequency is programmable in the Clock Distribution Module (see Note [Table 16](#)).

**Table 16 External interrupt latencies**

Interrupt Type	Pin Name	Clock Cycles	Reference Clock	Core Interrupt	SpecID
Interrupt Requests	IRQ0	10	IP_CLK	critical (cint)	A4.1
	IRQ0	10	IP_CLK	normal (int)	A4.2
	IRQ1	10	IP_CLK	normal (int)	A4.3
	IRQ2	10	IP_CLK	normal (int)	A4.5
	IRQ3	10	IP_CLK	normal (int)	A4.6

# Freescale Semiconductor, Inc.

## Electrical and Thermal Characteristics

**Table 16 External interrupt latencies (continued)**

Interrupt Type	Pin Name	Clock Cycles	Reference Clock	Core Interrupt	SpecID
Standard GPIO Interrupts	GPIO_PSC3_4	12	IP_CLK	normal (int)	A4.7
	GPIO_PSC3_5	12	IP_CLK	normal (int)	A4.8
	GPIO_PSC3_8	12	IP_CLK	normal (int)	A4.9
	GPIO_USB_9	12	IP_CLK	normal (int)	A4.10
	GPIO_ETH1_4	12	IP_CLK	normal (int)	A4.11
	GPIO_ETH1_5	12	IP_CLK	normal (int)	A4.12
	GPIO_ETH1_6	12	IP_CLK	normal (int)	A4.13
	GPIO_ETH1_7	12	IP_CLK	normal (int)	A4.14
GPIO WakeUp Interrupts	GPIO_PSC1_4	12	IP_CLK	normal (int)	A4.15
	GPIO_PSC2_4	12	IP_CLK	normal (int)	A4.16
	GPIO_PSC3_9	12	IP_CLK	normal (int)	A4.17
	GPIO_ETH1_8	12	IP_CLK	normal (int)	A4.18
	GPIO_IRDA_0	12	IP_CLK	normal (int)	A4.19
	DGP_IN0	12	IP_CLK	normal (int)	A4.20
	DGP_IN1	12	IP_CLK	normal (int)	A4.21

Notes:

- 1) The frequency of IP\_CLK depends on register settings in Clock Distribution Module. See the MPC5200 User Manual [1].
- 2) The interrupt latency descriptions in the table above are related to non competitive, non masked but enabled external interrupt sources. Take care of interrupt prioritization which may increase the latencies.

Since all external interrupt signals are synchronized into the internal processor bus clock domain, each of these signals has to exceed a minimum pulse width of more than one IP\_CLK cycle.

**Table 17 Minimum pulse width for external interrupts to be recognized**

Name	Min Pulse Width	Max Pulse Width	Reference Clock	SpecID
All external interrupts (IRQs, GPIOs)	> 1 clock cycle	—	IP_CLK	A4.22

Notes:

- 1) The frequency of the IP\_CLK depends on the register settings in Clock Distribution Module. See the MPC5200 User Manual [1] for further information.
- 2) If the same interrupt occurs a second time while its interrupt service routine has not cleared the former one, the second interrupt will not be recognized at all.

Besides synchronization, prioritization, and mapping the latency of an external interrupt to the start of its associated interrupt service routine also depends on the following conditions: To get a minimum interrupt service response time, it is recommended to enable the instruction cache and set up the maximum core clock, XL bus, and IP bus frequencies (depending on board design and programming). In addition, it is advisable to execute an interrupt handler, which has been implemented in assembly code.

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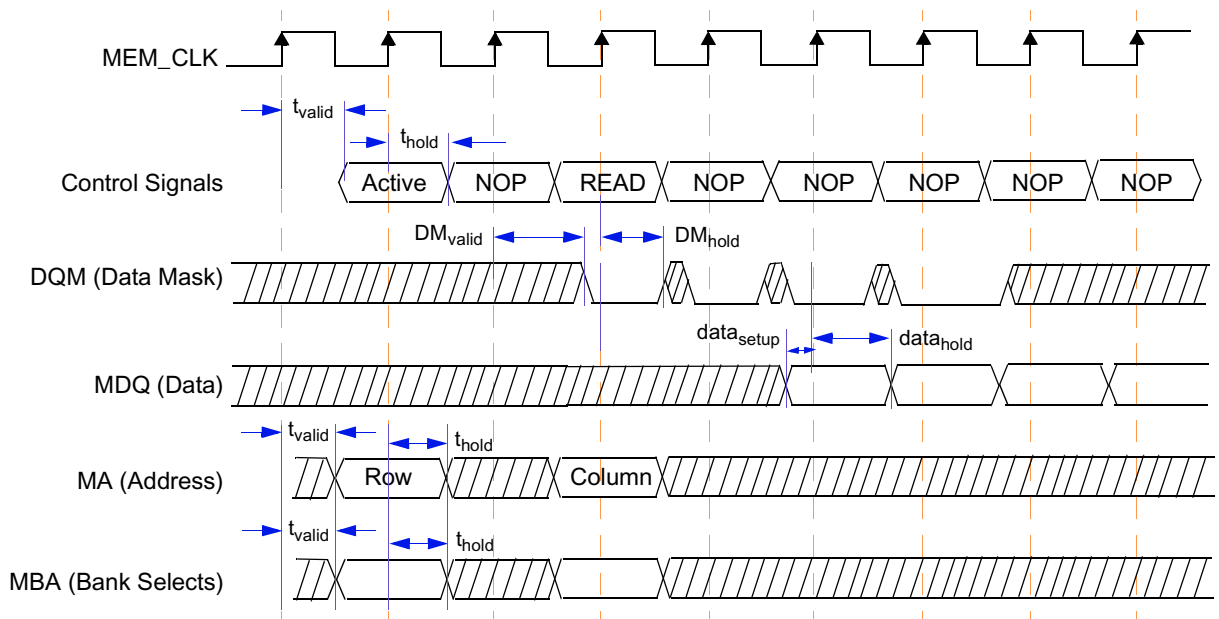
## Electrical and Thermal Characteristics

### 3.3.5 SDRAM

#### 3.3.5.4 Memory Interface Timing-Standard SDRAM Read Command

Table 18 Standard SDRAM Memory Read Timing

Sym	Description	Min	Max	Units	SpecID
$t_{mem\_clk}$	MEM_CLK period	7.5	—	ns	A5.1
$t_{valid}$	Control Signals, Address and MBA Valid after rising edge of MEM_CLK	—	$t_{mem\_clk} * 0.5 + 0.4$	ns	A5.2
$t_{hold}$	Control Signals, Address and MBA Hold after rising edge of MEM_CLK	$t_{mem\_clk} * 0.5$	—	ns	A5.3
$DM_{valid}$	DQM valid after rising edge of MEM_CLK	—	$t_{mem\_clk} * 0.25 + 0.4$	ns	A5.4
$DM_{hold}$	DQM hold after rising edge of MEM_CLK	$t_{mem\_clk} * 0.25 - 0.7$	—	ns	A5.5
$data_{setup}$	MDQ setup to rising edge of MEM_CLK	—	0.3	ns	A5.6
$data_{hold}$	MDQ hold after rising edge of MEM_CLK	0.2	—	ns	A5.7



NOTE: Control Signals are composed of RAS, CAS,  $\overline{MEM\_WE}$ ,  $\overline{MEM\_CS}$ ,  $\overline{MEM\_CS1}$  and CLK\_EN

Figure 5 Timing Diagram—Standard SDRAM Memory Read Timing

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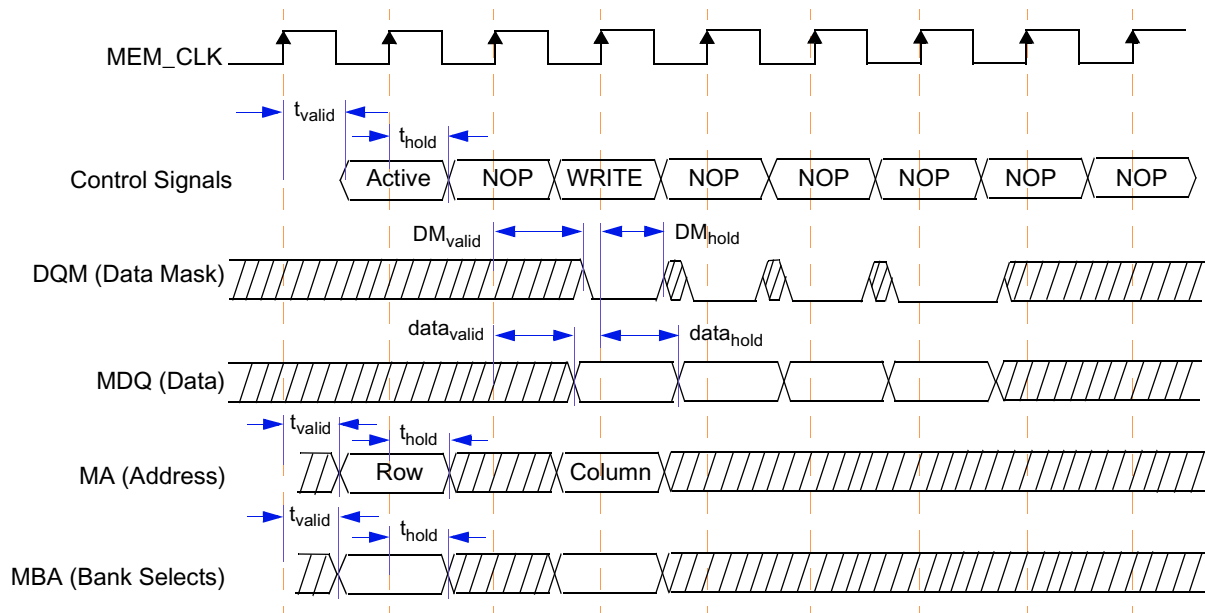
## Electrical and Thermal Characteristics

### 3.3.5.5 Memory Interface Timing-Standard SDRAM Write Command

In Standard SDRAM, all signals are activated on the Mem\_clk from the Memory Controller and captured on the Mem\_clk clock at the memory device.

**Table 19 Standard SDRAM Write Timing**

Sym	Description	Min	Max	Units	SpecID
$t_{mem\_clk}$	MEM_CLK period	7.5	—	ns	A5.8
$t_{valid}$	Control Signals, Address and MBA Valid after rising edge of MEM_CLK	—	$t_{mem\_clk} * 0.5 + 0.4$	ns	A5.9
$t_{hold}$	Control Signals, Address and MBA Hold after rising edge of MEM_CLK	$t_{mem\_clk} * 0.5$	—	ns	A5.10
$DM_{valid}$	DQM valid after rising edge of MEM_CLK	—	$t_{mem\_clk} * 0.25 + 0.4$	ns	A5.11
$DM_{hold}$	DQM hold after rising edge of Mem_clk	$t_{mem\_clk} * 0.25 - 0.7$	—	ns	A5.12
$data_{valid}$	MDQ valid after rising edge of MEM_CLK	—	$t_{mem\_clk} * 0.75 + 0.4$	ns	A5.13
$data_{hold}$	MDQ hold after rising edge of MEM_CLK	$t_{mem\_clk} * 0.75 - 0.7$	—	ns	A5.14



NOTE: Control Signals are composed of RAS, CAS,  $\overline{MEM\_WE}$ ,  $\overline{MEM\_CS}$ ,  $\overline{MEM\_CS1}$  and CLK\_EN

**Figure 6 Timing Diagram—Standard SDRAM Memory Write Timing**

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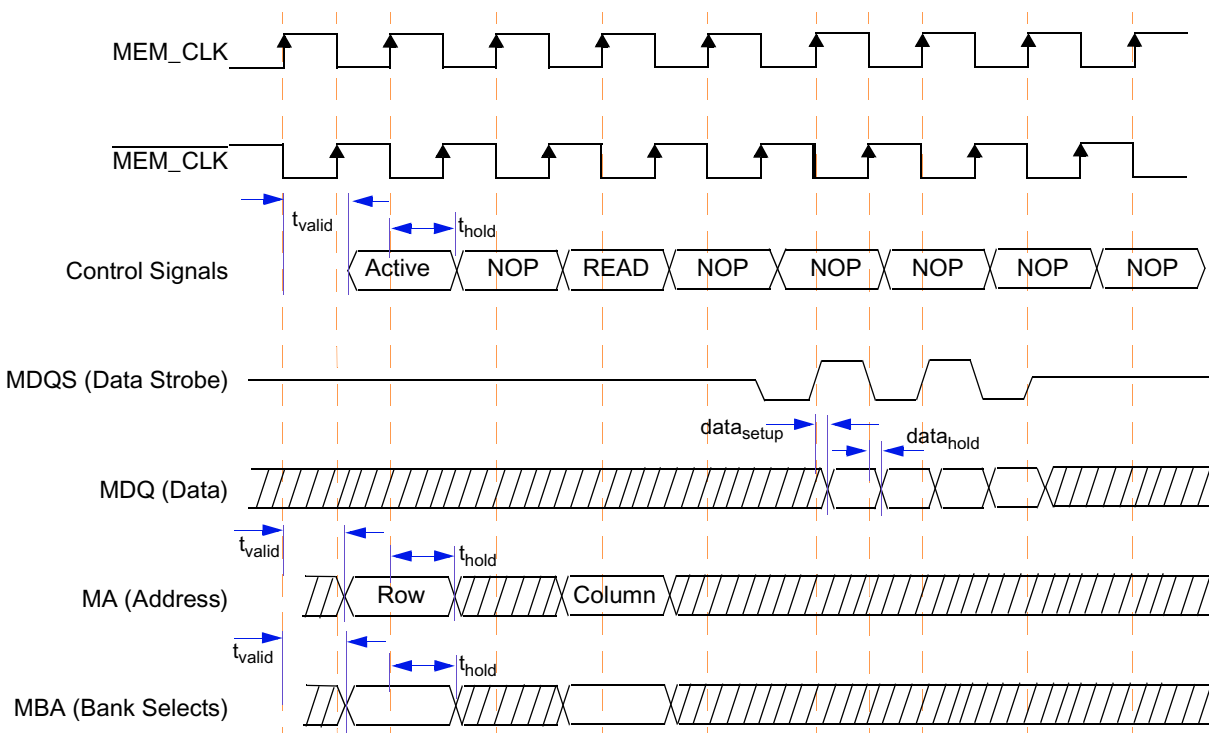
## Electrical and Thermal Characteristics

### 3.3.5.6 Memory Interface Timing-DDR SDRAM Read Command

The SDRAM Memory Controller uses an internally skewed clock for reading DDR memory. The programmable bits in the Reset Configuration Register used to account for unknown board delays are in the CDM module. The internal read clock can be delayed up to 3 ns under worst operating conditions in 32 increments of 95 ps, (1.4 ns in 45 ps increments under best case operating conditions) by programming the CDM Reset Configuration Register tap delay bits. Note: These bits in the CDM Reset Configuration register are not 'reset configured' but have a hard coded reset value **and** are writable during operation.

**Table 20 DDR SDRAM Memory Read Timing**

Sym	Description	Min	Max	Units	SpecID
$t_{mem\_clk}$	MEM_CLK period	7.5	—	ns	A5.15
$t_{valid}$	Control Signals, Address and MBA valid after rising edge of MEM_CLK	—	$t_{mem\_clk} * 0.5 + 0.4$	ns	A5.16
$t_{hold}$	Control Signals, Address and MBA hold after rising edge of MEM_CLK	$t_{mem\_clk} * 0.5$	—	ns	A5.17
$data_{setup}$	Setup time skewed by CDM Reset Config Reg [3:7] = 0b00010	—	0.4	ns	A5.18
$data_{hold}$	Hold time skewed by CDM Reset Config Reg [3:7] = 0b00010	2.34	—	ns	A5.19



NOTE: Control Signals signals are composed of RAS, CAS,  $\overline{MEM\_WE}$ ,  $\overline{MEM\_CS}$ ,  $\overline{MEM\_CS1}$  and CLK\_EN

**Figure 7 Timing Diagram—DDR SDRAM Memory Read Timing**

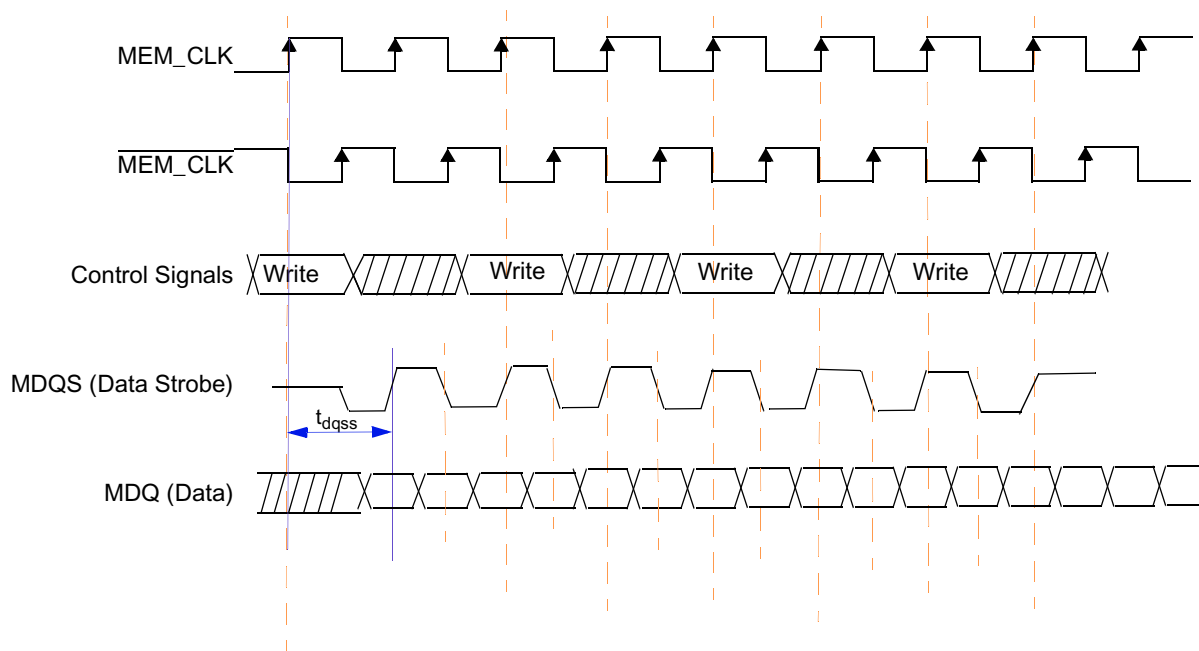
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## Electrical and Thermal Characteristics

### 3.3.5.7 Memory Interface Timing-DDR SDRAM Write Command

**Table 21 DDR SDRAM Memory Write Timing**

Sym	Description	Min	Max	Units	SpecID
$t_{mem\_clk}$	MEM_CLK period	7.5	—	ns	A5.20
$t_{DQSS}$	Delay from write command to first rising edge of MDQS	—	$t_{mem\_clk}+0.4$	ns	A5.21



NOTE: Control Signals signals are composed of RAS, CAS,  $\overline{\text{MEM\_WE}}$ ,  $\overline{\text{MEM\_CS}}$ ,  $\overline{\text{MEM\_CS1}}$  and CLK\_EN

**Figure 8 DDR SDRAM Memory Write Timing**



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## Electrical and Thermal Characteristics

### 3.3.6 PCI

The PCI interface on the MPC5200 is designed to PCI Version 2.2 and supports 33-MHz and 66-MHz PCI operations. See the PCI Local Bus Specification [4]; the component section specifies the electrical and timing parameters for PCI components with the intent that components connect directly together whether on the planar or an expansion board, without any external buffers or other “glue logic.” Parameters apply at the package pins, not at expansion board edge connectors.

The MPC5200 is always the source of the PCI CLK. The clock waveform must be delivered to each 33-MHz or 66-MHz PCI component in the system. Figure 9 shows the clock waveform and required measurement points for 3.3 V signaling environments. Table 22 summarizes the clock specifications.

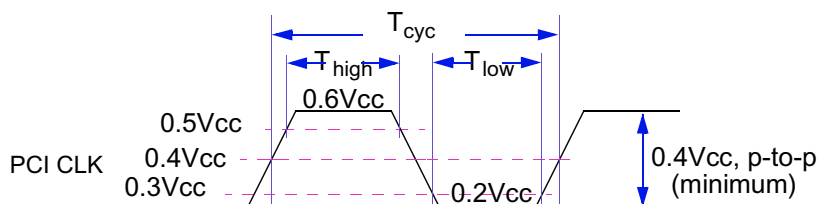


Figure 9 PCI CLK Waveform

Table 22 PCI CLK Specifications

Sym	Description	66 MHz		33 MHz		Units	Notes	SpecID
		Min	Max	Min	Max			
$T_{cyc}$	PCI CLK Cycle Time	15	30	30		ns	1,3	A6.1
$T_{high}$	PCI CLK High Time	6		11		ns		A6.2
$t_{low}$	PCI CLK Low Time	6						A6.3
-	PCI CLK Slew Rate	1.5	4	1	4	V/ns	2	A6.4

NOTES:

1. In general, all 66-MHz PCI components must work with any clock frequency up to 66 MHz. CLK requirements vary depending upon whether the clock frequency is above 33 MHz.
2. Rise and fall times are specified in terms of the edge rate measured in V/ns. This slew rate must be met across the minimum peak-to-peak portion of the clock waveform as shown in Figure 9.
3. The minimum clock period must not be violated for any single clock cycle, i.e., accounting for all system jitter.

Table 23 PCI Timing Parameters

Sym	Description	66 MHz		33 MHz		Units	Notes	SpecID
		Min	Max	Min	Max			
$T_{val}$	CLK to Signal Valid Delay - bused signals	2	6	2	11	ns	1,2,3	A6.5
$T_{val}(ptp)$	CLK to Signal Valid Delay - point to point	2	6	2	12	ns	1,2,3	A6.6
$T_{on}$	Float to Active Delay	2		2		ns	1	A6.7
$T_{off}$	Active to Float Delay		14		28	ns	1	A6.8

# Freescale Semiconductor, Inc.

## Electrical and Thermal Characteristics

Table 23 PCI Timing Parameters (continued)

Sym	Description	66 MHz		33 MHz		Units	Notes	SpecID
		Min	Max	Min	Max			
$T_{su}$	Input Setup Time to CLK - bused signals	3		7		ns	3,4	A6.9
$T_{su}(ptp)$	Input Setup Time to CLK - point to point	5		10,12		ns	3,4	A6.10
$T_h$	Input Hold Time from CLK	0		0		ns	4	A6.11

NOTES:

1. See the timing measurement conditions in the PCI Local Bus Specification [4]. It is important that all driven signal transitions drive to their  $V_{oh}$  or  $V_{ol}$  level within one  $T_{cyc}$ .
2. Minimum times are measured at the package pin with the load circuit, and maximum times are measured with the load circuit as shown in the PCI Local Bus Specification [4].
3. REQ# and GNT# are point-to-point signals and have different input setup times than do bused signals. GNT# and REQ# have a setup of 5 ns at 66 MHz. All other signals are bused.
4. See the timing measurement conditions in the PCI Local Bus Specification [4].

For Measurement and Test Conditions, see the PCI Local Bus Specification [4].

### 3.3.7 Local Plus Bus

The Local Plus Bus is the external bus interface of the MPC5200. Eight configurable Chip-selects are provided. There are two main modes of operation: non-MUXed and MUXED. The reference clock is the PCI CLK. Refer to PCI CLK specification. The maximum bus frequency is 66 MHz.

The following timing numbers indicate when data will be latched or driven onto the external bus, relative to the PCI CLK.

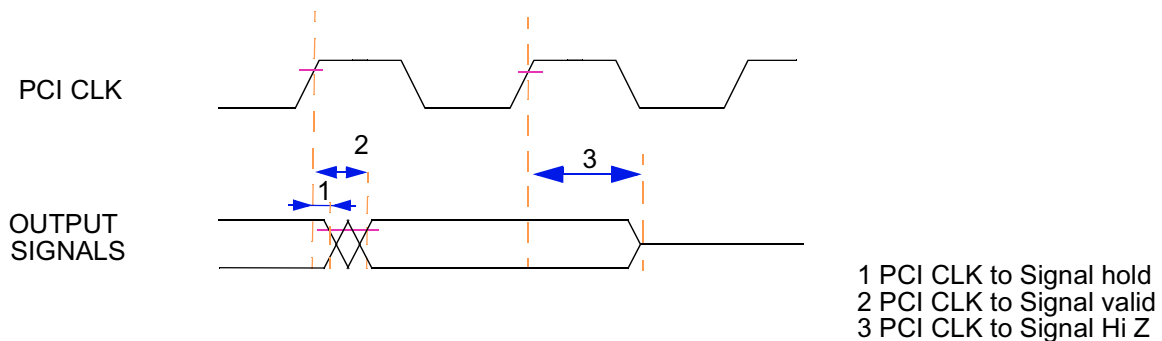


Figure 10 Output Signals Timing

#### 3.3.7.1 Non-MUXed Mode

Table 24 Non-MUXed Mode Timing

Sym	Description	Min	Max	Units	Notes	SpecID
$t_{AV}$	PCI CLK to ADDR valid	-	2	ns		A7.1
$t_{AH}$	PCI CLK to ADDR hold	1	-	ns		A7.2

# Freescale Semiconductor, Inc.

## Electrical and Thermal Characteristics

**Table 24 Non-MUXed Mode Timing (continued)**

Sym	Description	Min	Max	Units	Notes	SpecID
t <sub>DV</sub>	PCI CLK to DATA output valid	-	2	ns		A7.3
t <sub>DZ</sub>	PCI CLK to DATA output Hi Z	-	2	ns		A7.4
t <sub>CSA</sub>	PCI CLK to CS assertion	-	1.8	ns		A7.5
t <sub>CSN</sub>	PCI CLK to CS negation	-	1.8	ns		A7.6
t <sub>OEa</sub>	PCI CLK to OE assertion	-	1.5	ns		A7.7
t <sub>OEN</sub>	PCI CLK to OE negation	-	1.5	ns		A7.8
t <sub>RWV</sub>	PCI CLK to RW valid	-	1	ns		A7.9
t <sub>RWH</sub>	PCI CLK to RW hold	1	-	ns		A7.10
t <sub>TSIZV</sub>	PCI CLK to TSIZ valid	-	2	ns		A7.11
t <sub>TSIZH</sub>	PCI CLK to TSIZ hold	1	-	ns		A7.12
t <sub>DS</sub>	DATA input to PCI CLK setup	2	-	ns		A7.13
t <sub>DH</sub>	DATA input to PCI CLK hold	-	1	ns		A7.14

NOTES:

1. Wait states for Reads and Writes can be specified as 0 to 127.
2. Dead cycles can be specified as 0 to 3. Dead cycles will be added to the end of Chip Select read access and will occur in addition to any cycles which may already exist. These cycles provide a peripheral additional time to tri-state its bus after a read operation. This is for all access types.
3. Transfer Size TSIZE(1:0) are available in Non-MUXed mode for MOST Graphics or Large Flash Modes only.

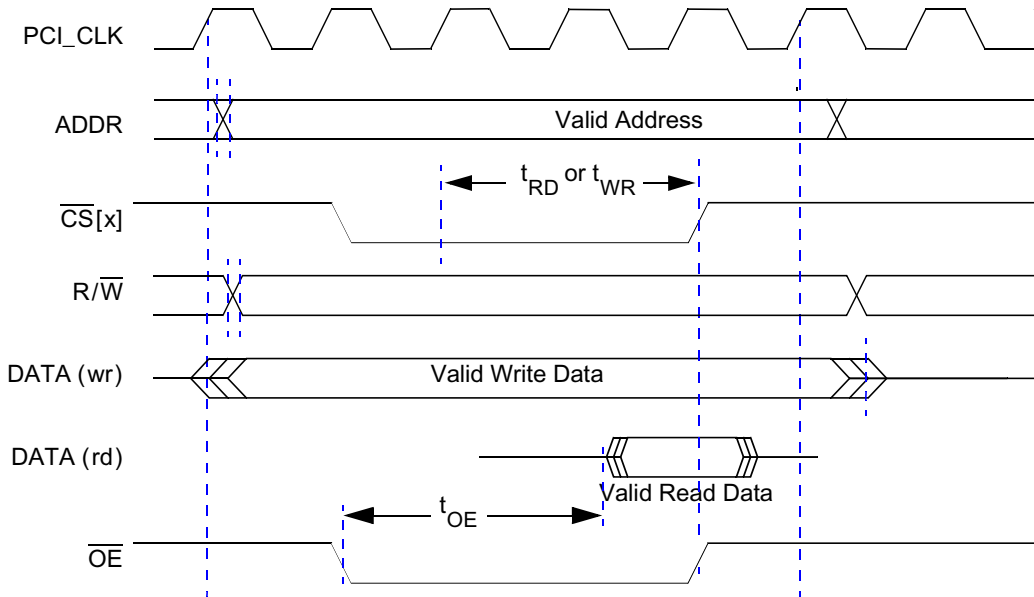
For understanding the different hold/valid/assertion/negation times refer to Figure 10.

The timing values in the above table are for a clock ratio of IP\_CLK : PCI\_CLK = 1 : 1 only.

The values will be different for other IP\_CLK : PCI\_CLK clock ratios.

# Freescale Semiconductor, Inc.

## Electrical and Thermal Characteristics



- Note: 1. The  $t_{RD}/t_{WR}$  is wait states as programmed for corresponding access and chip select.  
 2.  $\overline{OE}$  is active during Read only,  $t_{OE}$  is the Output Enable to Output Delay time  
 3. Read data has nominal setup/hold requirements around the  $\overline{CS}$  negation.

**Figure 11 Timing Diagram—Non-MUXed Mode**

### 3.3.7.2 MUXed Mode

**Table 25 MUXed Mode Timing**

Sym	Description	Min	Max	Units	Notes	SpecID
$t_{AV}$	PCI CLK to ADDR valid	-	2	ns		A7.15
$t_{AH}$	PCI CLK to ADDR hold	1	-	ns		A7.16
$t_{DV}$	PCI CLK to DATA output valid	-	2	ns		A7.17
$t_{DZ}$	PCI CLK to DATA output Hi Z	-	2	ns		A7.18
$t_{CSA}$	PCI CLK to CS assertion	-	1.8	ns		A7.19
$t_{CSN}$	PCI CLK to CS negation	-	1.8	ns		A7.20
$t_{OEA}$	PCI CLK to OE assertion	-	1.5	ns		A7.21
$t_{OEN}$	PCI CLK to OE negation	-	1.5	ns		A7.22
$t_{RWV}$	PCI CLK to RW valid	-	1	ns		A7.23
$t_{RWH}$	PCI CLK to RW hold	1	-	ns		A7.24
$t_{ALEA}$	PCI CLK to ALE assertion	-	2	ns		A7.25
$t_{ALEN}$	PCI CLK to ALE negation	-	2	ns		A7.26
$t_{DS}$	DATA input to PCI CLK setup	2	-	ns		A7.27

# Freescale Semiconductor, Inc.

## Electrical and Thermal Characteristics

**Table 25 MUXed Mode Timing (continued)**

Sym	Description	Min	Max	Units	Notes	SpecID
t <sub>DH</sub>	DATA input to PCI CLK hold	-	1	ns		A7.28

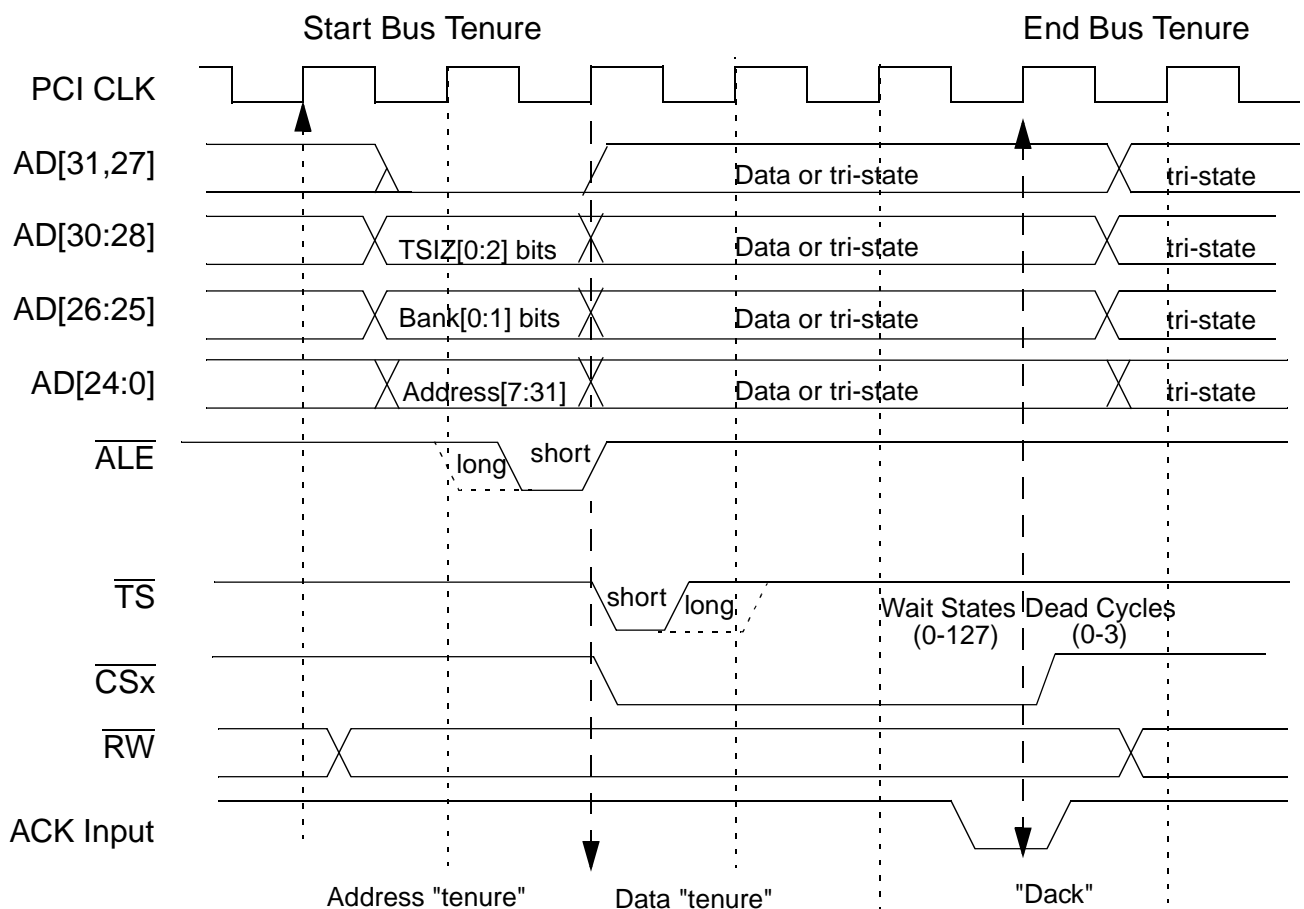
NOTES:

1. Wait states for Reads and Writes can be inserted when configured.
2. Dead cycles can be specified as 0 to 3. Dead cycles will be added to the end of Chip Select read access and will occur in addition to any cycles which may already exist. These cycles provide a peripheral additional time to tri-state its bus after a read operation. This is for all access types.
3. Transfer Size TSIZE(1:0) are available in Non-MUXed mode for MOST Graphics or Large Flash Modes only.

For understanding the different hold/valid/assertion/negation times refer to Figure 10.

The timing values in the above table are for a clock ratio of IP\_CLK : PCI\_CLK = 1 : 1 only.

The values will be different for other IP\_CLK : PCI\_CLK clock ratios.



**Figure 12 Timing Diagram - MUXed Mode**

# Freescale Semiconductor, Inc.

## Electrical and Thermal Characteristics

### 3.3.8 ATA

The MPC5200 ATA Controller is completely software programmable. It can be programmed to operate with ATA protocols using their respective timing, as described in the ANSI ATA-4 specification. The ATA interface is completely asynchronous in nature. Signal relationships are based on specific fixed timing in terms of timing units (nano seconds).

ATA data setup and hold times, with respect to Read/Write strobes, are software programmable inside the ATA Controller. Data setup and hold times are implemented using counters. The counters count the number of ATA clock cycles needed to meet the ANSI ATA-4 timing specifications. For details, see the ANSI ATA-4 specification [5] and how to program an ATA Controller and ATA drive for different ATA protocols and their respective timing. See the MPC5200 User Manual [1].

The MPC5200 ATA Host Controller design makes data available coincidentally with the active edge of the WRITE strobe in PIO and Multiword DMA modes.

- Write data is latched by the drive at the inactive edge of the WRITE strobe. This gives ample setup-time beyond that required by the ATA-4 specification.
- Data is held unchanged until the next active edge of the WRITE strobe. This gives ample hold-time beyond that required by the ATA-4 specification.

All ATA transfers are programmed in terms of system clock cycles (IP bus clocks) in the ATA Host Controller timing registers. This puts constraints on the ATA protocols and their respective timing modes in which the ATA Controller can communicate with the drive.

Faster ATA modes (i.e., UDMA 0, 1, 2) are supported when the system is running at a sufficient frequency to provide adequate data transfer rates. Adequate data transfer rates are a function of the following:

- The MPC5200 operating frequency (IP bus clock frequency)
- Internal MPC5200 bus latencies
- Other system load dependent variables

The ATA clock is the same frequency as the IP bus clock in MPC5200. See the MPC5200 User Manual [1].

#### NOTE:

All output timing numbers are specified for nominal 50 pF loads.

**Table 26 PIO Mode Timing Specifications**

	PIO Timing Parameter	Min/Max (ns)	Mode 0 (ns)	Mode 1 (ns)	Mode 2 (ns)	Mode 3 (ns)	Mode 4 (ns)	SpecID
t0	Cycle Time	min	600	383	240	180	120	A8.1
t1	Address valid to $\overline{\text{DIOR}}/\overline{\text{DIOW}}$ setup	min	70	50	30	30	25	A8.2
t2	$\overline{\text{DIOR}}/\overline{\text{DIOW}}$ pulse width 16-bit 8-bit	min min	165 290	125 290	100 290	80 80	70 70	A8.3
t2i	$\overline{\text{DIOR}}/\overline{\text{DIOW}}$ recovery time	min	—	—	—	70	25	A8.4
t3	$\overline{\text{DIOW}}$ data setup	min	60	45	30	30	20	A8.5
t4	$\overline{\text{DIOW}}$ data hold	min	30	20	15	10	10	A8.6
t5	$\overline{\text{DIOR}}$ data setup	min	50	35	20	20	20	A8.7
t6	$\overline{\text{DIOR}}$ data hold	min	5	5	5	5	5	A8.8

# Freescale Semiconductor, Inc.

## Electrical and Thermal Characteristics

Table 26 PIO Mode Timing Specifications (continued)

	PIO Timing Parameter	Min/Max (ns)	Mode 0 (ns)	Mode 1 (ns)	Mode 2 (ns)	Mode 3 (ns)	Mode 4 (ns)	SpecID
t <sub>9</sub>	IOR/DIOW to address valid hold	min	20	15	10	10	10	A8.9
t <sub>A</sub>	IORDY setup	max	35	35	35	35	35	A8.10
t <sub>B</sub>	IORDY pulse width	max	1250	1250	1250	1250	1250	A8.11

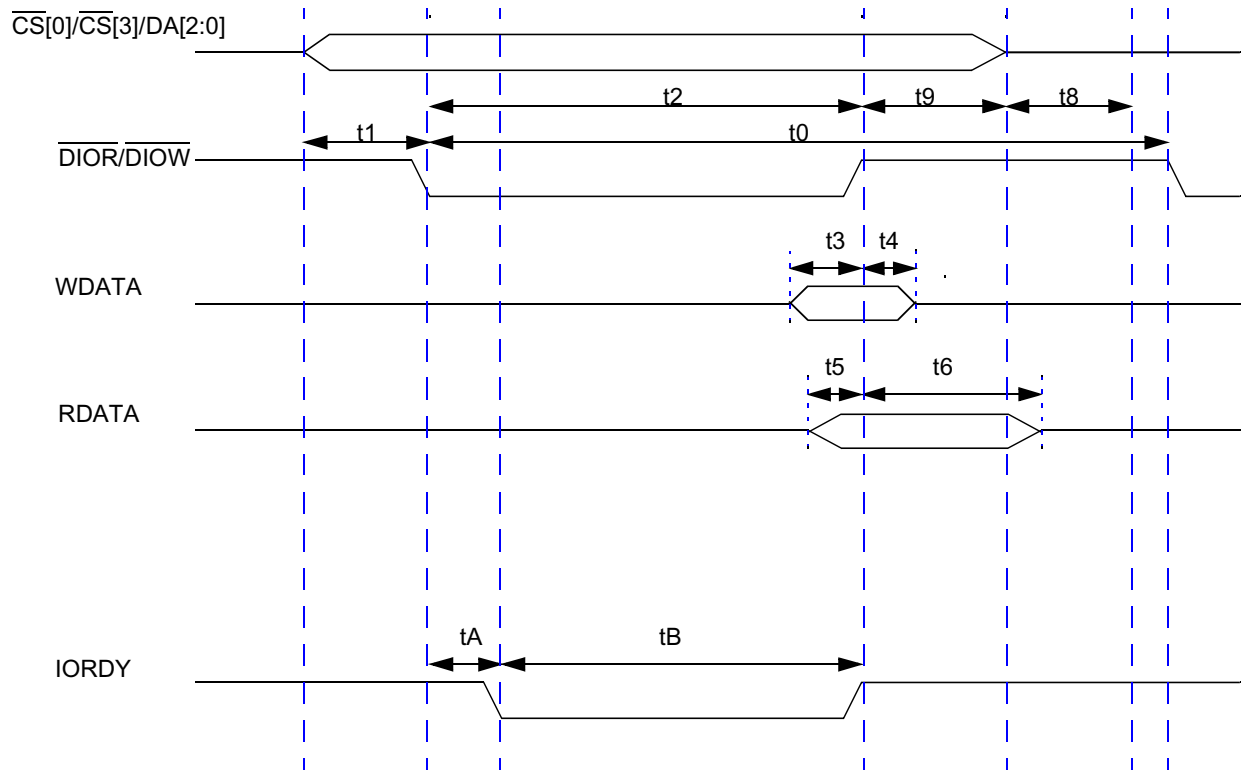


Figure 13 PIO Mode Timing

Table 27 Multiword DMA Timing Specifications

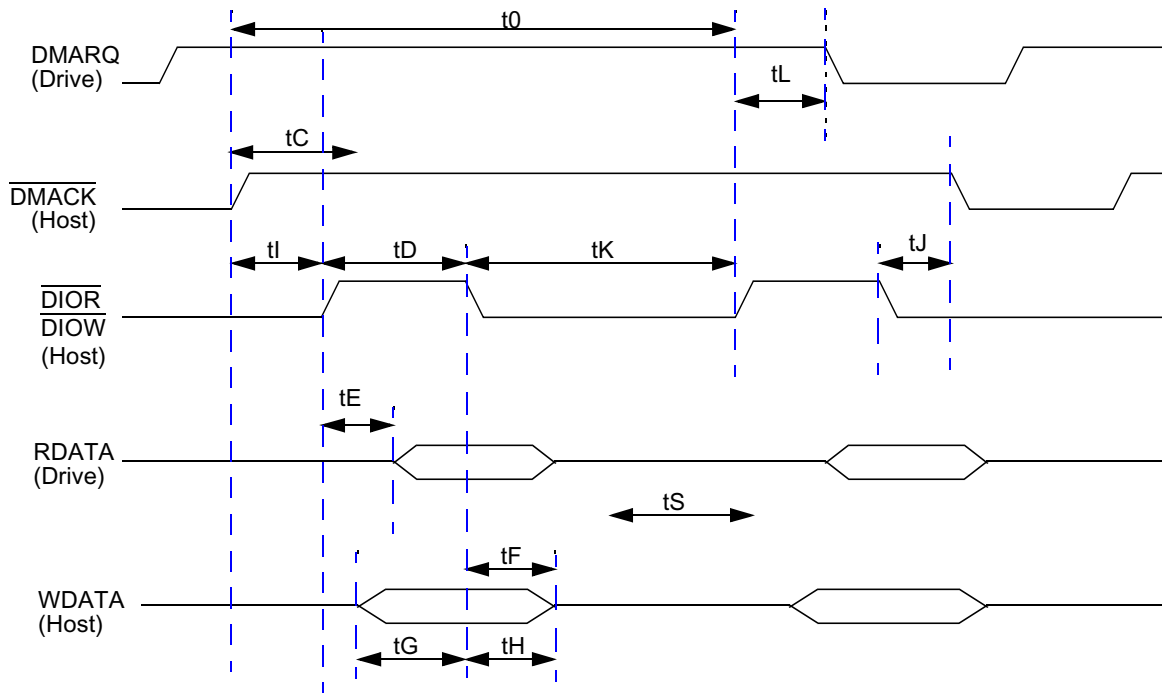
	Multiword DMA Timing Parameters	Min/Max	Mode 0(ns)	Mode 1(ns)	Mode 2(ns)	SpecID
t <sub>0</sub>	Cycle Time	min	480	150	120	A8.12
t <sub>C</sub>	DMACK to DMARQ delay	max	—	—	—	A8.13
t <sub>D</sub>	DIOR/DIOW pulse width (16-bit)	min	215	80	70	A8.14
t <sub>E</sub>	DIOR data access	max	150	60	50	A8.15
t <sub>G</sub>	DIOR/DIOW data setup	min	100	30	20	A8.16
t <sub>F</sub>	DIOR data hold	min	5	5	5	A8.17
t <sub>H</sub>	DIOW data hold	min	20	15	10	A8.18

# Freescale Semiconductor, Inc.

## Electrical and Thermal Characteristics

**Table 27 Multiword DMA Timing Specifications (continued)**

	Multiword DMA Timing Parameters	Min/Max	Mode 0(ns)	Mode 1(ns)	Mode 2(ns)	SpecID
tI	DMACK to $\overline{\text{DIOR}}/\overline{\text{DIOw}}$ setup	min	0	0	0	A8.19
tJ	$\overline{\text{DIOR}}/\overline{\text{DIOw}}$ to DMACK hold	min	20	5	5	A8.20
tKr	$\overline{\text{DIOR}}$ negated pulse width	min	50	50	25	A8.21
tKw	$\overline{\text{DIOw}}$ negated pulse width	min	215	50	25	A8.22
tLr	$\overline{\text{DIOR}}$ to DMARQ delay	max	120	40	35	A8.23
tLw	$\overline{\text{DIOw}}$ to DMARQ delay	max	40	40	35	A8.24



**NOTE:** The direction of signal assertion is towards the top of the page, and the direction of negation is towards the bottom of the page, irrespective of the electrical properties of the signal.

**Figure 14 Multiword DMA Timing**

**Table 28 Ultra DMA Timing Specification**

Name	MODE 0 (ns)		MODE 1 (ns)		MODE 2 (ns)		Comment	SpecID
	Min	Max	Min	Max	Min	Max		
(t) <sub>2CYC</sub>	240	—	160	—	120	—	Typical sustained average two cycle time.	A8.25



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## Electrical and Thermal Characteristics

Table 28 Ultra DMA Timing Specification (continued)

Name	MODE 0 (ns)		MODE 1 (ns)		MODE 2 (ns)		Comment	SpecID
	Min	Max	Min	Max	Min	Max		
(t) <sub>CYC</sub>	114	—	75	—	55	—	Cycle time allowing for asymmetry and clock variations from STROBE edge to STROBE edge	A8.26
(t) <sub>2CYC</sub>	235	—	156	—	117	—	Two-cycle time allowing for clock variations, from rising edge to next rising edge or from falling edge to next falling edge of STROBE.	A8.27
(t) <sub>DS</sub>	15	—	10	—	7	—	Data setup time at recipient.	A8.28
(t) <sub>DH</sub>	5	—	5	—	5	—	Data hold time at recipient.	A8.29
(t) <sub>DVS</sub>	70	—	48	—	34	—	Data valid setup time at sender, to STROBE edge.	A8.30
(t) <sub>DVH</sub>	6	—	6	—	6	—	Data valid hold time at sender, from STROBE edge.	A8.31
(t) <sub>FS</sub>	0	230	0	200	0	170	First STROBE time for drive to first negate $\overline{\text{DSTROBE}}$ from STOP during a data-in burst.	A8.32
(t) <sub>LI</sub>	0	150	0	150	0	150	Limited Interlock time. <sup>1 2</sup>	A8.33
(t) <sub>MLI</sub>	20	—	20	—	20	—	Interlock time with minimum. <sup>1 2</sup>	A8.34
(t) <sub>UI</sub>	0	—	0	—	0	—	Unlimited interlock time. <sup>1 2</sup>	A8.35
(t) <sub>AZ</sub>	—	10	—	10	—	10	Maximum time allowed for output drivers to release from being asserted or negated	A8.36
(t) <sub>ZAH</sub>	20	—	20	—	20	—	Minimum delay time required for output drivers to assert or negate from released state	A8.37
(t) <sub>ZAD</sub>	0	—	0	—	0	—		A8.38
(t) <sub>ENV</sub>	20	70	20	70	20	70	Envelope time—from $\overline{\text{DMACK}}$ to STOP and $\overline{\text{HDMARDY}}$ during data out burst initiation.	A8.39
(t) <sub>SR</sub>	—	50	—	30	—	20	STROBE to $\overline{\text{DMARDY}}$ time, if $\overline{\text{DMARDY}}$ is negated before this long after STROBE edge, the recipient receives no more than one additional data word.	A8.40
(t) <sub>RFS</sub>	—	75	—	60	—	50	Ready-to-Final STROBE time—no STROBE edges are sent this long after negation of $\overline{\text{DMARDY}}$ .	A8.41
(t) <sub>RP</sub>	160	—	125	—	100	—	Ready-to-Pause time—the time recipient waits to initiate pause after negating $\overline{\text{DMARDY}}$ .	A8.42
(t) <sub>IORDYZ</sub>	—	20	—	20	—	20	Pull-up time before allowing IORDY to be released.	A8.43

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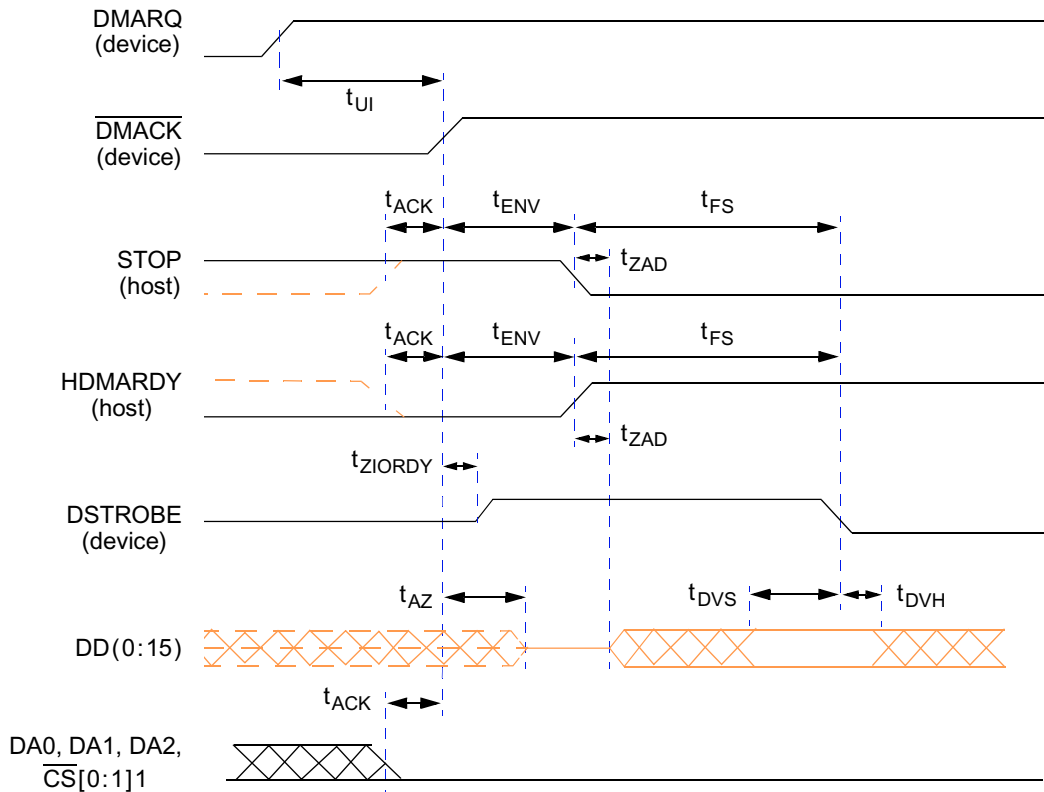
## Electrical and Thermal Characteristics

**Table 28 Ultra DMA Timing Specification (continued)**

Name	MODE 0 (ns)		MODE 1 (ns)		MODE 2 (ns)		Comment	SpecID
	Min	Max	Min	Max	Min	Max		
(t) <sub>ZIORDY</sub>	0	—	0	—	0	—	Minimum time drive waits before driving IORDY	A8.44
(t) <sub>ACK</sub>	20	—	20	—	20	—	Setup and hold times for $\overline{\text{DMACK}}$ , before assertion or negation.	A8.45
(t) <sub>SS</sub>	50	—	50	—	50	—	Time from STROBE edge to negation of DMARQ or assertion of STOP, when sender terminates a burst.	A8.46

- $t_{UI}$ ,  $t_{MLI}$ ,  $t_{LI}$  indicate sender-to-recipient or recipient-to-sender interlocks. That is, one agent (either sender or recipient) is waiting for the other agent to respond with a signal before proceeding.

  - $t_{UI}$  is an unlimited interlock that has no maximum time value.
  - $t_{MLI}$  is a limited time-out that has a defined minimum.
  - $t_{LI}$  is a limited time-out that has a defined maximum.
- All timing parameters are measured at the connector of the drive to which the parameter applies. For example, the sender shall stop generating STROBE edges  $t_{RFS}$  after negation of DMARDY. Both STROBE and DMARDY timing measurements are taken at the connector of the sender. Even though the sender stops generating STROBE edges, the receiver may receive additional STROBE edges due to propagation delays. All timing measurement switching points (low to high and high to low) are taken at 1.5 V.



**Figure 15 Timing Diagram—Initiating an Ultra DMA Data In Burst**

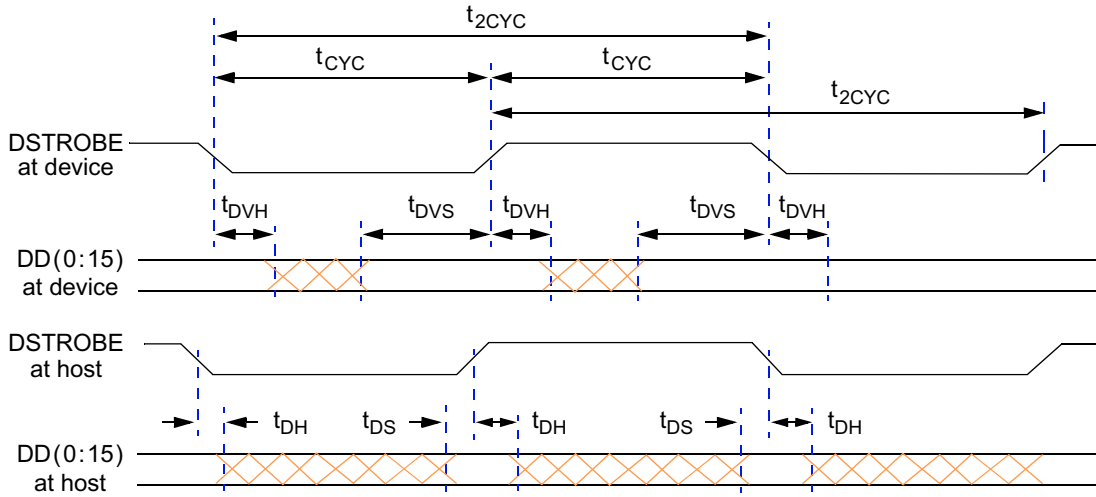


Figure 16 Timing Diagram—Sustained Ultra DMA Data In Burst

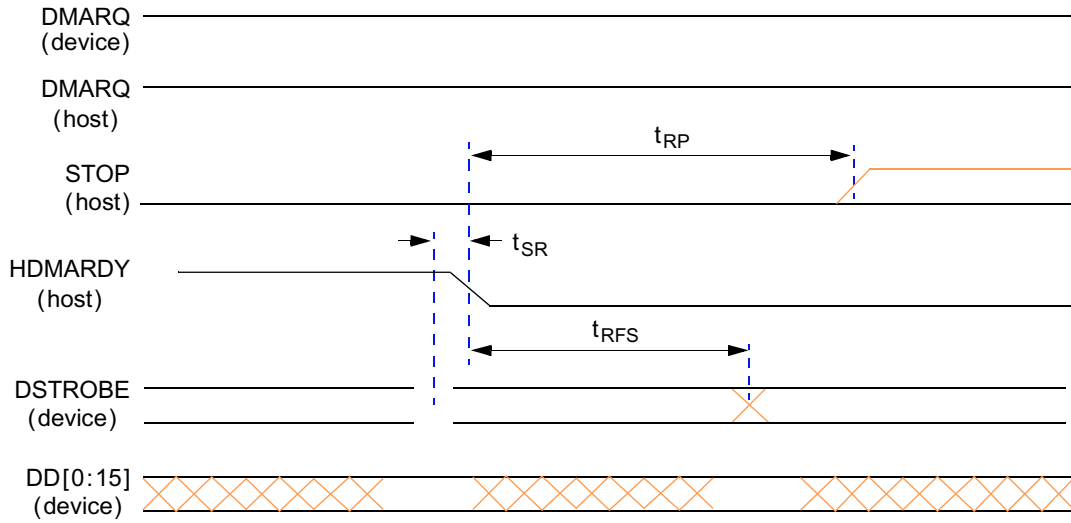
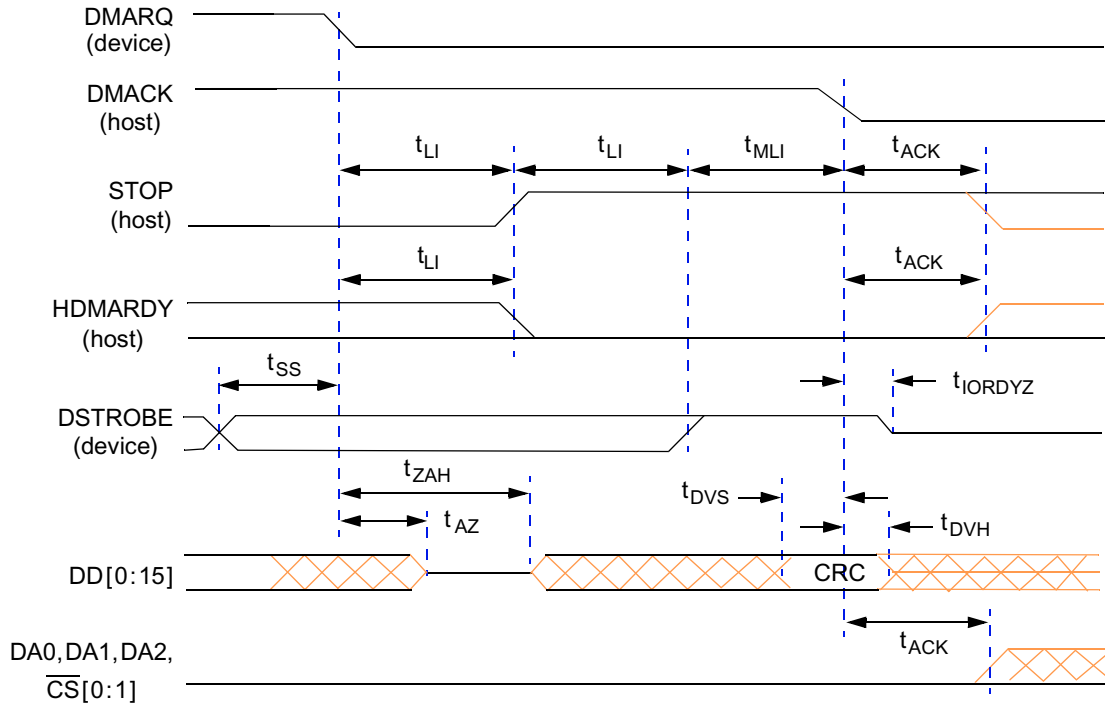


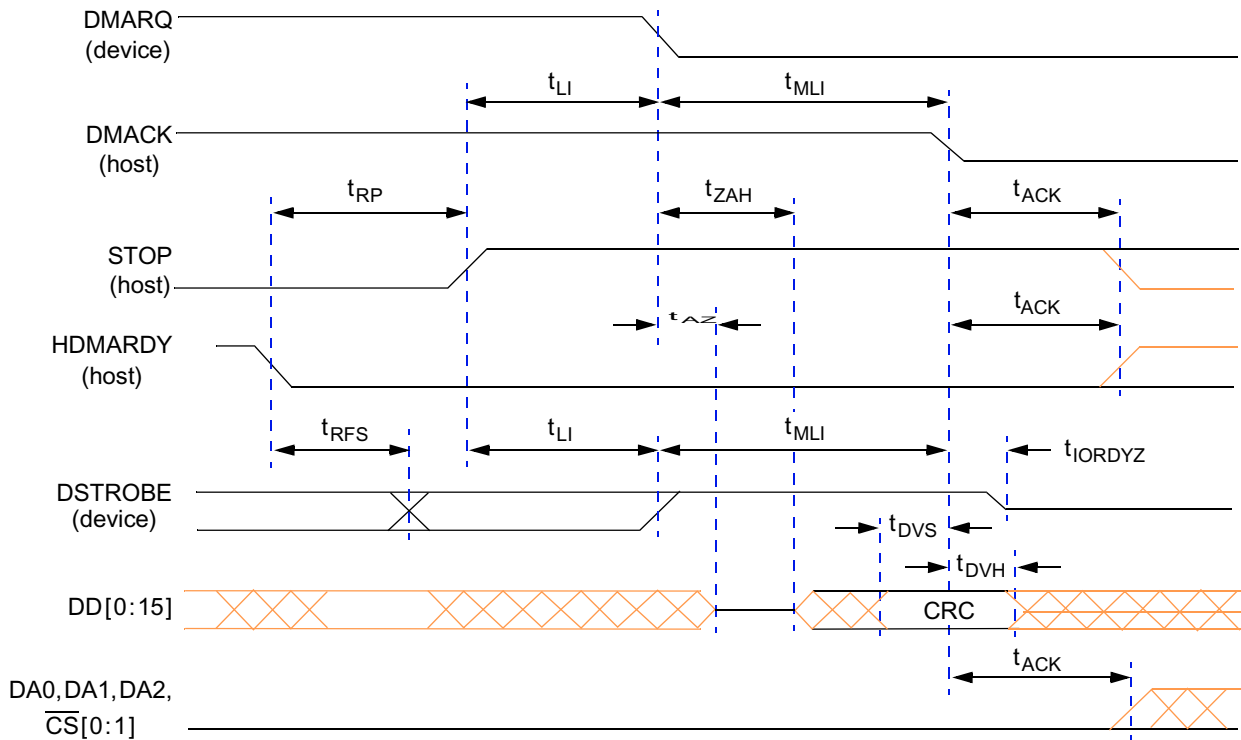
Figure 17 Timing Diagram—Host Pausing an Ultra DMA Data In Burst

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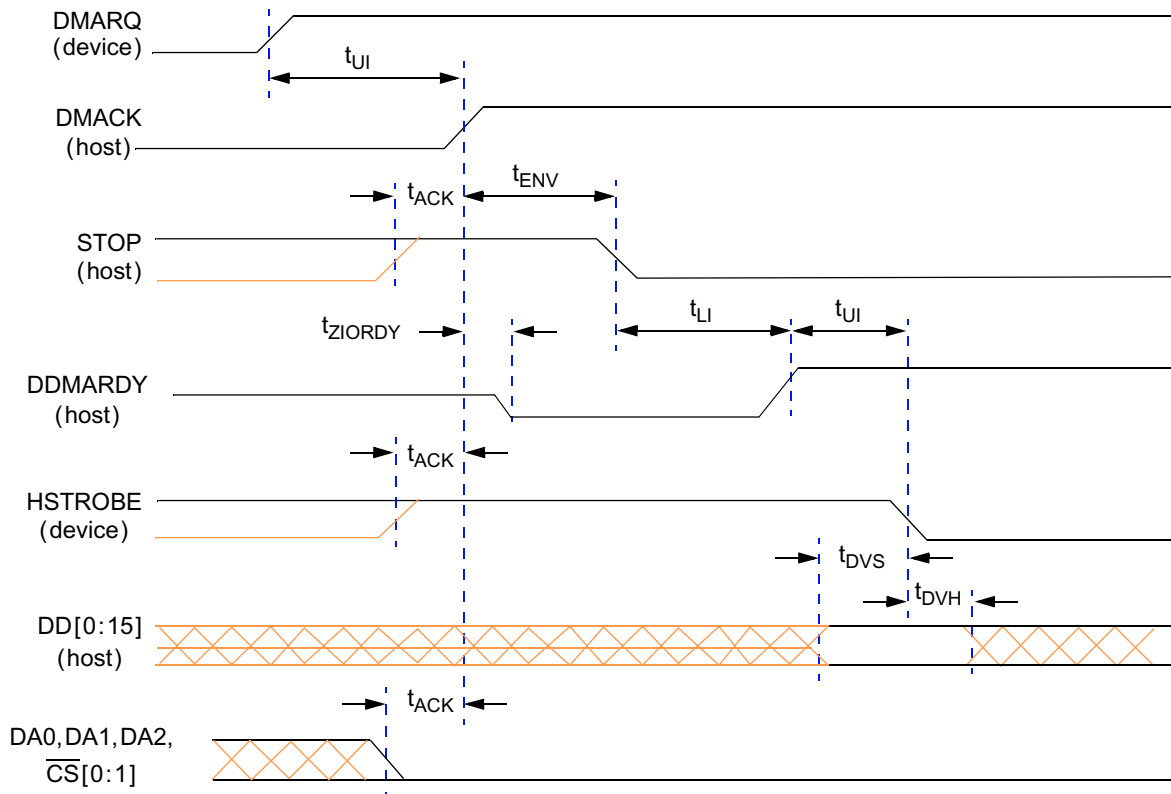
## Electrical and Thermal Characteristics



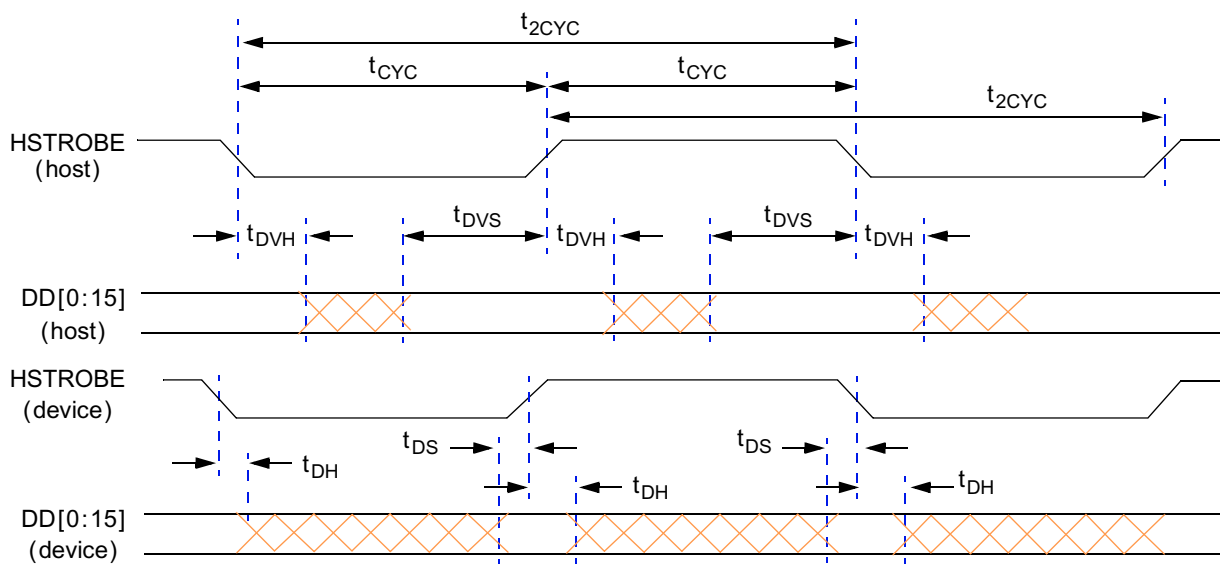
**Figure 18 Timing Diagram—Drive Terminating Ultra DMA Data In Burst**



**Figure 19 Timing Diagram—Host Terminating Ultra DMA Data In Burst**



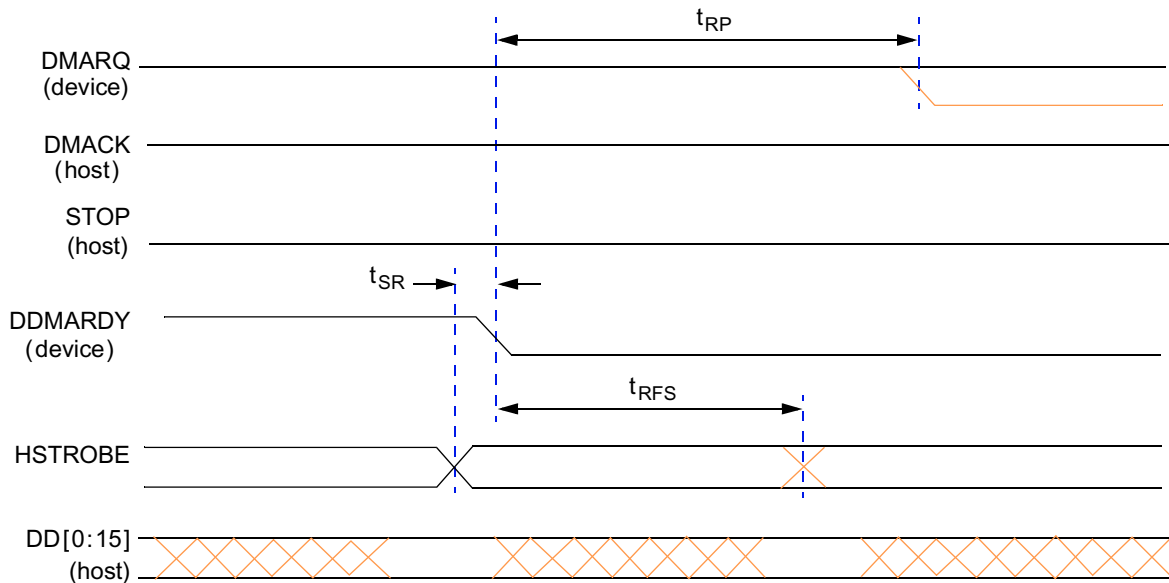
**Figure 20 Timing Diagram—Initiating an Ultra DMA Data Out Burst**



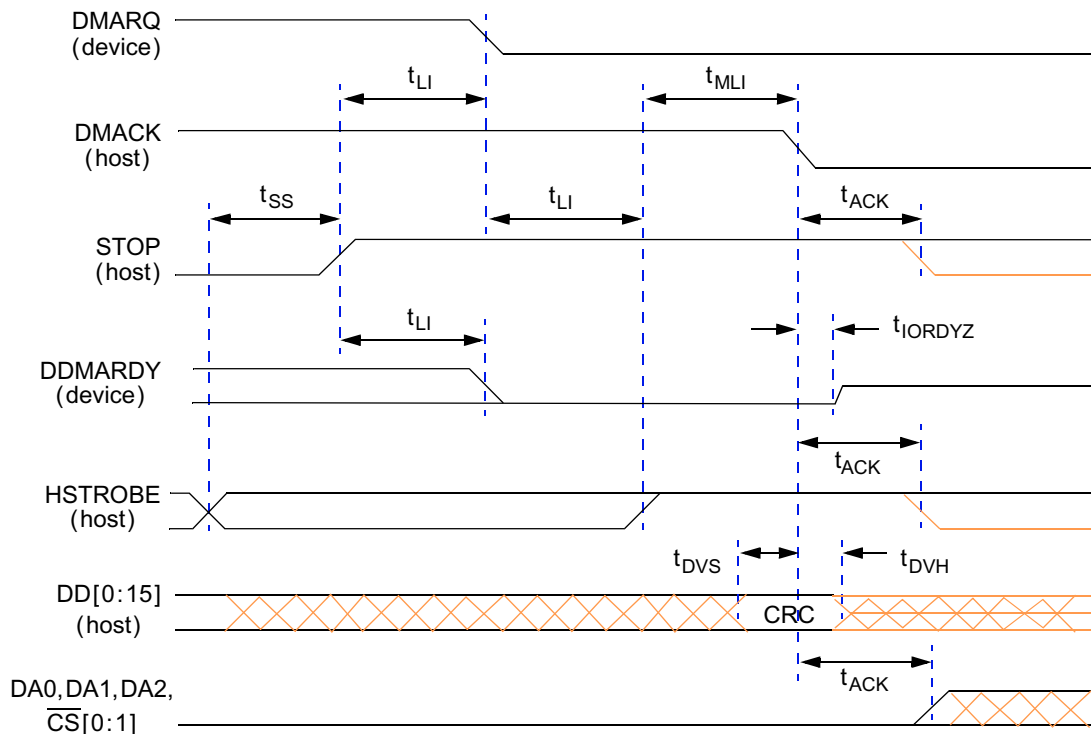
**Figure 21 Timing Diagram—Sustained Ultra DMA Data Out Burst**

# Freescale Semiconductor, Inc.

## Electrical and Thermal Characteristics



**Figure 22 Timing Diagram—Drive Pausing an Ultra DMA Data Out Burst**



**Figure 23 Timing Diagram—Host Terminating Ultra DMA Data Out Burst**

# Freescale Semiconductor, Inc.

## Electrical and Thermal Characteristics

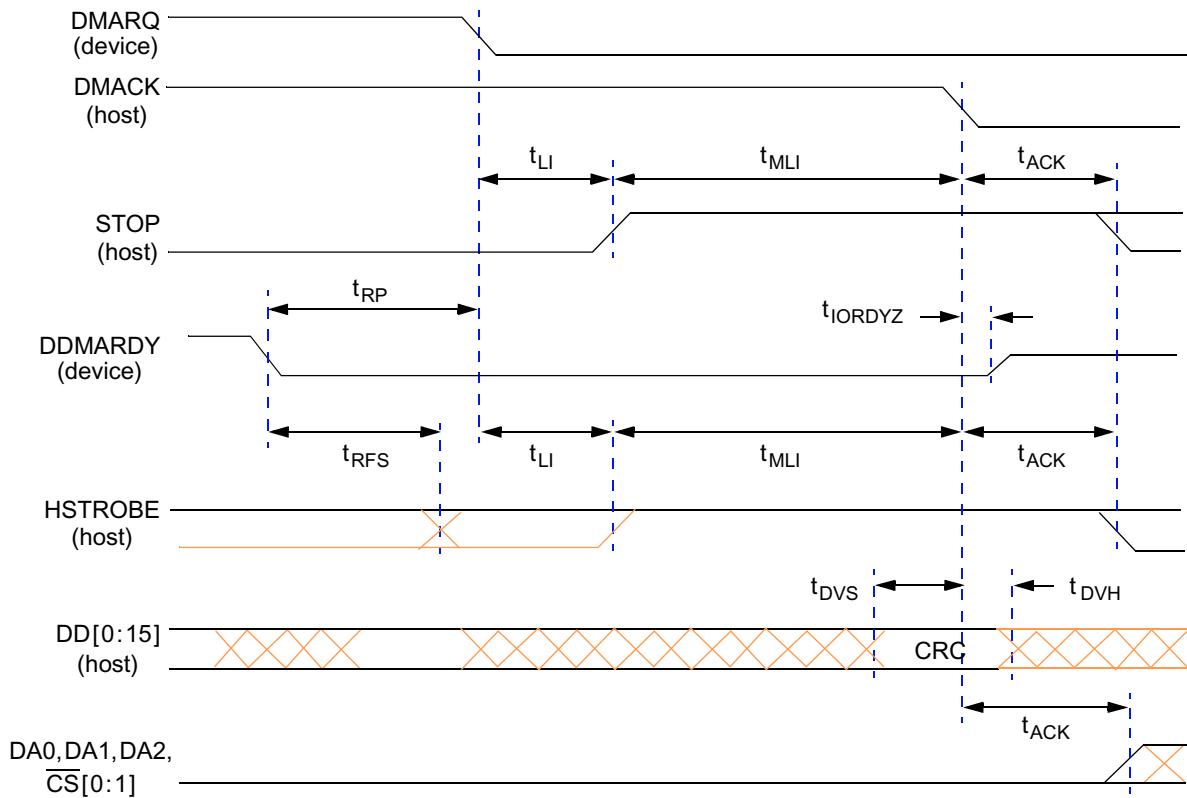


Figure 24 Timing Diagram—Drive Terminating Ultra DMA Data Out Burst

Table 29 Timing Specification ata\_isolation

Sym	Description	Min	Max	Units	SpecID
1	ata_isolation setup time	7	-	IP Bus cycles	A8.47
2	ata_isolation hold time	19	-	IP Bus cycles	A8.48

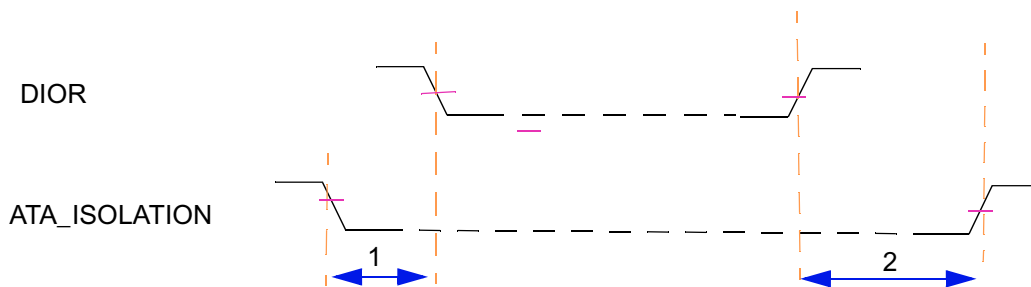


Figure 25 Timing Diagram-ATA-ISOLATION

# Freescale Semiconductor, Inc.

## Electrical and Thermal Characteristics

### 3.3.9 Ethernet

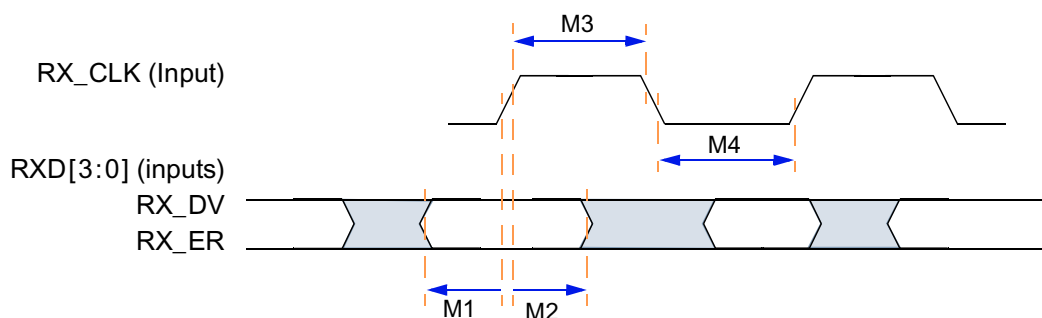
#### AC Test Timing Conditions:

- Output Loading  
All Outputs: 25 pF

**Table 30 MII Rx Signal Timing**

Sym	Description	Min	Max	Unit	SpecID
M1	RXD[3:0], RX_DV, RX_ER to RX_CLK setup	10	—	ns	A9.1
M2	RX_CLK to RXD[3:0], RX_DV, RX_ER hold	10	—	ns	A9.2
M3	RX_CLK pulse width high	35%	65%	RX_CLK Period <sup>1</sup>	A9.3
M4	RX_CLK pulse width low	35%	65%	RX_CLK Period <sup>1</sup>	A9.4

<sup>1</sup> RX\_CLK shall have a frequency of 25% of data rate of the received signal. See the IEEE 802.3 Specification [6].



**Figure 26 Ethernet Timing Diagram—MII Rx Signal**

**Table 31 MII Tx Signal Timing**

Sym	Description	Min	Max	Unit	SpecID
M5	TX_CLK rising edge to TXD[3:0], TX_EN, TX_ER Delay	0	25	ns	A9.5
M6	TX_CLK pulse width high	35%	65%	TX_CLK Period <sup>1</sup>	A9.6
M7	TX_CLK pulse width low	35%	65%	TX_CLK Period <sup>1</sup>	A9.7



# Freescale Semiconductor, Inc.

## Electrical and Thermal Characteristics

- 1 the TX\_CLK frequency shall be 25% of the nominal transmit frequency, e.g., a PHY operating at 100 Mb/s must provide a TX\_CLK frequency of 25 MHz and a PHY operating at 10 Mb/s must provide a TX\_CLK frequency of 2.5 MHz. See the IEEE 802.3 Specification [6].

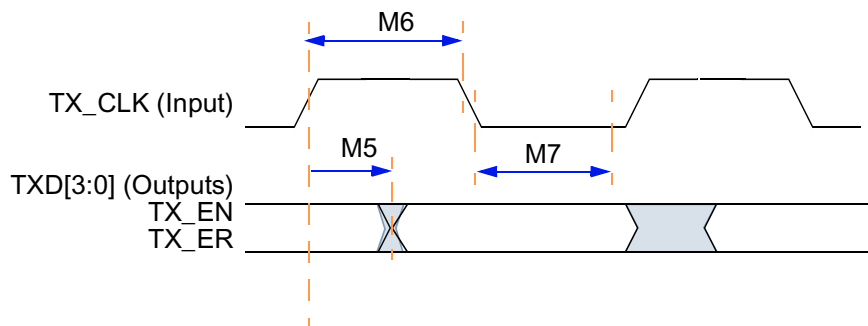


Figure 27 Ethernet Timing Diagram—MII Tx Signal

Table 32 MII Async Signal Timing

Sym	Description	Min	Max	Unit	SpecID
M8	CRS, COL minimum pulse width	1.5	—	TX_CLK Period	A9.8

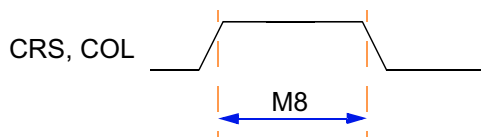


Figure 28 Ethernet Timing Diagram—MII Async

Table 33 MII Serial Management Channel Signal Timing

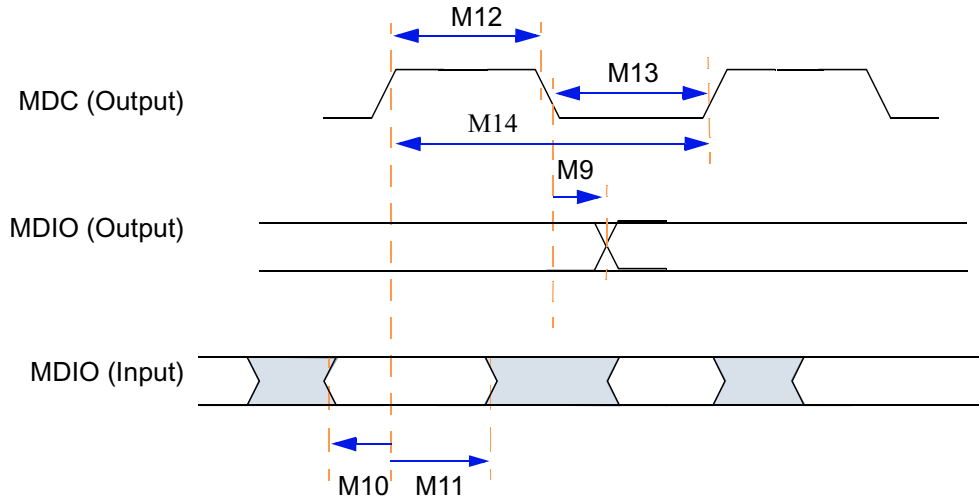
Sym	Description	Min	Max	Unit	SpecID
M9	MDC falling edge to MDIO output delay	0	25	ns	A9.9
M10	MDIO (input) to MDC rising edge setup	10	—	ns	A9.10
M11	MDIO (input) to MDC rising edge hold	10	—	ns	A9.11
M12	MDC pulse width high <sup>1</sup>	160	—	ns	A9.12
M13	MDC pulse width low <sup>1</sup>	160	—	ns	A9.13
M14	MDC period <sup>2</sup>	400	—	ns	A9.14

- 1 MDC is generated by MPC5200 with a duty cycle of 50% except when MII\_SPEED in the FEC MII\_SPEED control register is changed during operation. See the MPC5200 User Manual [1].

# Freescale Semiconductor, Inc.

## Electrical and Thermal Characteristics

- The MDC period must be set to a value of less than or equal to 2.5 MHz (to be compliant with the IEEE MII characteristic) by programming the FEC MII\_SPEED control register. See the MPC5200 User Manual [1].



**Figure 29 Ethernet Timing Diagram—MII Serial Management**

### 3.3.10 USB

**Table 34 Timing Specifications—USB Output Line**

Sym	Description	Min	Max	Units	SpecID
1	USB Bit width <sup>1</sup>	83.3	667	ns	A10.1
2	Transceiver enable time	83.3	667	ns	A10.2
3	Signal falling time	—	7.9	ns	A10.3
4	Signal rising time	—	7.9	ns	A10.4

<sup>1</sup> Defined in the USB config register, (12 Mbit/s or 1.5 Mbit/s mode).

**NOTE:**

Output timing was specified at a nominal 50 pF load.

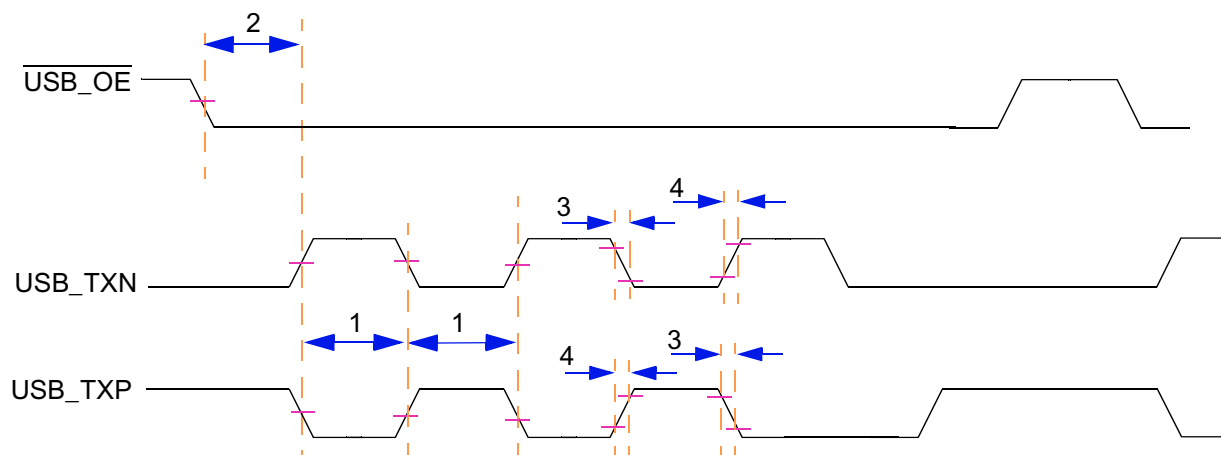


Figure 30 Timing Diagram—USB Output Line

### 3.3.11 SPI

Table 35 Timing Specifications — SPI Master Mode, Format 0 (CPHA = 0)

Sym	Description	Min	Max	Units	SpecID
1	Cycle time	4	1024	IP-Bus Cycle <sup>1</sup>	A11.1
2	Clock high or low time	2	512	IP-Bus Cycle <sup>1</sup>	A11.2
3	Slave select clock delay	15.0	—	ns	A11.3
4	Output Data valid after Slave Select ( $\overline{SS}$ )	—	20.0	ns	A11.4
5	Output Data valid after SCK	—	20.0	ns	A11.5
6	Input Data setup time	20.0	—	ns	A11.6
7	Input Data hold time	20.0	—	ns	A11.7
8	Slave disable lag time	15.0	—	ns	A11.8
9	Sequential transfer delay	1	—	IP-Bus Cycle <sup>1</sup>	A11.9
10	Clock falling time	—	7.9	ns	A11.10
11	Clock rising time	—	7.9	ns	A11.11

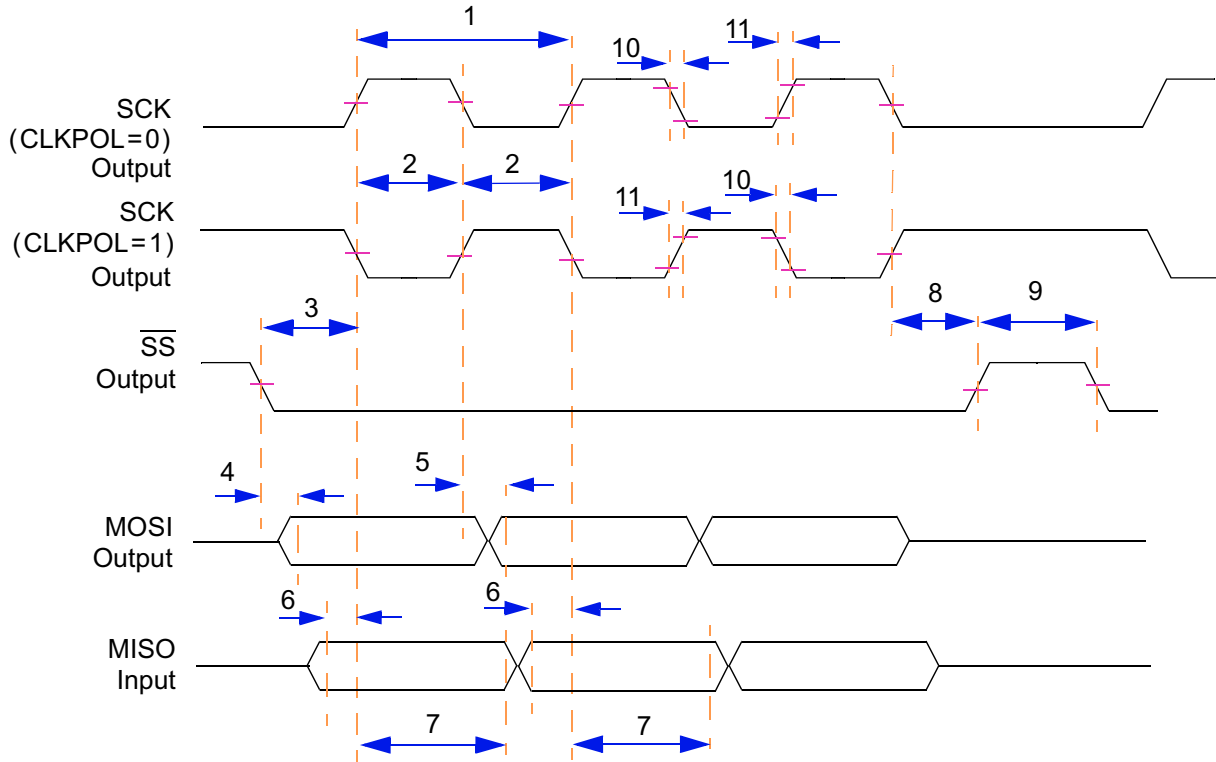
<sup>1</sup> Inter Peripheral Clock is defined in the MPC5200 User Manual [1].

**NOTE:**

Output timing was specified at a nominal 50 pF load.

# Freescale Semiconductor, Inc.

## Electrical and Thermal Characteristics



**Figure 31 Timing Diagram — SPI Master Mode, Format 0 (CPHA = 0)**

**Table 36 Timing Specifications — SPI Slave Mode, Format 0 (CPHA = 0)**

Sym	Description	Min	Max	Units	SpecID
1	Cycle time	4	1024	IP-Bus Cycle <sup>1</sup>	A11.12
2	Clock high or low time	2	512	IP-Bus Cycle <sup>1</sup>	A11.13
3	Slave select clock delay	15.0	—	ns	A11.14
4	Output Data valid after Slave Select ( $\overline{SS}$ )	—	50.0	ns	A11.15
5	Output Data valid after SCK	—	50.0	ns	A11.16
6	Input Data setup time	50.0	—	ns	A11.17
7	Input Data hold time	0.0	—	ns	A11.18
8	Slave disable lag time	15.0	—	ns	A11.19
9	Sequential Transfer delay	1	—	IP-Bus Cycle <sup>1</sup>	A11.20

<sup>1</sup> Inter Peripheral Clock is defined in the MPC5200 User Manual [1].

**NOTE:**

Output timing was specified at a nominal 50 pF load.

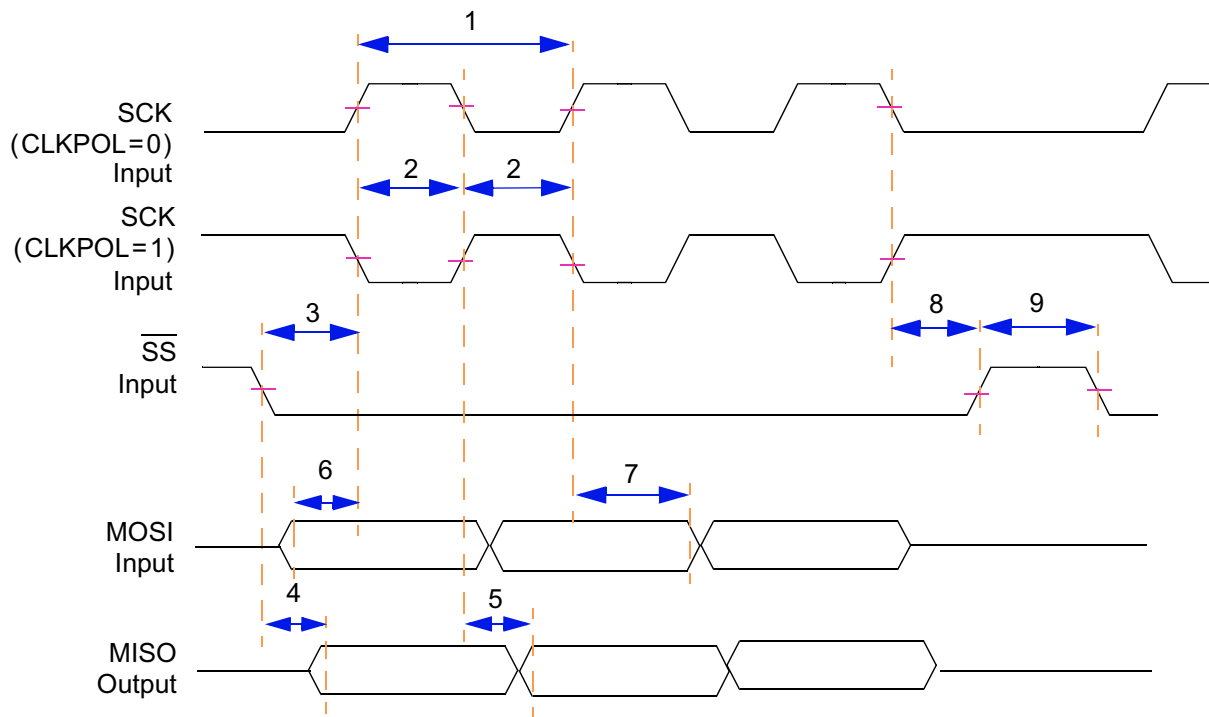


Figure 32 Timing Diagram — SPI Slave Mode, Format 0 (CPHA = 0)

Table 37 Timing Specifications — SPI Master Mode, Format 1 (CPHA = 1)

Sym	Description	Min	Max	Units	SpecID
1	Cycle time	4	1024	IP-Bus Cycle <sup>1</sup>	A11.21
2	Clock high or low time	2	512	IP-Bus Cycle <sup>1</sup>	A11.22
3	Slave select clock delay	15.0	—	ns	A11.23
4	Output data valid	—	20.0	ns	A11.24
5	Input Data setup time	20.0	—	ns	A11.25
6	Input Data hold time	20.0	—	ns	A11.26
7	Slave disable lag time	15.0	—	ns	A11.27
8	Sequential Transfer delay	1	—	IP-Bus Cycle <sup>1</sup>	A11.28
9	Clock falling time	—	7.9	ns	A11.29
10	Clock rising time	—	7.9	ns	A11.30

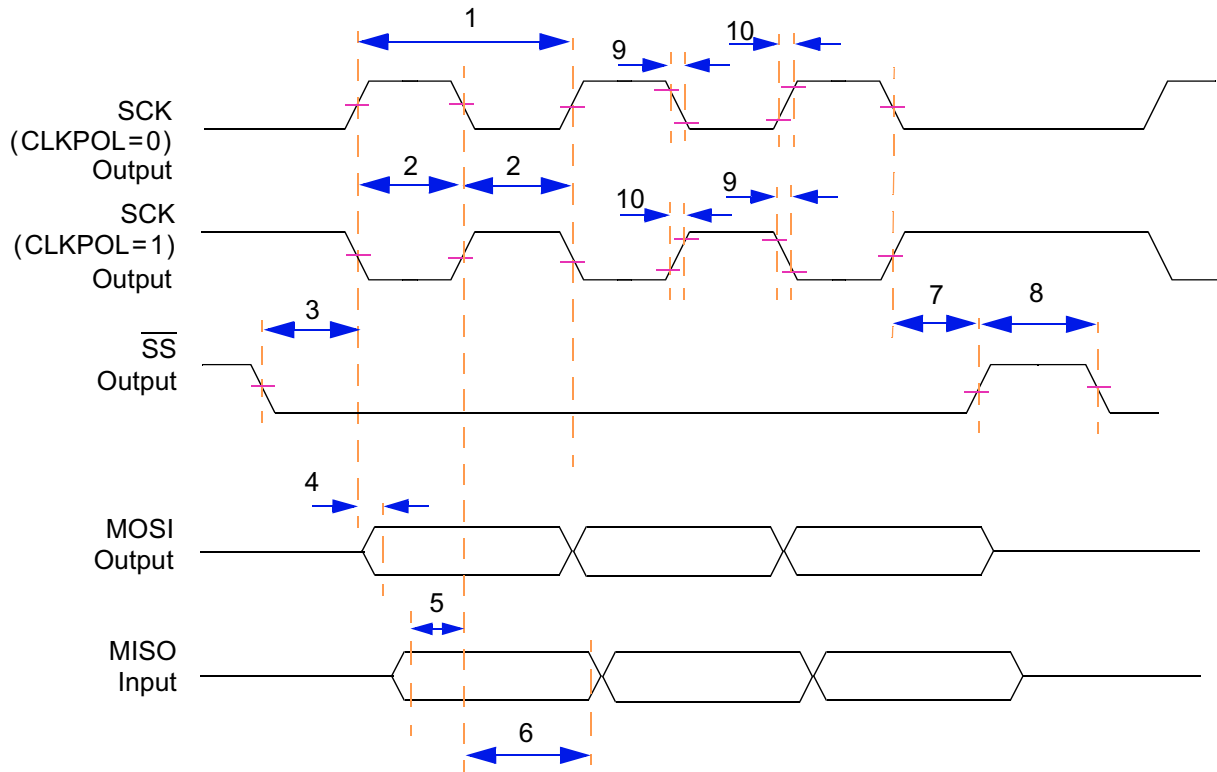
1 Inter Peripheral Clock is defined in the MPC5200 User Manual [1].

**NOTE:**

Output timing was specified at a nominal 50 pF load.

# Freescale Semiconductor, Inc.

## Electrical and Thermal Characteristics



**Figure 33 Timing Diagram — SPI Master Mode, Format 1 (CPHA = 1)**

**Table 38 Timing Specifications — SPI Slave Mode, Format 1 (CPHA = 1)**

Sym	Description	Min	Max	Units	SpecID
1	Cycle time	4	1024	IP-Bus Cycle <sup>1</sup>	A11.31
2	Clock high or low time	2	512	IP-Bus Cycle <sup>1</sup>	A11.32
3	Slave select clock delay	15.0	—	ns	A11.33
4	Output data valid	—	50.0	ns	A11.34
5	Input Data setup time	50.0	—	ns	A11.35
6	Input Data hold time	0.0	—	ns	A11.36
7	Slave disable lag time	15.0	—	ns	A11.37
8	Sequential Transfer delay	1	—	IP-Bus Cycle <sup>1</sup>	A11.38

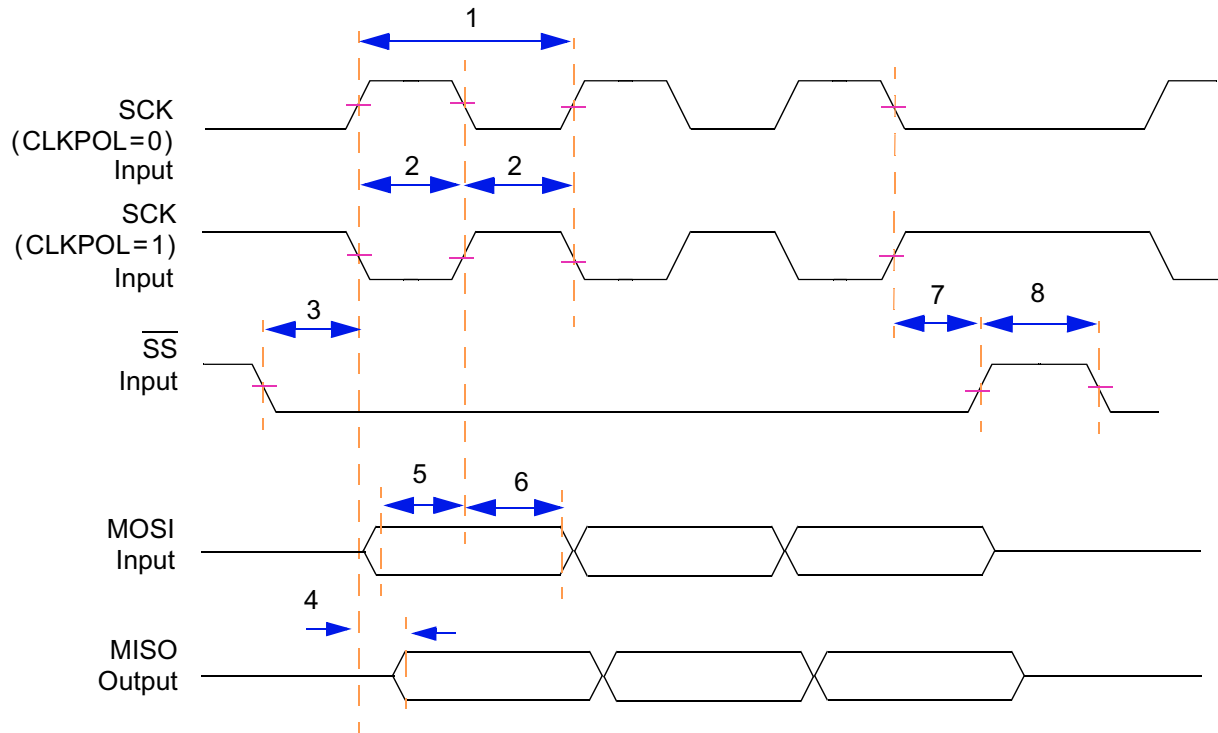
<sup>1</sup> Inter Peripheral Clock is defined in the MPC5200 User Manual [1].

**NOTE:**

Output timing was specified at a nominal 50 pF load.

# Freescale Semiconductor, Inc.

## Electrical and Thermal Characteristics



**Figure 34 Timing Diagram — SPI Slave Mode, Format 1 (CPHA = 1)**

# Freescale Semiconductor, Inc.

## Electrical and Thermal Characteristics

### 3.3.12 MSCAN

The CAN functions are available as RX and TX pins at normal IO pads (I<sup>2</sup>C1+GPTimer or PSC2). There is no filter for the WakeUp dominant pulse. Any High-to-Low edge can cause WakeUp, if configured.

### 3.3.13 I<sup>2</sup>C

**Table 39 I<sup>2</sup>C Input Timing Specifications—SCL and SDA**

Sym	Description	Min	Max	Units	SpecID
1	Start condition hold time	2	—	IP-Bus Cycle <sup>1</sup>	A13.1
2	Clock low period	8	—	IP-Bus Cycle <sup>1</sup>	A13.2
4	Data hold time	0.0	—	ns	A13.3
6	Clock high time	4	—	IP-Bus Cycle <sup>1</sup>	A13.4
7	Data setup time	0.0	—	ns	A13.5
8	Start condition setup time (for repeated start condition only)	2	—	IP-Bus Cycle <sup>1</sup>	A13.6
9	Stop condition setup time	2	—	IP-Bus Cycle <sup>1</sup>	A13.7

<sup>1</sup> Inter Peripheral Clock is defined in the MPC5200 User Manual [1].

**Table 40 I<sup>2</sup>C Output Timing Specifications—SCL and SDA**

Sym	Description	Min	Max	Units	SpecID
1 <sup>1</sup>	Start condition hold time	6	—	IP-Bus Cycle <sup>3</sup>	A13.8
2 <sup>1</sup>	Clock low period	10	—	IP-Bus Cycle <sup>3</sup>	A13.9
3 <sup>2</sup>	SCL/SDA rise time	—	7.9	ns	A13.10
4 <sup>1</sup>	Data hold time	7	—	IP-Bus Cycle <sup>3</sup>	A13.11
5 <sup>1</sup>	SCL/SDA fall time	—	7.9	ns	A13.12
6 <sup>1</sup>	Clock high time	10	—	IP-Bus Cycle <sup>3</sup>	A13.13
7 <sup>1</sup>	Data setup time	2	—	IP-Bus Cycle <sup>3</sup>	A13.14
8 <sup>1</sup>	Start condition setup time (for repeated start condition only)	20	—	IP-Bus Cycle <sup>3</sup>	A13.15
9 <sup>1</sup>	Stop condition setup time	10	—	IP-Bus Cycle <sup>3</sup>	A13.16



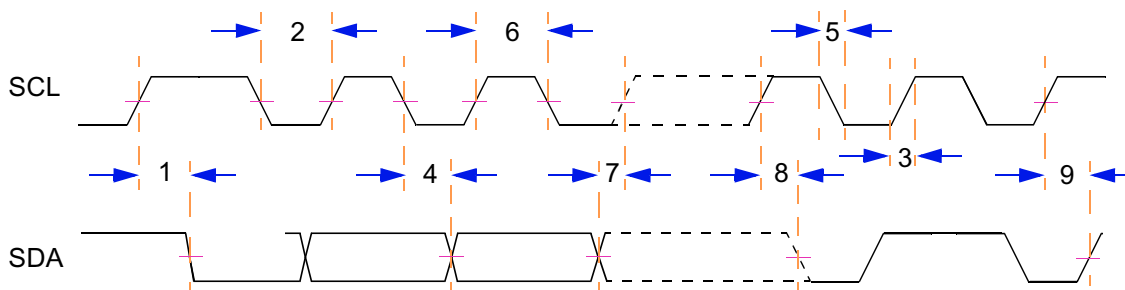
# Freescale Semiconductor, Inc.

## Electrical and Thermal Characteristics

- 1 Programming IFDR with the maximum frequency (IFDR=0x20) results in the minimum output timings listed. The I<sup>2</sup>C interface is designed to scale the data transition time, moving it to the middle of the SCL low period. The actual position is affected by the prescale and division values programmed in IFDR.
- 2 Because SCL and SDA are open-drain-type outputs, which the processor can only actively drive low, the time SCL or SDA takes to reach a high level depends on external signal capacitance and pull-up resistor values
- 3 Inter Peripheral Clock is defined in the MPC5200 User Manual [1].

**NOTE:**

Output timing was specified at a nominal 50 pF load.



**Figure 35 Timing Diagram—I<sup>2</sup>C Input/Output**

### 3.3.14 J1850

See the MPC5200 User Manual [1].

### 3.3.15 PSC

#### 3.3.15.1 Codec Mode (8,16,24 and 32-bit) / I<sup>2</sup>S Mode

**Table 41 Timing Specifications—8,16, 24 and 32-bit CODEC / I<sup>2</sup>S Master Mode**

Sym	Description	Min	Typ	Max	Units	SpecID
1	Bit Clock cycle time, programmed in CCS register	40.0	—	—	ns	A15.1
2	Clock pulse width	—	50	—	% <sup>1</sup>	A15.2
3	Bit Clock fall time	—	—	7.9	ns	A15.3
4	Bit Clock rise time	—	—	7.9	ns	A15.4
5	FrameSync valid after clock edge	—	—	8.4	ns	A15.5
6	FrameSync invalid after clock edge	—	—	8.4	ns	A15.6
7	Output Data valid after clock edge	—	—	9.3	ns	A15.7
8	Input Data setup time	6.0	—	—	ns	A15.8

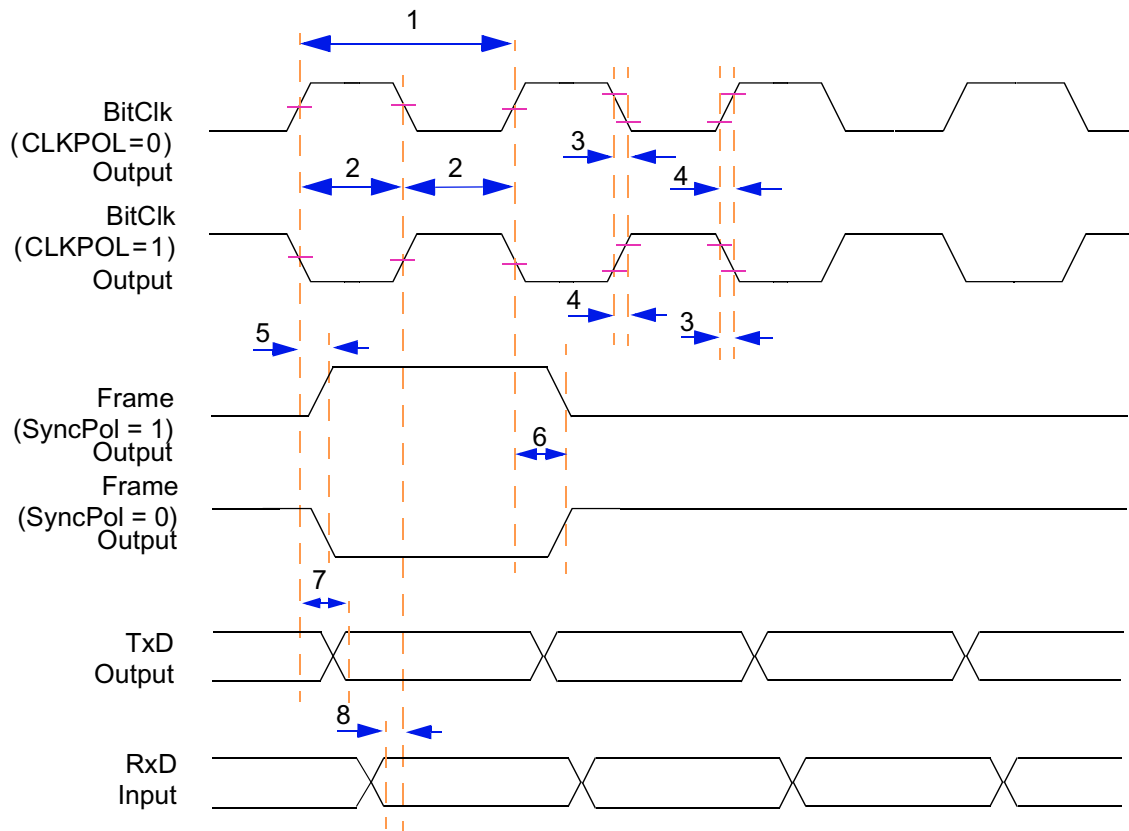
1 Bit Clock cycle time

**NOTE:**

Output timing was specified at a nominal 50 pF load.

# Freescale Semiconductor, Inc.

## Electrical and Thermal Characteristics



**Figure 36 Timing Diagram — 8,16, 24, and 32-bit CODEC / I<sup>2</sup>S Master Mode**

**Table 42 Timing Specifications — 8,16, 24, and 32-bit CODEC / I<sup>2</sup>S Slave Mode**

Sym	Description	Min	Typ	Max	Units	SpecID
1	Bit Clock cycle time	40.0	—	—	ns	A15.9
2	Clock pulse width	—	50	—	% <sup>1</sup>	A15.10
3	FrameSync setup time	1.0	—	—	ns	A15.11
4	Output Data valid after clock edge	—	—	14.0	ns	A15.12
5	Input Data setup time	1.0	—	—	ns	A15.13
6	Input Data hold time	1.0	—	—	ns	A15.14

<sup>1</sup> Bit Clock cycle time

**NOTE:**

Output timing was specified at a nominal 50 pF load.

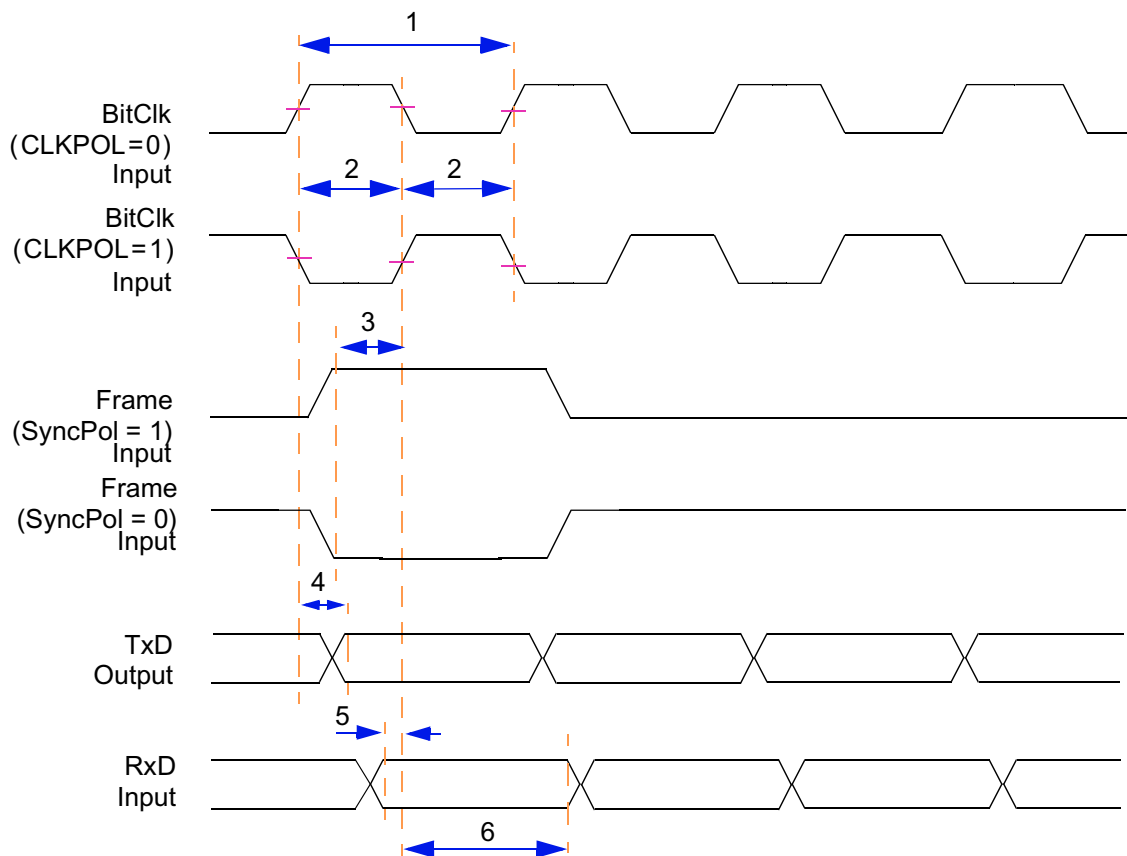


Figure 37 Timing Diagram — 8,16, 24, and 32-bit CODEC / I<sup>2</sup>S Slave Mode

3.3.15.2 AC97 Mode

Table 43 Timing Specifications — AC97 Mode

Sym	Description	Min	Typ	Max	Units	SpecID
1	Bit Clock cycle time	—	81.4	—	ns	A15.15
2	Clock pulse high time	—	40.7	—	ns	A15.16
3	Clock pulse low time	—	40.7	—	ns	A15.17
4	Frame valid after rising clock edge	—	—	13.0	ns	A15.18
5	Output Data valid after rising clock edge	—	—	14.0	ns	A15.19
6	Input Data setup time	1.0	—	—	ns	A15.20
7	Input Data hold time	1.0	—	—	ns	A15.21

**NOTE:**

Output timing was specified at a nominal 50 pF load.

# Freescale Semiconductor, Inc.

## Electrical and Thermal Characteristics

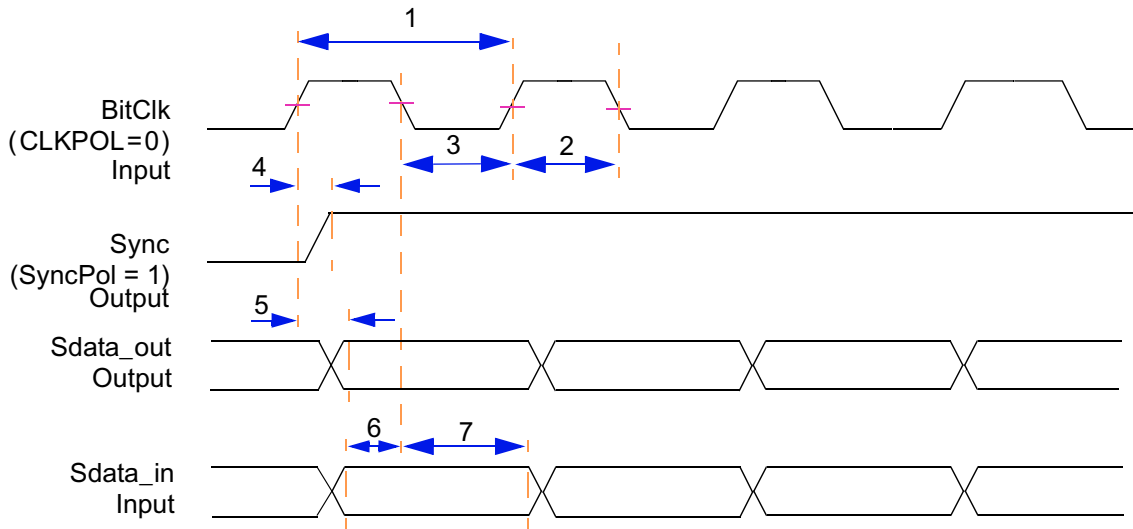


Figure 38 Timing Diagram — AC97 Mode

### 3.3.15.3 IrDA Mode

Table 44 Timing Specifications — IrDA Transmit Line

Sym	Description	Min	Max	Units	SpecID
1	Pulse high time, defined in the IrDA protocol definition	0.125	10000	$\mu$ s	A15.22
2	Pulse low time, defined in the IrDA protocol definition	0.125	10000	$\mu$ s	A15.23
3	Transmitter rising time	—	7.9	ns	A15.24
4	Transmitter falling time	—	7.9	ns	A15.25

**NOTE:**

Output timing was specified at a nominal 50 pF load.

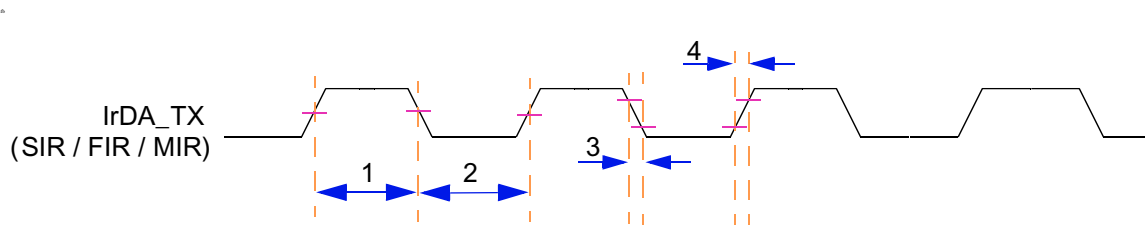


Figure 39 Timing Diagram — IrDA Transmit Line

# Freescale Semiconductor, Inc.

## Electrical and Thermal Characteristics

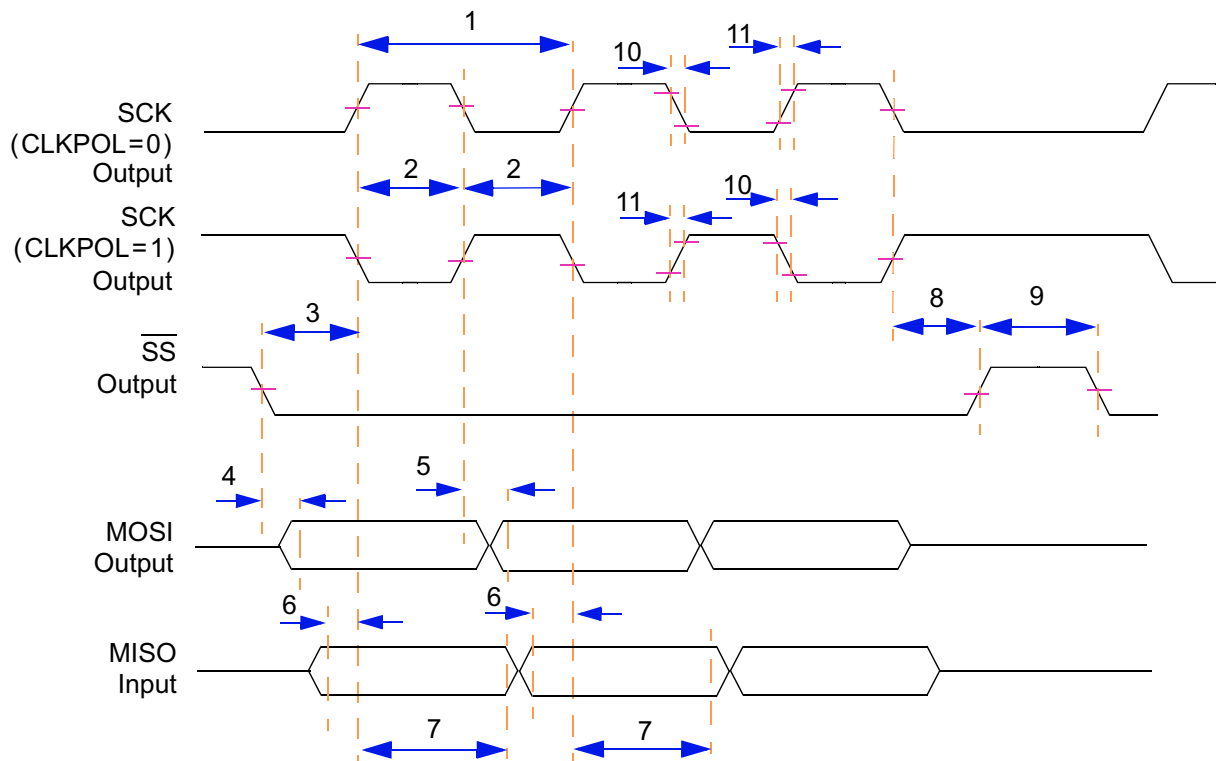
### 3.3.15.4 SPI Mode

**Table 45 Timing Specifications — SPI Master Mode, Format 0 (CPHA = 0)**

Sym	Description	Min	Max	Units	SpecID
1	SCK cycle time, programmable in the PSC CCS register	30.0	—	ns	A15.26
2	SCK pulse width, 50% SCK cycle time	15.0	—	ns	A15.27
3	Slave select clock delay, programmable in the PSC CCS register	30.0	—	ns	A15.28
4	Output Data valid after Slave Select ( $\overline{SS}$ )	—	8.9	ns	A15.29
5	Output Data valid after SCK	—	8.9	ns	A15.30
6	Input Data setup time	6.0	—	ns	A15.31
7	Input Data hold time	1.0	—	ns	A15.32
8	Slave disable lag time	—	8.9	ns	A15.33
9	Sequential Transfer delay, programmable in the PSC CTUR / CTLR register	15.0	—	ns	A15.34
10	Clock falling time	—	7.9	ns	A15.35
11	Clock rising time	—	7.9	ns	A15.36

**NOTE:**

Output timing was specified at a nominal 50 pF load.



**Figure 40 Timing Diagram — SPI Master Mode, Format 0 (CPHA = 0)**

# Freescale Semiconductor, Inc.

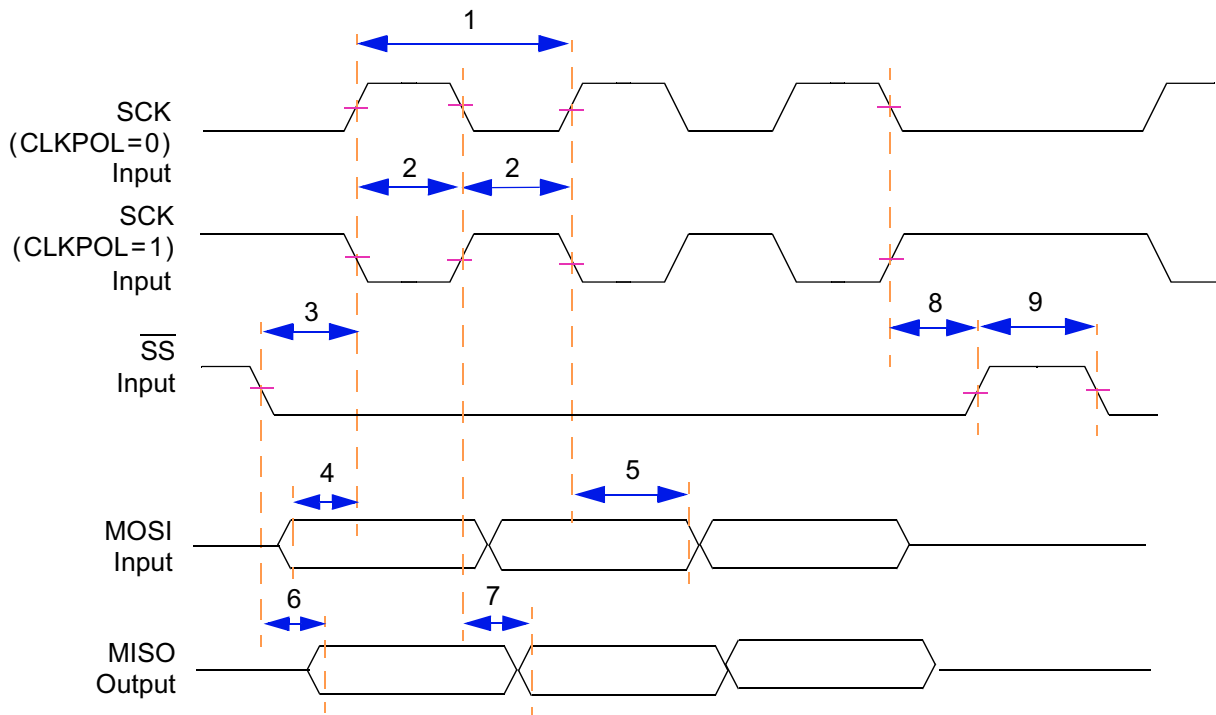
## Electrical and Thermal Characteristics

**Table 46 Timing Specifications — SPI Slave Mode, Format 0 (CPHA = 0)**

Sym	Description	Min	Max	Units	SpecID
1	SCK cycle time, programable in the PSC CCS register	30.0	—	ns	A15.37
2	SCK pulse width, 50% SCK cycle time	15.0	—	ns	A15.38
3	Slave select clock delay	1.0	—	ns	A15.39
4	Input Data setup time	1.0	—	ns	A15.40
5	Input Data hold time	1.0	—	ns	A15.41
6	Output data valid after $\overline{SS}$	—	14.0	ns	A15.42
7	Output data valid after SCK	—	14.0	ns	A15.43
8	Slave disable lag time	0.0	—	ns	A15.44
9	Minimum Sequential Transfer delay = 2 * IP Bus clock cycle time	30.0	—	—	A15.45

**NOTE:**

Output timing was specified at a nominal 50 pF load.



**Figure 41 Timing Diagram — SPI Slave Mode, Format 0 (CPHA = 0)**

# Freescale Semiconductor, Inc.

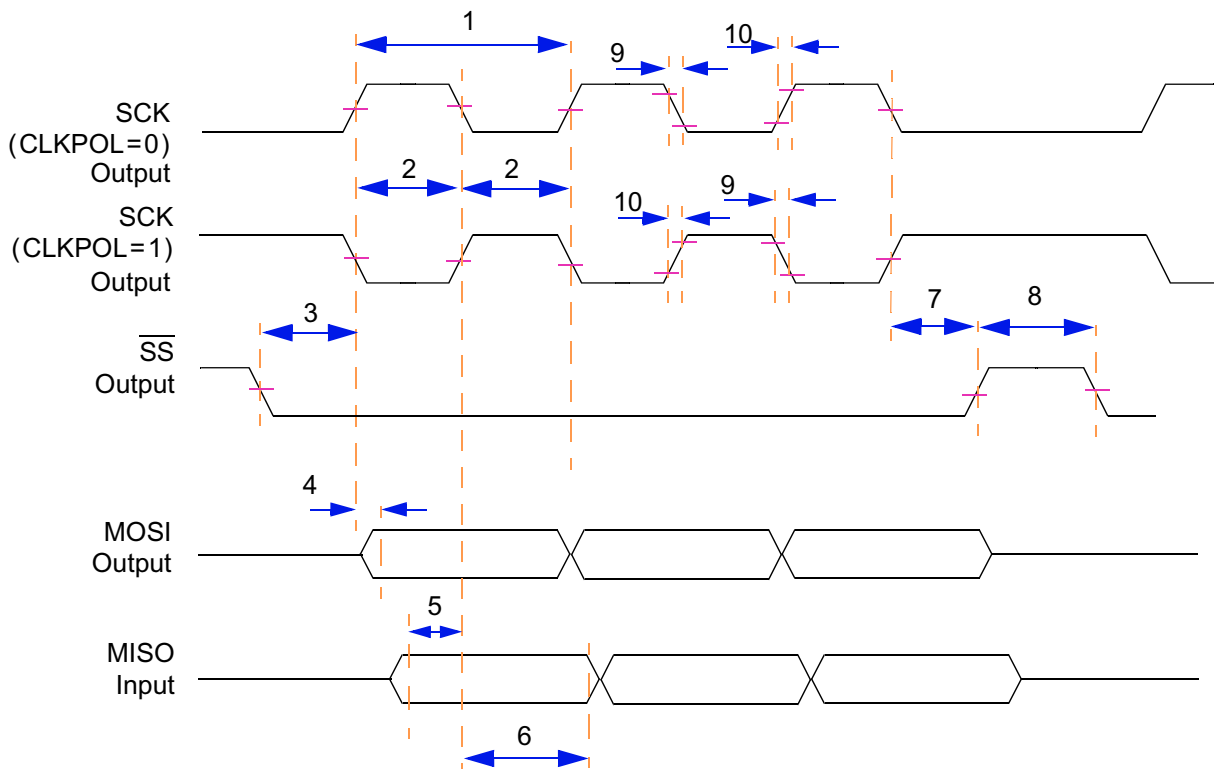
## Electrical and Thermal Characteristics

**Table 47 Timing Specifications — SPI Master Mode, Format 1 (CPHA = 1)**

Sym	Description	Min	Max	Units	SpecID
1	SCK cycle time, programable in the PSC CCS register	30.0	—	ns	A15.46
2	SCK pulse width, 50% SCK cycle time	15.0	—	ns	A15.47
3	Slave select clock delay, programable in the PSC CCS register	30.0	—	ns	A15.48
4	Output data valid	—	8.9	ns	A15.49
5	Input Data setup time	6.0	—	ns	A15.50
6	Input Data hold time	1.0	—	ns	A15.51
7	Slave disable lag time	—	8.9	ns	A15.52
8	Sequential Transfer delay, programable in the PSC CTUR / CTLR register	15.0	—	ns	A15.53
9	Clock falling time	—	7.9	ns	A15.54
10	Clock rising time	—	7.9	ns	A15.55

**NOTE:**

Output timing was specified at a nominal 50 pF load.



**Figure 42 Timing Diagram — SPI Master Mode, Format 1 (CPHA = 1)**

# Freescale Semiconductor, Inc.

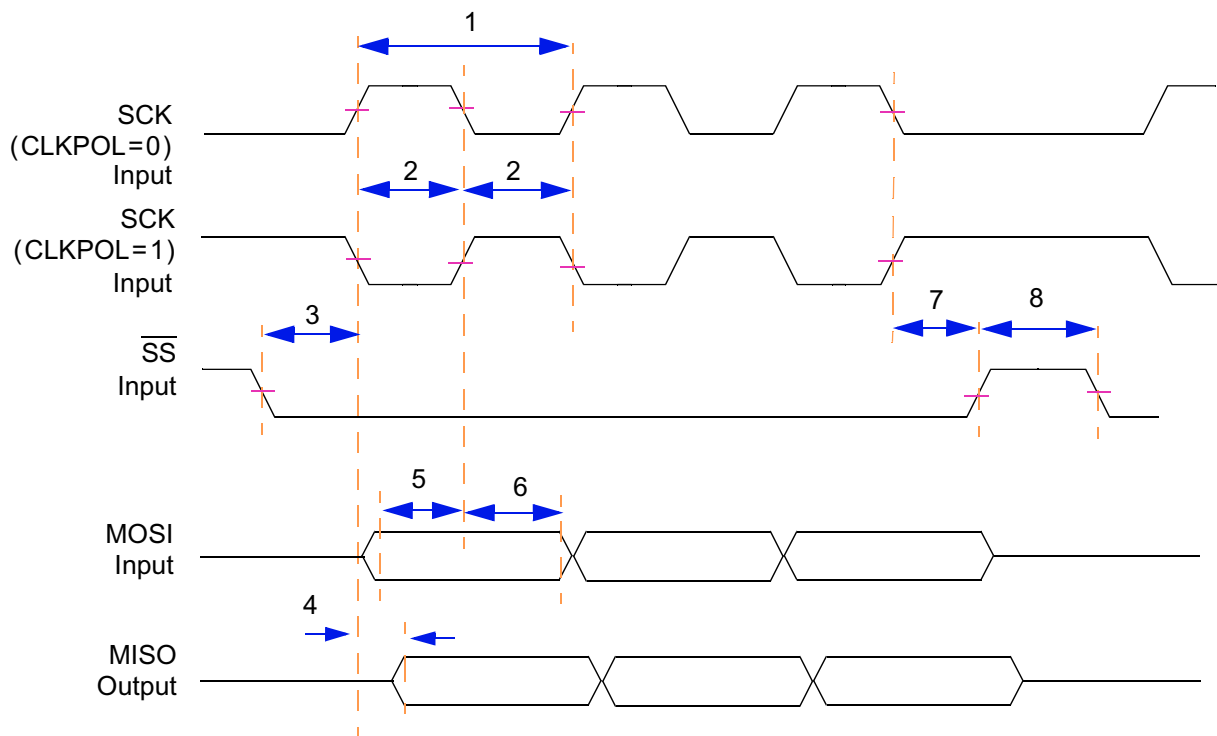
## Electrical and Thermal Characteristics

**Table 48 Timing Specifications — SPI Slave Mode, Format 1 (CPHA = 1)**

Sym	Description	Min	Max	Units	SpecID
1	SCK cycle time, programable in the PSC CCS register	30.0	—	ns	A15.56
2	SCK pulse width, 50% SCK cycle time	15.0	—	ns	A15.57
3	Slave select clock delay	0.0	—	ns	A15.58
4	Output data valid	—	14.0	ns	A15.59
5	Input Data setup time	2.0	—	ns	A15.60
6	Input Data hold time	1.0	—	ns	A15.61
7	Slave disable lag time	0.0	—	ns	A15.62
8	Minimum Sequential Transfer delay = 2 * IP-Bus clock cycle time	30.0	—	ns	A15.63

**NOTE:**

Output timing was specified at a nominal 50 pF load.



**Figure 43 Timing Diagram — SPI Slave Mode, Format 1 (CPHA = 1)**



# Freescale Semiconductor, Inc.

## Electrical and Thermal Characteristics

### 3.3.16 GPIOs and Timers

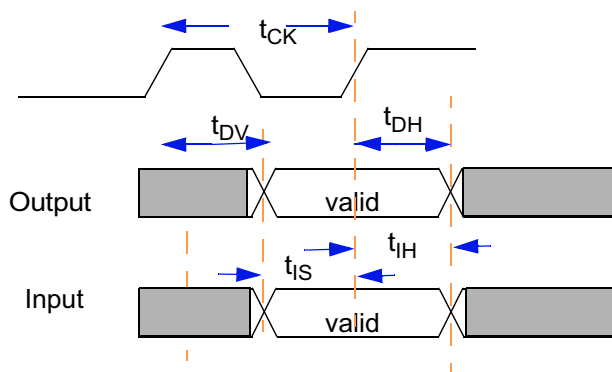
#### 3.3.16.1 General and Asynchronous Signals

The MPC5200 contains several sets of I/Os that do not require special setup, hold, or valid requirements. Most of these are asynchronous to the system clock. The following numbers are provided for test and validation purposes only, and they assume a 133 MHz internal bus frequency.

Figure 44 shows the GPIO Timing Diagram. Table 49 gives the timing specifications.

**Table 49 Asynchronous Signals**

Sym	Description	Min	Max	Units	SpecID
$t_{CK}$	Clock Period	7.52	—	ns	A16.1
$t_{IS}$	Input Setup for Async Signal	12	—	ns	A16.2
$t_{IH}$	Input Hold for Async Signals	1	—	ns	A16.3
$t_{DV}$	Output Valid	—	15.33	ns	A16.4
$t_{DH}$	Output Hold	1	—	ns	A16.5



**Figure 44 Timing Diagram—Asynchronous Signals**

### 3.3.17 IEEE 1149.1 (JTAG) AC Specifications

**Table 50 JTAG Timing Specification**

Sym	Characteristic	Min	Max	Unit	SpecID
—	TCK frequency of operation.	0	25	MHz	A17.1
1	TCK cycle time.	40	—	ns	A17.2
2	TCK clock pulse width measured at 1.5V.	1.08	—	ns	A17.3
3	TCK rise and fall times.	0	3	ns	A17.4

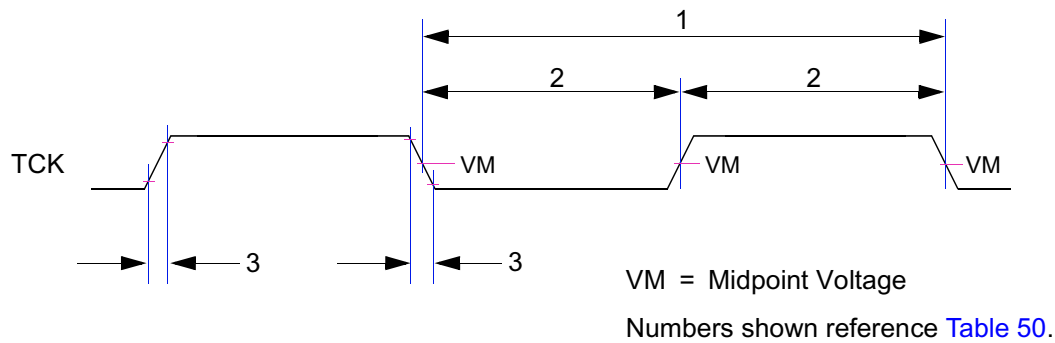
# Freescale Semiconductor, Inc.

## Electrical and Thermal Characteristics

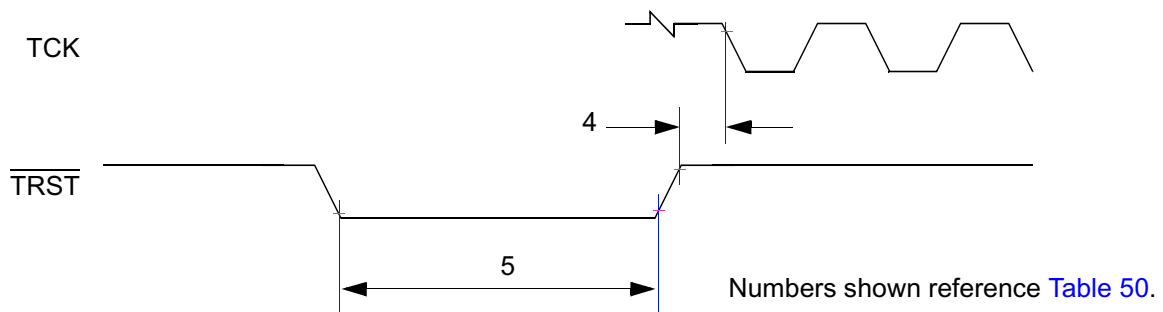
**Table 50 JTAG Timing Specification (continued)**

Sym	Characteristic	Min	Max	Unit	SpecID
4	TRST setup time to tck falling edge <sup>1</sup> .	10	—	ns	A17.5
5	$\overline{\text{TRST}}$ assert time.	5	—	ns	A17.6
6	Input data setup time <sup>2</sup> .	5	—	ns	A17.7
7	Input data hold time <sup>2</sup> .	15	—	ns	A17.8
8	TCK to output data valid <sup>3</sup> .	0	30	ns	A17.9
9	TCK to output high impedance <sup>3</sup> .	0	30	ns	A17.10
10	TMS, TDI data setup time.	5	—	ns	A17.11
11	TMS, TDI data hold time.	1	—	ns	A17.12
12	TCK to TDO data valid.	0	15	ns	A17.13
13	TCK to TDO high impedance.	0	15	ns	A17.14

- 1  $\overline{\text{TRST}}$  is an asynchronous signal. The setup time is for test purposes only.
- 2 Non-test, other than TDI and TMS, signal input timing with respect to TCK.
- 3 Non-test, other than TDO, signal output timing with respect to TCK.



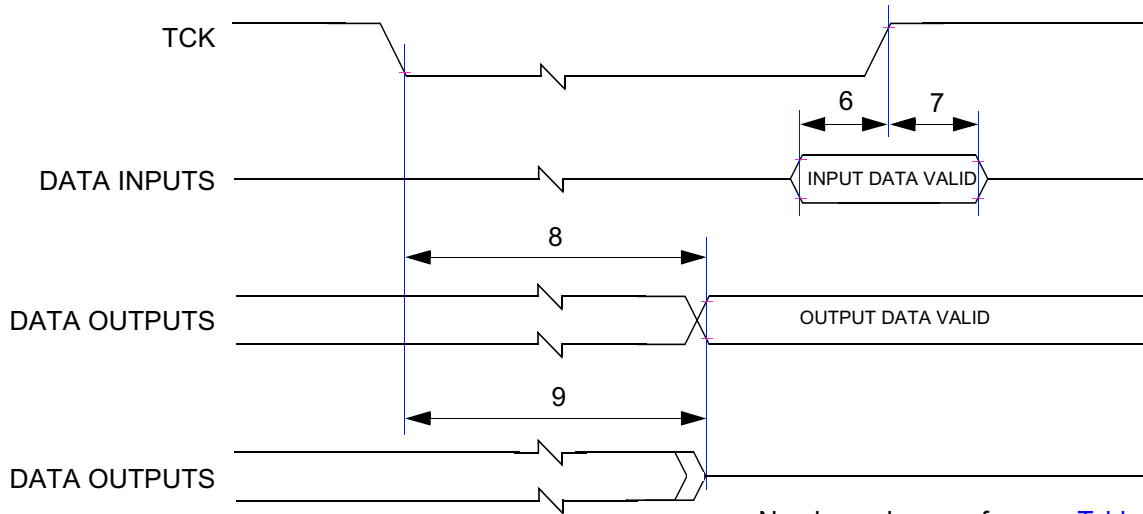
**Figure 45 Timing Diagram—JTAG Clock Input**



**Figure 46 Timing Diagram—JTAG TRST**

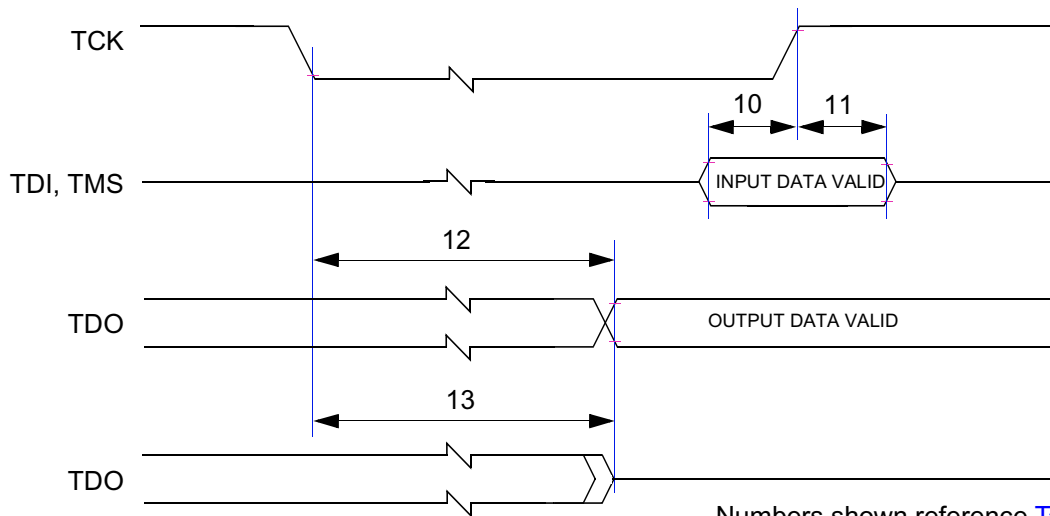
# Freescale Semiconductor, Inc.

## Electrical and Thermal Characteristics



Numbers shown reference [Table 50](#).

**Figure 47 Timing Diagram—JTAG Boundary Scan**



Numbers shown reference [Table 50](#).

**Figure 48 Timing Diagram—Test Access Port**

# Freescale Semiconductor, Inc.

## Package Description

### 4 Package Description

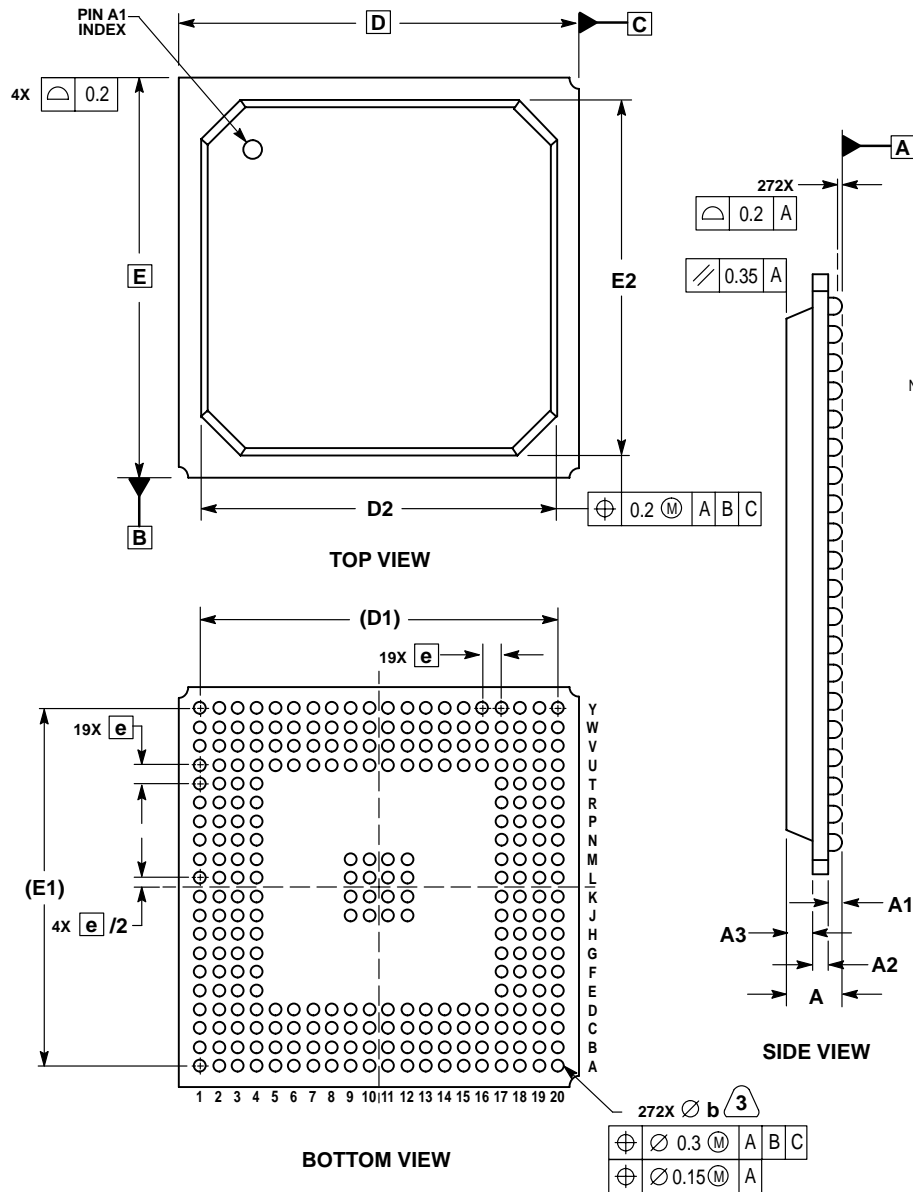
#### 4.1 Package Parameters

The MPC5200 uses a 27 mm x 27 mm TE-PBGA package. The package parameters are as provided in the following list:

- Package outline 27 mm x 27 mm
- Interconnects 272
- Pitch 1.27 mm

#### 4.2 Mechanical Dimensions

[Figure 49](#) provides the mechanical dimensions, top surface, side profile, and pinout for the MPC5200, 272 TE-PBGA package.



- NOTES:
1. DIMENSIONS AND TOLERANCING PER ASME Y14.5M, 1994.
  2. DIMENSIONS IN MILLIMETERS.
  3. DIMENSION IS MEASURED AT THE MAXIMUM SOLDER BALL DIAMETER PARALLEL TO PRIMARY DATUM A.
  4. PRIMARY DATUM A AND THE SEATING PLANE ARE DEFINED BY THE SPHERICAL CROWNS OF THE SOLDER BALLS.

MILLIMETERS		
DIM	MIN	MAX
A	2.05	2.65
A1	0.50	0.70
A2	0.50	0.70
A3	1.05	1.25
b	0.60	0.90
D	27.00	BSC
D1	24.13	REF
D2	23.30	24.70
E	27.00	BSC
E1	24.13	REF
E2	23.30	24.70
e	1.27	BSC

CASE 1135A-01  
ISSUE B

Figure 49 Mechanical Dimensions and Pinout Assignments for the MPC5200, 272 TE-PBGA

# Freescale Semiconductor, Inc.

## Package Description

### 5.3 Pinout Listings

See details in the MPC5200 User Manual [1].

**Table 51 MPC5200 Pinout Listing**

Name	Alias	Type	Power Supply	Output Driver Type	Input Type	Pull-up/down
<b>SDRAM</b>						
MEM_CAS	CAS	I/O	VDD_MEM_IO	DRV16_MEM	TTL	
MEM_CLK_EN	CLK_EN	I/O	VDD_MEM_IO	DRV16_MEM	TTL	
MEM_CS		I/O	VDD_MEM_IO	DRV16_MEM	TTL	
MEM_DQM[3:0]	DQM	I/O	VDD_MEM_IO	DRV16_MEM	TTL	
MEM_MA[12:0]	MA	I/O	VDD_MEM_IO	DRV16_MEM	TTL	
MEM_MBA[1:0]	MBA	I/O	VDD_MEM_IO	DRV16_MEM	TTL	
MEM_MDQS[3:0]	MDQS	I/O	VDD_MEM_IO	DRV16_MEM	TTL	
MEM_MDQ[31:0]	MDQ	I/O	VDD_MEM_IO	DRV16_MEM	TTL	
MEM_CLK		I/O	VDD_MEM_IO	DRV16_MEM	TTL	
MEM_CLK		I/O	VDD_MEM_IO	DRV16_MEM	TTL	
MEM_RAS	RAS	I/O	VDD_MEM_IO	DRV16_MEM	TTL	
MEM_WE		I/O	VDD_MEM_IO	DRV16_MEM	TTL	
<b>PCI</b>						
EXT_AD[31:0]		I/O	VDD_IO	PCI	PCI	
PCI_CBE_0		I/O	VDD_IO	PCI	PCI	
PCI_CBE_1		I/O	VDD_IO	PCI	PCI	
PCI_CBE_2		I/O	VDD_IO	PCI	PCI	
PCI_CBE_3		I/O	VDD_IO	PCI	PCI	
PCI_CLOCK		I/O	VDD_IO	PCI	PCI	
PCI_DEVSEL		I/O	VDD_IO	PCI	PCI	
PCI_FRAME		I/O	VDD_IO	PCI	PCI	
PCI_GNT		I/O	VDD_IO	DRV8	TTL	
PCI_IDSEL		I/O	VDD_IO	DRV8	TTL	
PCI_IRDY		I/O	VDD_IO	PCI	PCI	
PCI_PAR		I/O	VDD_IO	PCI	PCI	

**Table 51 MPC5200 Pinout Listing (continued)**

Name	Alias	Type	Power Supply	Output Driver Type	Input Type	Pull-up/down
$\overline{\text{PCI\_PERR}}$		I/O	VDD_IO	PCI	PCI	
$\overline{\text{PCI\_REQ}}$		I/O	VDD_IO	DRV8	TTL	
$\overline{\text{PCI\_RESET}}$		I/O	VDD_IO	PCI	PCI	
$\overline{\text{PCI\_SERR}}$		I/O	VDD_IO	PCI	PCI	
$\overline{\text{PCI\_STOP}}$		I/O	VDD_IO	PCI	PCI	
$\overline{\text{PCI\_TRDY}}$		I/O	VDD_IO	PCI	PCI	
<b>Local Plus</b>						
LP_ACK		I/O	VDD_IO	DRV8	TTL	PULLUP
$\overline{\text{LP\_ALE}}$		I/O	VDD_IO	DRV8	TTL	
LP_OE		I/O	VDD_IO	DRV8	TTL	
LP_RW		I/O	VDD_IO	DRV8	TTL	
$\overline{\text{LP\_TS}}$		I/O	VDD_IO	DRV8	TTL	
$\overline{\text{LP\_CS0}}$		I/O	VDD_IO	DRV8	TTL	
$\overline{\text{LP\_CS1}}$		I/O	VDD_IO	DRV8	TTL	
$\overline{\text{LP\_CS2}}$		I/O	VDD_IO	DRV8	TTL	
$\overline{\text{LP\_CS3}}$		I/O	VDD_IO	DRV8	TTL	
$\overline{\text{LP\_CS4}}$		I/O	VDD_IO	DRV8	TTL	
$\overline{\text{LP\_CS5}}$		I/O	VDD_IO	DRV8	TTL	
<b>ATA</b>						
$\overline{\text{ATA\_DACK}}$		I/O	VDD_IO	DRV8	TTL	
ATA_DRQ		I/O	VDD_IO	DRV8	TTL	PULLDOWN
ATA_INTRQ		I/O	VDD_IO	DRV8	TTL	PULLDOWN
ATA_IOCHRDY		I/O	VDD_IO	DRV8	TTL	PULLUP
$\overline{\text{ATA\_IOR}}$		I/O	VDD_IO	DRV8	TTL	
$\overline{\text{ATA\_IOW}}$		I/O	VDD_IO	DRV8	TTL	
ATA_ISOLATION		I/O	VDD_IO	DRV8	TTL	
<b>Ethernet</b>						
ETH_0	TX, TX_EN	I/O	VDD_IO	DRV4	TTL	

# Freescale Semiconductor, Inc.

## Package Description

**Table 51 MPC5200 Pinout Listing (continued)**

Name	Alias	Type	Power Supply	Output Driver Type	Input Type	Pull-up/down
ETH_1	RTS, TXD[0]	I/O	VDD_IO	DRV4	TTL	
ETH_2	USB_TXP, TX, TXD[1]	I/O	VDD_IO	DRV4	TTL	
ETH_3	USB_PRTPW, TXD[2]	I/O	VDD_IO	DRV4	TTL	
ETH_4	USB_SPEED, TXD[3]	I/O	VDD_IO	DRV4	TTL	
ETH_5	USB_SUPEND, TX_ER	I/O	VDD_IO	DRV4	TTL	
ETH_6	USB_OE, RTS, MDC	I/O	VDD_IO	DRV4	TTL	
ETH_7	TXN, MDIO	I/O	VDD_IO	DRV4	TTL	
ETH_8	RX_DV	I/O	VDD_IO	DRV4	TTL	
ETH_9	CD, RX_CLK	I/O	VDD_IO	DRV4	Schmitt	
ETH_10	CTS, COL	I/O	VDD_IO	DRV4	TTL	
ETH_11	TX_CLK	I/O	VDD_IO	DRV4	Schmitt	
ETH_12	RXD[0]	I/O	VDD_IO	DRV4	TTL	
ETH_13	USB_RXD, CTS, RXD[1]	I/O	VDD_IO	DRV4	TTL	
ETH_14	USB_RXP, UART_RX, RXD[2]	I/O	VDD_IO	DRV4	TTL	
ETH_15	USB_RXN, RX, RXD[3]	I/O	VDD_IO	DRV4	TTL	
ETH_16	USB_OVRCNT, CTS, RX_ER	I/O	VDD_IO	DRV4	TTL	
ETH_17	CD, CRS	I/O	VDD_IO	DRV4	TTL	
<b>IRDA</b>						
PSC6_0	IRDA_RX, TxD	I/O	VDD_IO	DRV4	TTL	
PSC6_1	RxD	I/O	VDD_IO	DRV4	TTL	
PSC6_2	Frame, CTS	I/O	VDD_IO	DRV4	TTL	
PSC6_3	IR_USB_CLK, Bi tClk, RTS	I/O	VDD_IO	DRV4	TTL	



**Table 51 MPC5200 Pinout Listing (continued)**

Name	Alias	Type	Power Supply	Output Driver Type	Input Type	Pull-up/down
<b>USB</b>						
USB_0	USB_OE	I/O	VDD_IO	DRV4	TTL	
USB_1	USB_TXN	I/O	VDD_IO	DRV4	TTL	
USB_2	USB_TXP	I/O	VDD_IO	DRV4	TTL	
USB_3	USB_RXD	I/O	VDD_IO	DRV4	TTL	
USB_4	USB_RXP	I/O	VDD_IO	DRV4	TTL	
USB_5	USB_RXN	I/O	VDD_IO	DRV4	TTL	
USB_6	USB_PRTPWR	I/O	VDD_IO	DRV4	TTL	
USB_7	USB_SPEED	I/O	VDD_IO	DRV4	TTL	
USB_8	USB_SUPEND	I/O	VDD_IO	DRV4	TTL	
USB_9	USB_OVRCNT	I/O	VDD_IO	DRV4	TTL	
<b>I<sup>2</sup>C</b>						
I2C_0	SCL	I/O	VDD_IO	DRV4	Schmitt	
I2C_1	SDA	I/O	VDD_IO	DRV4	Schmitt	
I2C_2	SCL	I/O	VDD_IO	DRV4	Schmitt	
I2C_3	SDA	I/O	VDD_IO	DRV4	Schmitt	
<b>PSC</b>						
PSC1_0	TxD, Sdata_out, MOSI, TX	I/O	VDD_IO	DRV4	TTL	
PSC1_1	RxD, Sdata_in, MISO, TX	I/O	VDD_IO	DRV4	TTL	
PSC1_2	Mclk, Sync, RTS	I/O	VDD_IO	DRV4	TTL	
PSC1_3	BitClk, SCK, CTS	I/O	VDD_IO	DRV4	TTL	
PSC1_4	Frame, SS, CD	I/O	VDD_IO	DRV4	TTL	
PSC2_0	TxD, Sdata_out, MOSI, TX	I/O	VDD_IO	DRV4	TTL	
PSC2_1	RxD, Sdata_in, MISO, TX	I/O	VDD_IO	DRV4	TTL	
PSC2_2	Mclk, Sync, RTS	I/O	VDD_IO	DRV4	TTL	

# Freescale Semiconductor, Inc.

## Package Description

**Table 51 MPC5200 Pinout Listing (continued)**

Name	Alias	Type	Power Supply	Output Driver Type	Input Type	Pull-up/down
PSC2_3	BitClk, SCK, CTS	I/O	VDD_IO	DRV4	TTL	
PSC2_4	Frame, $\overline{SS}$ , CD	I/O	VDD_IO	DRV4	TTL	
PSC3_0	USB_OE, TxDS, TX	I/O	VDD_IO	DRV4	TTL	
PSC3_1	USB_TXN, RxD, RX	I/O	VDD_IO	DRV4	TTL	
PSC3_2	USB_TXP, BitClk, RTS	I/O	VDD_IO	DRV4	TTL	
PSC3_3	USB_RXD, Frame, $\overline{SS}$ , CTS	I/O	VDD_IO	DRV4	TTL	
PSC3_4	USB_RXP, CD	I/O	VDD_IO	DRV4	TTL	
PSC3_5	USB_RXN	I/O	VDD_IO	DRV4	TTL	
PSC3_6	USB_PRTPWR, Mclk, MOSI	I/O	VDD_IO	DRV4	TTL	
PSC3_7	USB_SPEED, MISO	I/O	VDD_IO	DRV4	TTL	
PSC3_8	USB_SUSPEND, $\overline{SS}$	I/O	VDD_IO	DRV4	TTL	
PSC3_9	USB_OVRCNT, SCK	I/O	VDD_IO	DRV4	TTL	
<b>GPIO/TIMER</b>						
GPIO_WKUP_6	$\overline{MEM\_CS1}$	I/O	VDD_MEM_IO	DRV16_MEM	TTL	PULLUP_MEM
GPIO_WKUP_7		I/O	VDD_IO	DRV8	TTL	
TIMER_0		I/O	VDD_IO	DRV4	TTL	
TIMER_1		I/O	VDD_IO	DRV4	TTL	
TIMER_2	MOSI	I/O	VDD_IO	DRV4	TTL	
TIMER_3	MISO	I/O	VDD_IO	DRV4	TTL	
TIMER_4	SS	I/O	VDD_IO	DRV4	TTL	
TIMER_5	SCK	I/O	VDD_IO	DRV4	TTL	
TIMER_6		I/O	VDD_IO	DRV4	TTL	
TIMER_7		I/O	VDD_IO	DRV4	TTL	

**Table 51 MPC5200 Pinout Listing (continued)**

Name	Alias	Type	Power Supply	Output Driver Type	Input Type	Pull-up/down
<b>Clock</b>						
SYS_XTAL_IN		Input	VDD_IO			
SYS_XTAL_OUT		Output	VDD_IO			
RTC_XTAL_IN		Input	VDD_IO			
RTC_XTAL_OUT		Output	VDD_IO			
<b>Misc</b>						
$\overline{\text{PORRESET}}$		Input	VDD_IO	DRV4	Schmitt	
$\overline{\text{HRESET}}$		I/O	VDD_IO	DRV8_OD <sup>1</sup>	Schmitt	
$\overline{\text{SRESET}}$		I/O	VDD_IO	DRV8_OD <sup>1</sup>	Schmitt	
IRQ0		I/O	VDD_IO	DRV4	TTL	
IRQ1		I/O	VDD_IO	DRV4	TTL	
IRQ2		I/O	VDD_IO	DRV4	TTL	
IRQ3		I/O	VDD_IO	DRV4	TTL	
<b>Test/Configuration</b>						
SYS_PLL_TPA		I/O	VDD_IO	DRV4	TTL	
TEST_MODE_0		Input	VDD_IO	DRV4	TTL	
TEST_MODE_1		Input	VDD_IO	DRV4	TTL	
TEST_SEL_0		I/O	VDD_IO	DRV4	TTL	PULLUP
TEST_SEL_1		I/O	VDD_IO	DRV8	TTL	
JTAG_TCK	TCK	Input	VDD_IO	DRV4	TTL	PULLUP
JTAG_TDI	TDI	Input	VDD_IO	DRV4	TTL	PULLUP
JTAG_TDO	TDO	I/O	VDD_IO	DRV8	TTL	
JTAG_TMS	TMS	Input	VDD_IO	DRV4	TTL	PULLUP
$\overline{\text{JTAG_TRST}}$	TRST	Input	VDD_IO	DRV4	TTL	PULLUP
<b>Power and Ground</b>						
VDD_IO		-				
VDD_MEM_IO		-				

# Freescale Semiconductor, Inc.

## Package Description

Table 51 MPC5200 Pinout Listing (continued)

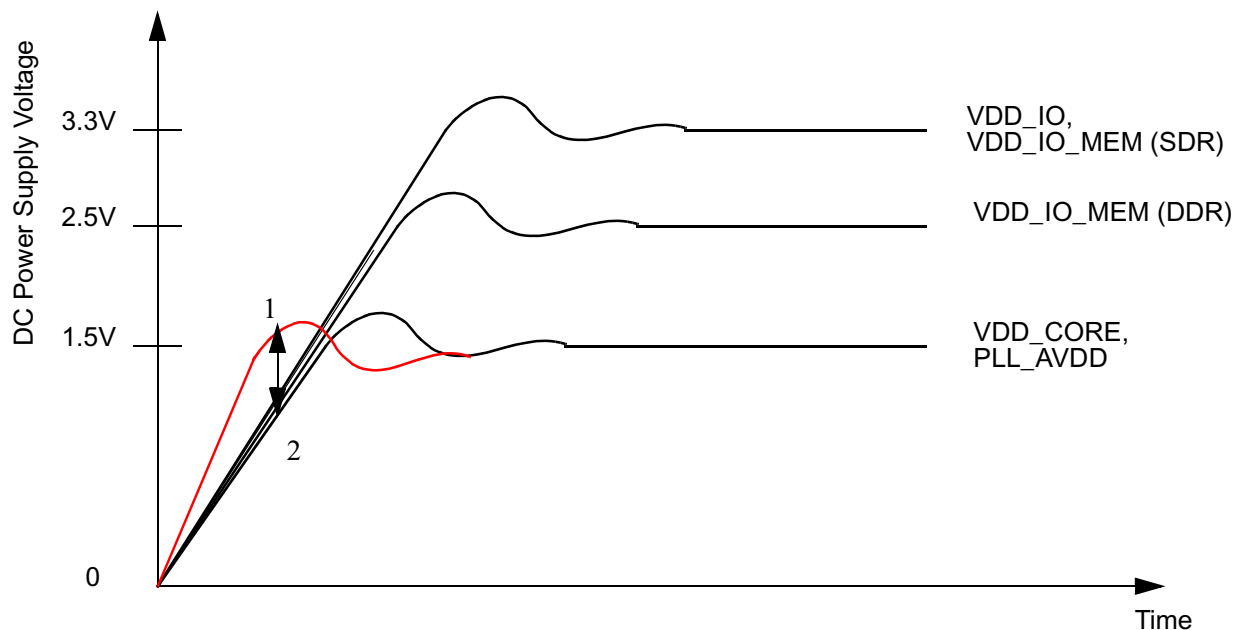
Name	Alias	Type	Power Supply	Output Driver Type	Input Type	Pull-up/down
VDD_CORE		-				
VSS_IO/CORE		-				
SYS_PLL_AVDD		-				
CORE_PLL_AVDD		-				

- 1 All "open drain" outputs of the MPC5200 are actually regular three-state output drivers with the output data tied low and the output enable controlled. Thus, unlike a true open drain, there is a current path from the external system to the MPC5200 I/O power rail if the external signal is driven above the MPC5200 I/O power rail voltage.

## 6 System Design Information

### 6.1 Power UP/Down Sequencing

Figure 50 shows situations in sequencing the I/O VDD (VDD\_IO), Memory VDD (VDD\_IO\_MEM), PLL VDD (PLL\_AVDD), and Core VDD (VDD\_CORE).



Note:

1. VDD\_CORE should not exceed VDD\_IO, VDD\_IO\_MEM or PLL\_AVDD by more than 0.4 V at any time, including power-up.
2. It is recommended that VDD\_CORE/PLL\_AVDD should track VDD\_IO/VDD\_IO\_MEM up to 0.9 V then separate for completion of ramps.
3. Input voltage must not be greater than the supply voltage (VDD\_IO, VDD\_IO\_MEM, VDD\_CORE, or PLL\_AVDD) by more than 0.5 V at any time, including during power-up.
4. Use 1 microsecond or slower rise time for all supplies.

**Figure 50 Supply Voltage Sequencing**

The relationship between VDD\_IO\_MEM and VDD\_IO is non-critical during power-up and power-down sequences. Both VDD\_IO\_MEM (2.5 V or 3.3 V) and VDD\_IO are specified relative to VDD\_CORE.

#### 6.1.1 Power Up Sequence

If VDD\_IO/VDD\_IO\_MEM are powered up with the VDD\_CORE at 0V, the sense circuits in the I/O pads will cause all pad output drivers connected to the VDD\_IO/VDD\_IO\_MEM to be in a high-impedance state. There is no limit to how long after VDD\_IO/VDD\_IO\_MEM powers up before VDD\_CORE must power up. VDD\_CORE should not lead the VDD\_IO, VDD\_IO\_MEM or PLL\_AVDD by more than 0.4 V during power ramp up or there will be high current in the internal ESD protection diodes. The rise times on the power supplies should be slower than 1 microsecond to avoid turning on the internal ESD protection clamp diodes.

The recommended power up sequence is as follows:

Use one microsecond or slower rise time for all supplies.

# Freescale Semiconductor, Inc.

## System Design Information

VDD\_CORE/PLL\_AVDD and VDD\_IO/VDD\_IO\_MEM should track up to 0.9 V and then separate for the completion of ramps with VDD\_IO/VDD\_IO\_MEM going to the higher external voltages. One way to accomplish this is to use a low drop-out voltage regulator.

### 6.1.2 Power Down Sequence

If VDD\_CORE/PLL\_AVDD are powered down first, then sense circuits in the I/O pads will cause all output drivers to be in a high impedance state. There is no limit on how long after VDD\_CORE and PLL\_AVDD power down before VDD\_IO or VDD\_IO\_MEM must power down. VDD\_CORE should not lag VDD\_IO, VDD\_IO\_MEM, or PLL\_AVDD going low by more than 0.4V during power down or there will be undesired high current in the ESD protection diodes. There are no requirements for the fall times of the power supplies.

The recommended power down sequence is as follows:

Drop VDD\_CORE/PLL\_AVDD to 0V.

Drop VDD\_IO/VDD\_IO\_MEM supplies.

## 6.2 System and CPU Core AVDD power supply filtering

Each of the independent PLL power supplies require filtering external to the device. The following drawing is a recommendation for the required filter circuit.

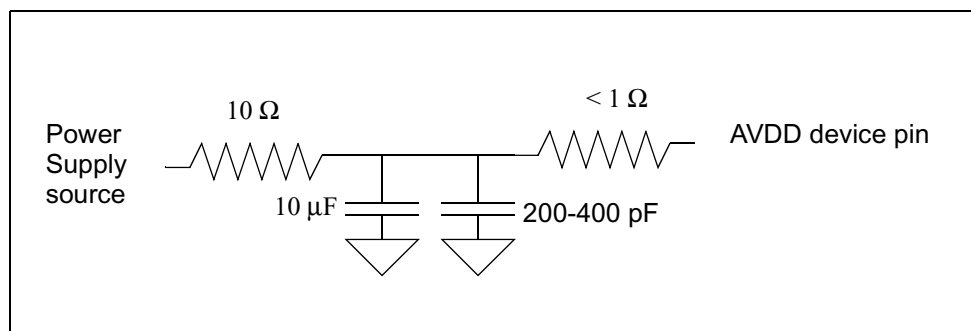


Figure 51 Power Supply Filtering

## 6.3 Pull-up/Pull-down Resistor Requirements

The MPC5200 requires external pull-up or pull-down resistors on certain pins.

### 6.3.1 Pull-down Resistor Requirements for TEST pins

The MPC5200 requires pull-down resistors on the test pins TEST\_MODE\_0, TEST\_MODE\_1, TEST\_SEL\_1.

### 6.3.2 Pull-up Requirements for the PCI Control Lines

If the PCI interface is NOT used (and internally disabled) the PCI control pins must be terminated as indicated by the PCI Local Bus specification [4]. This is also required for MOST/Graphics and Large Flash Mode.

PCI control signals always require pull-up resistors on the motherboard (not the expansion board) to ensure that they contain stable values when no agent is actively driving the bus. This includes PCI\_FRAME, PCI\_TRDY, PCI\_IRDY, PCI\_DEVSEL, PCI\_STOP, PCI\_SERR, PCI\_PERR, and PCI\_REQ.

### 6.3.3 Pull-up/Pull-down Requirements for MEM\_MDQS pins (SDRAM)

The MEM\_MDQS[3:0] signals are not used with SDR memories and require pull-up or pull-down resistors in SDRAM mode.

## 6.4 Information about JTAG\_TRST

Boundary scan testing is enabled through the JTAG interface signals. The JTAG\_TRST signal is optional in the IEEE 1149.1 specification but is provided on all processors that implement the PowerPC architecture. To obtain a reliable power-on reset performance, the JTAG\_TRST signal must be asserted during power-on reset.

### 6.4.1 JTAG\_TRST and PORRESET

The JTAG interface can control the direction of the MPC5200 I/O pads via the boundary scan chain. The JTAG module must be reset before the MPC5200 comes out of power-on reset; do this by asserting JTAG\_TRST before PORRESET is released.

For more details refer to the Reset and JTAG Timing Specification.



Figure 52  $\overline{\text{PORRESET}}$  vs.  $\overline{\text{JTAG\_TRST}}$

## 6.5 Connecting JTAG\_TRST

The wiring of the  $\overline{\text{JTAG\_TRST}}$  is dependent of the existence of a board-related debug interface.

Normally this interface is implemented, using a COP (common on-chip processor) connector. The COP allows a remote computer system (typically, a PC with dedicated hardware and debugging software) to access and control the internal operations of the MPC5200. The COP port requires the ability to independently assert  $\overline{\text{HRESET}}$  and  $\overline{\text{JTAG\_TRST}}$  in order to fully control the processor.

There are two possibilities to connect the JTAG interface: using it with a COP connector and without a COP connector.

### 6.5.1 Boards interfacing the JTAG port via a COP connector

For a board with a COP (common on-chip processor) connector, which accesses the JTAG interface and which needs to reset the JTAG module, simply wiring  $\overline{\text{TRST}}$  and  $\overline{\text{PORRESET}}$  is not recommended.

To reset the MPC5200 via the COP connector, the  $\overline{\text{HRESET}}$  pin of the COP should be connected to the  $\overline{\text{HRESET}}$  pin of the MPC5200.

The circuitry shown in Figure 53 allows the COP to assert  $\overline{\text{HRESET}}$  or  $\overline{\text{JTAG\_TRST}}$  separately, while any other board sources can drive  $\overline{\text{PORRESET}}$ .

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## System Design Information

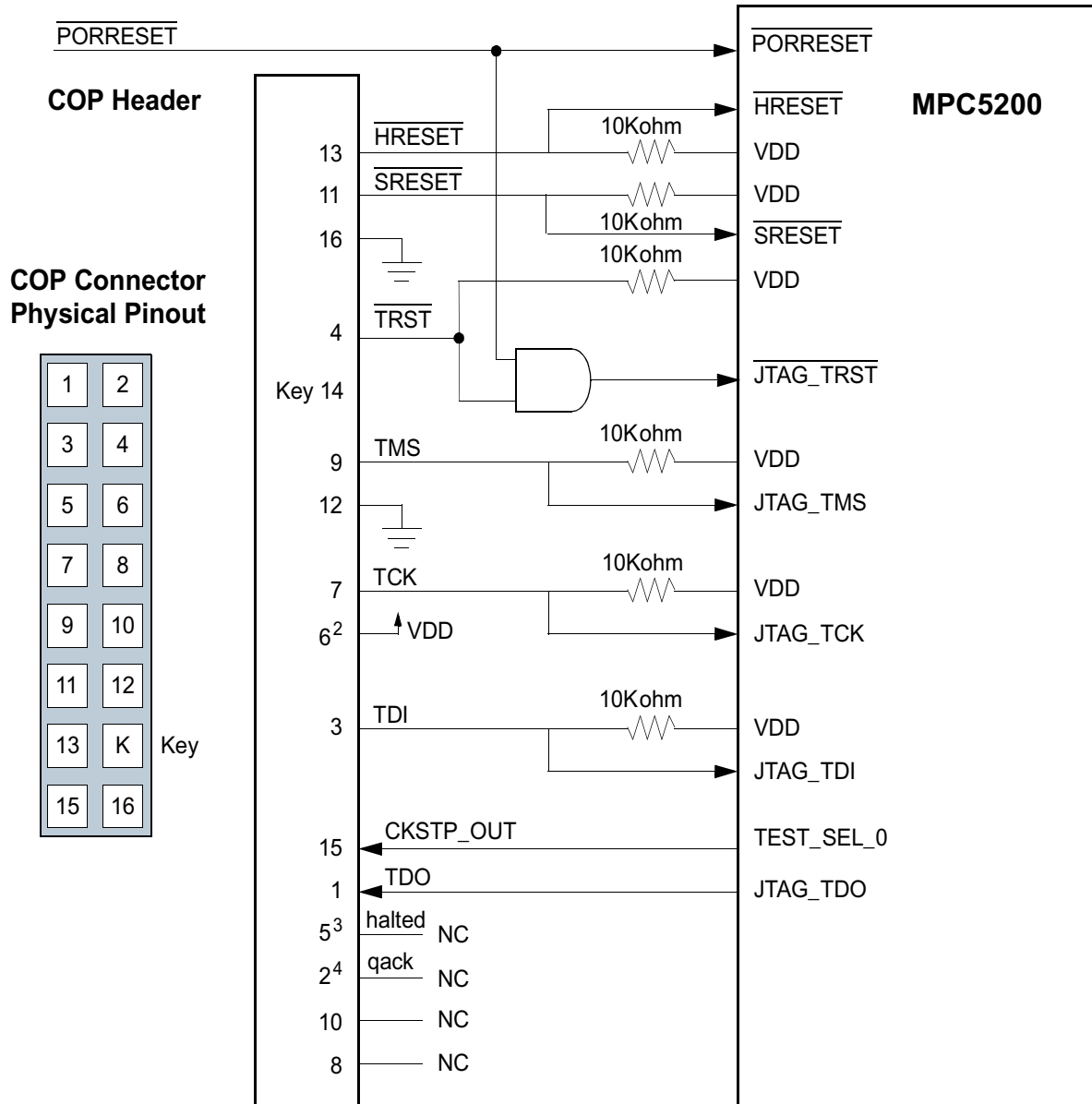


Figure 53 COP Connector Diagram

### 6.5.2 Boards without COP connector

If the JTAG interface is not used,  $\overline{\text{JTAG\_TRST}}$  should be tied to  $\overline{\text{PORRESET}}$ , so that it is asserted when the system reset signal (PORRESET) is asserted. This ensures that the JTAG scan chain is initialized during power on. Figure 54 shows the connection of the JTAG interface without COP connector.



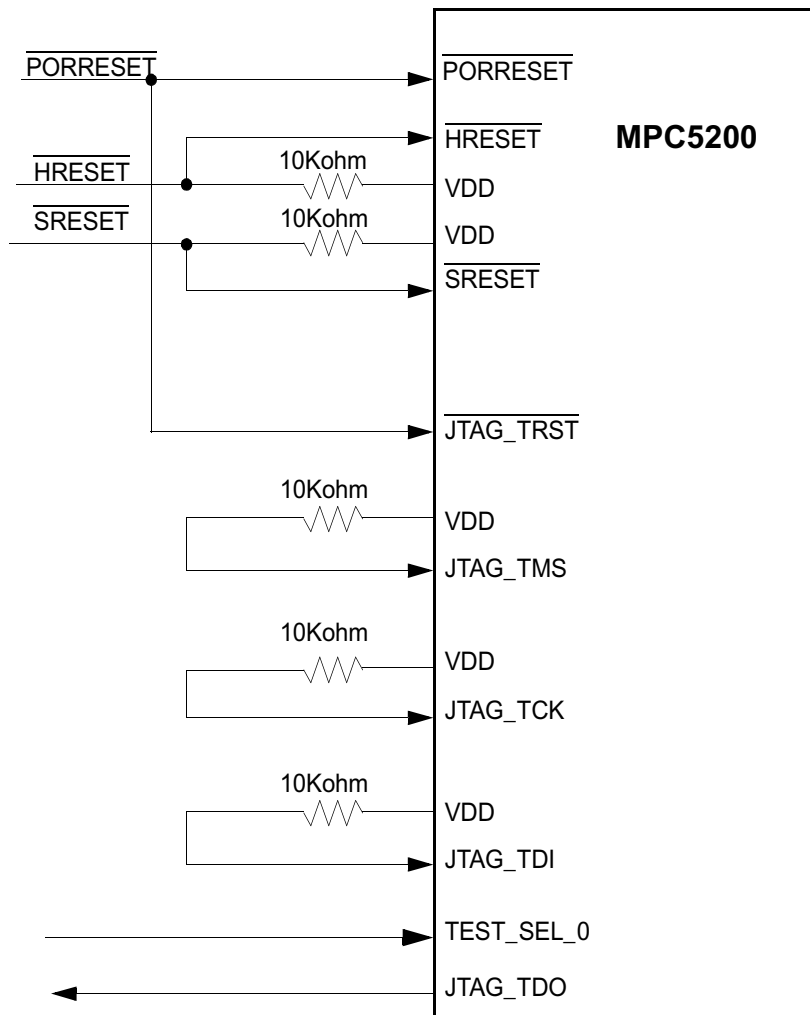


Figure 54  $\overline{\text{JTAG\_TRST}}$  wiring for boards without COP connector

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## Ordering Information

### 7 Ordering Information

Table 52 Ordering Information

Part Number	Speed	Ambient Temp	Qualification
MPC5200BV400	400	0C to 70C	Commercial
MPC5200CBV266	266	-40C to 85C	Industrial
MPC5200CBV400	400	-40C to 85C	Industrial
SPC5200CBV400	400	-40C to 85C	Automotive - AEC

## 8 Document Revision History

Table 53 provides a revision history for this hardware specification.

**Table 53 Document Revision History**

Rev. No.	Substantive Change(s)
0.1	First Preliminary release with some TBD's in spec tables (6/2003)
0.2	Added AC specs for missing modules, power-on sequence, misc other updates (7/2003)
0.2.1	Corrected maximum core operating frequency (7/2003)
0.3	Added Memory Interface Timing values, misc other updates (8/2003)
1.0	Added Information about JTAG_TRST (11/2003)
2.0	Added Power Numbers (Section 3.1.5), updated Oscillator and PLL Characteristics (Section 3.2), updated SDRAM AC Characteristics (Section 3.3.5)

**For more detailed information, refer to the following documentation:**

- [1] MPC5200 User Manual MPC5200UM
- [2] PowerPC Microprocessor Family: The Programming Environments for 32-bit Microprocessors, Rev. 2: MPCFPE32B/AD
- [3] G2 Core Reference Manual, Rev. 0: G2CORERM/D
- [4] PCI Local Bus Specification, Revision 2.2, December 18, 1998
- [5] ANSI ATA-4 Specification
- [6] IEEE 802.3 Specification (ETHERNET)

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